

Occupied Bandwidth

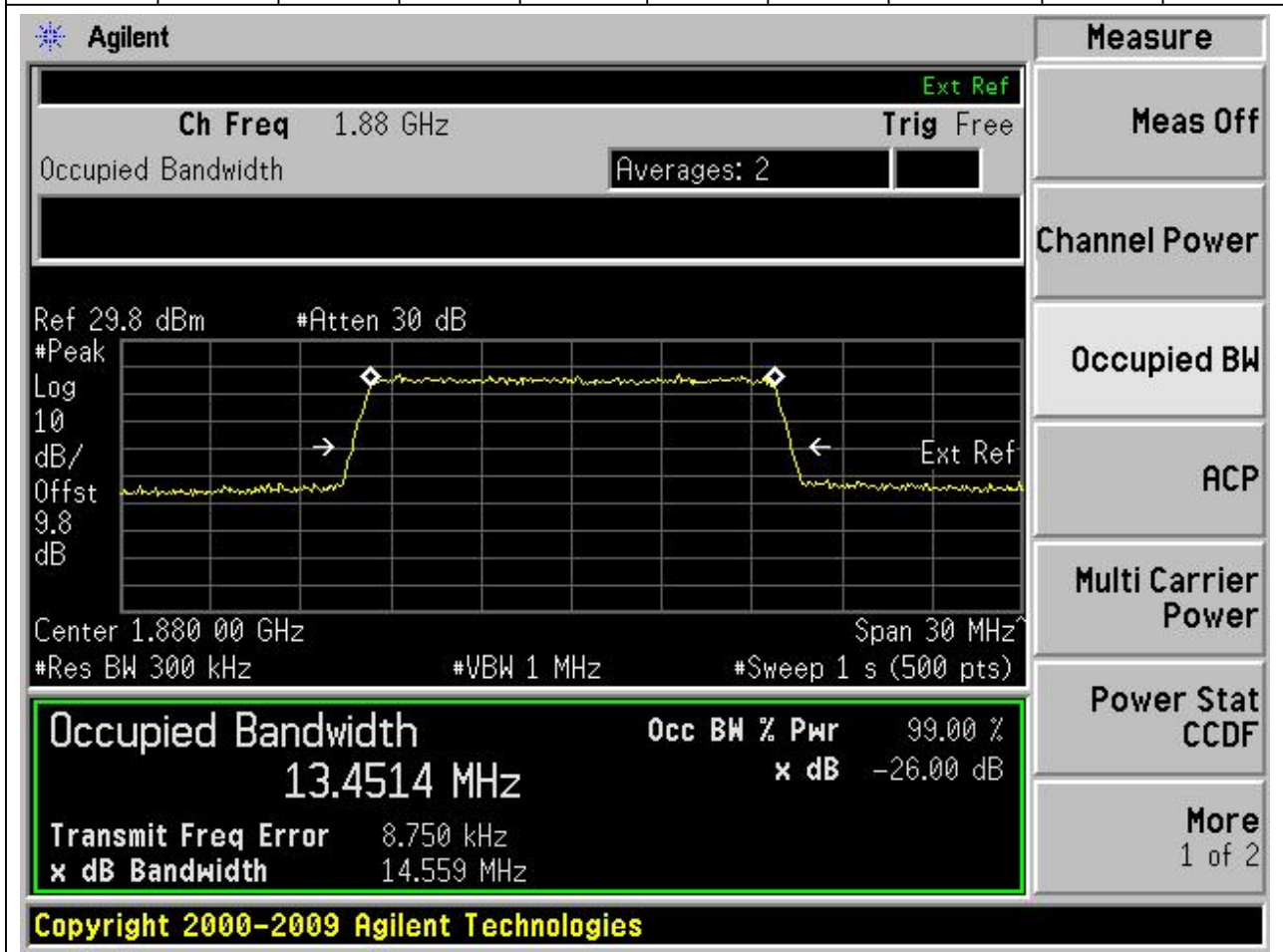
1.28. LTE Occupied Bandwidth_Part22-24-27(Channel:18900, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1880	99	26	0.3	Peak	9.8	13.45	14.56	15	Pass



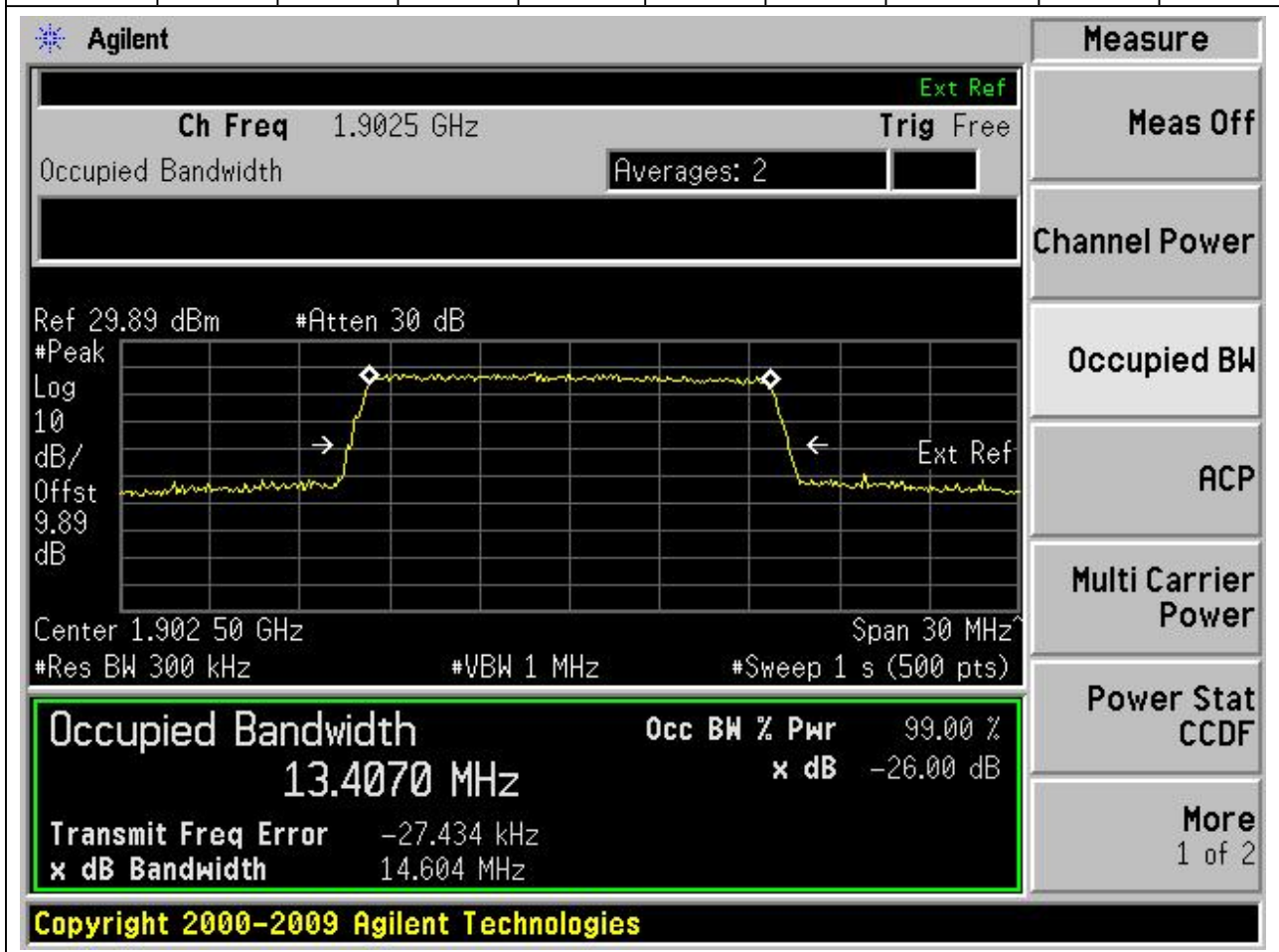
1.29. LTE Occupied Bandwidth_Part22-24-27(Channel:19125, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1902.5	99	26	0.3	Peak	9.88	13.41	14.6	15	Pass



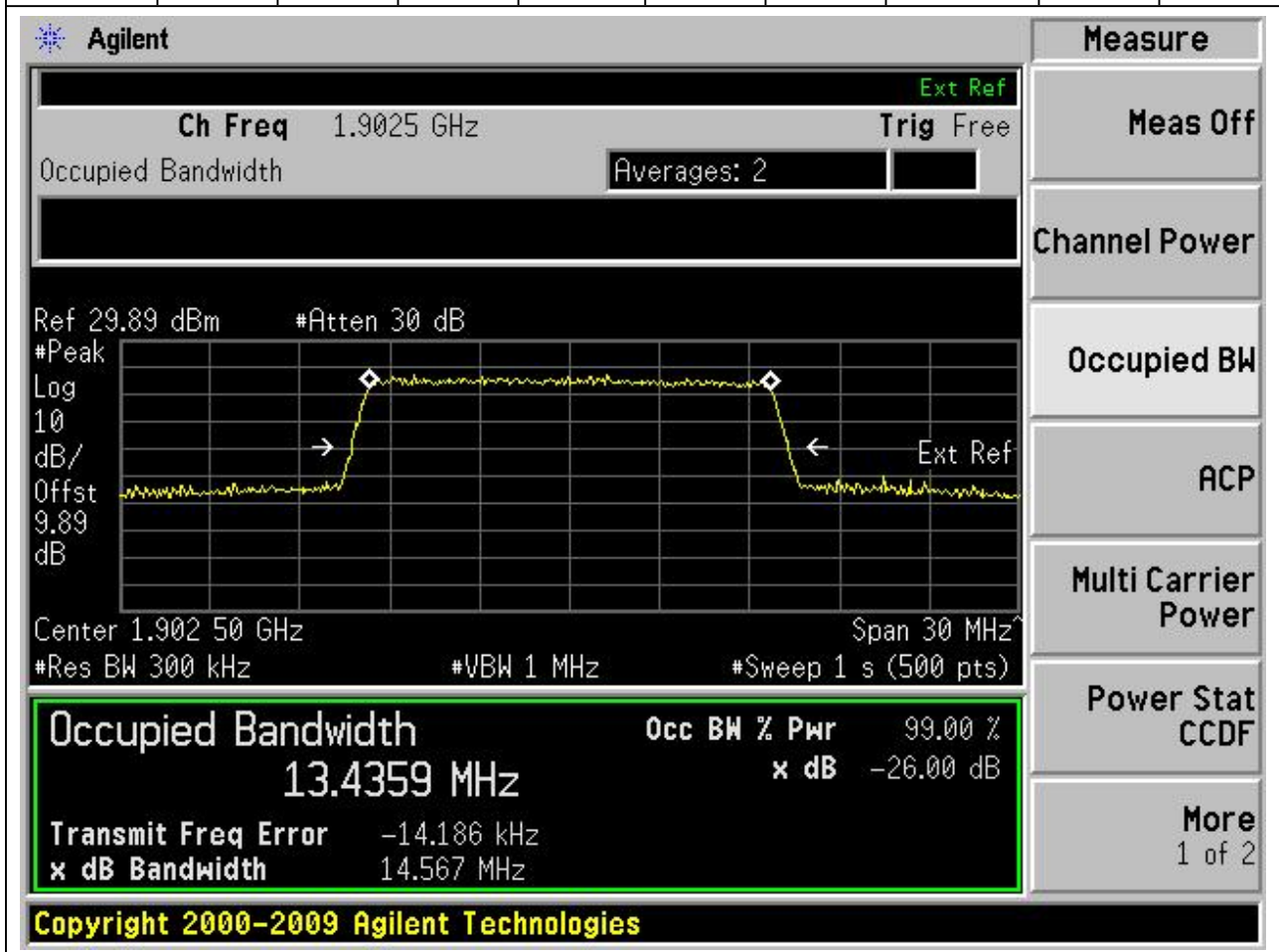
1.30. LTE Occupied Bandwidth_Part22-24-27(Channel:19125, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1902.5	99	26	0.3	Peak	9.88	13.44	14.57	15	Pass



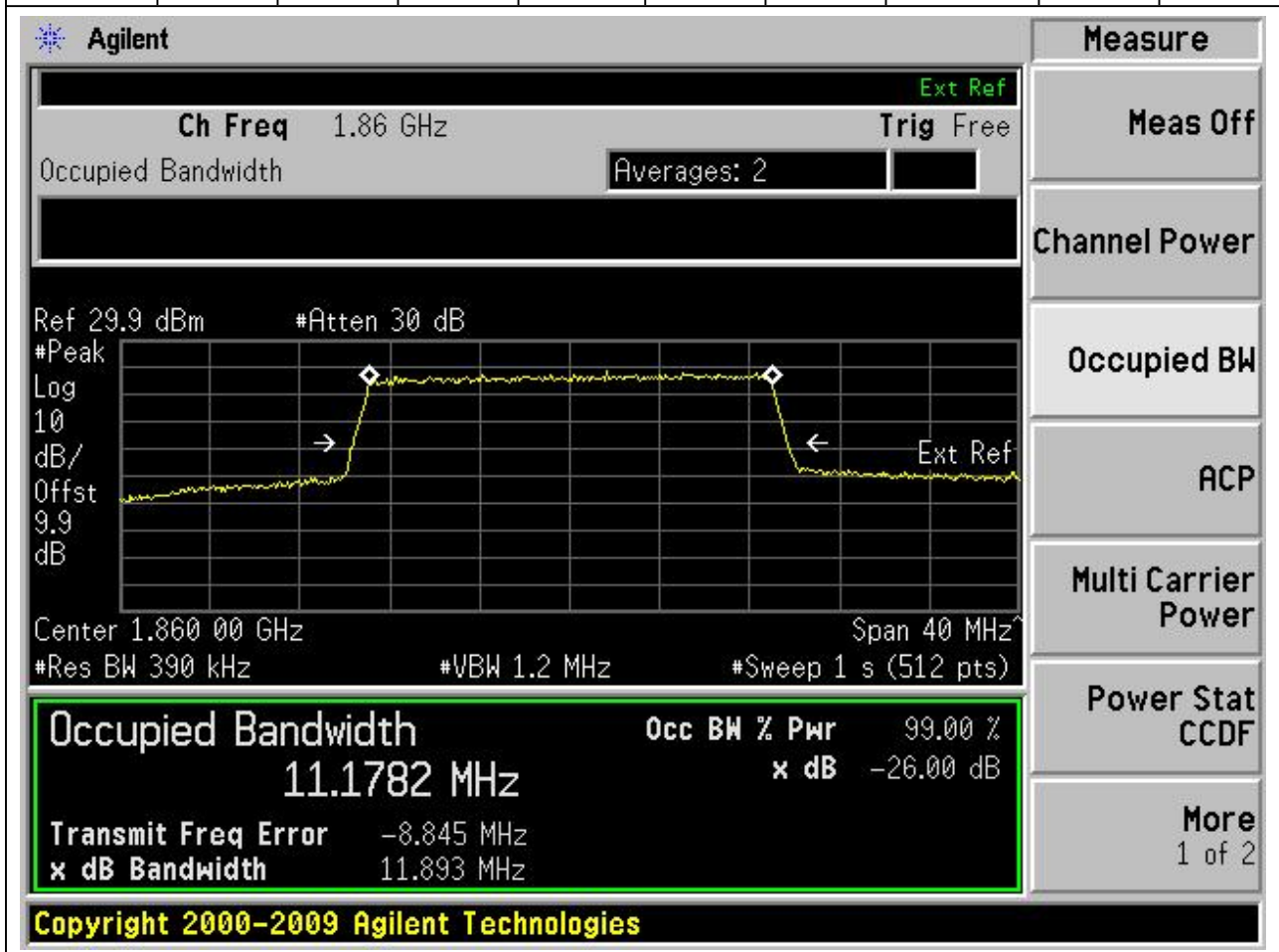
1.31. LTE Occupied Bandwidth_Part22-24-27(Channel:18700, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1860	99	26	0.39	Peak	9.9	11.18	11.89	20	Pass



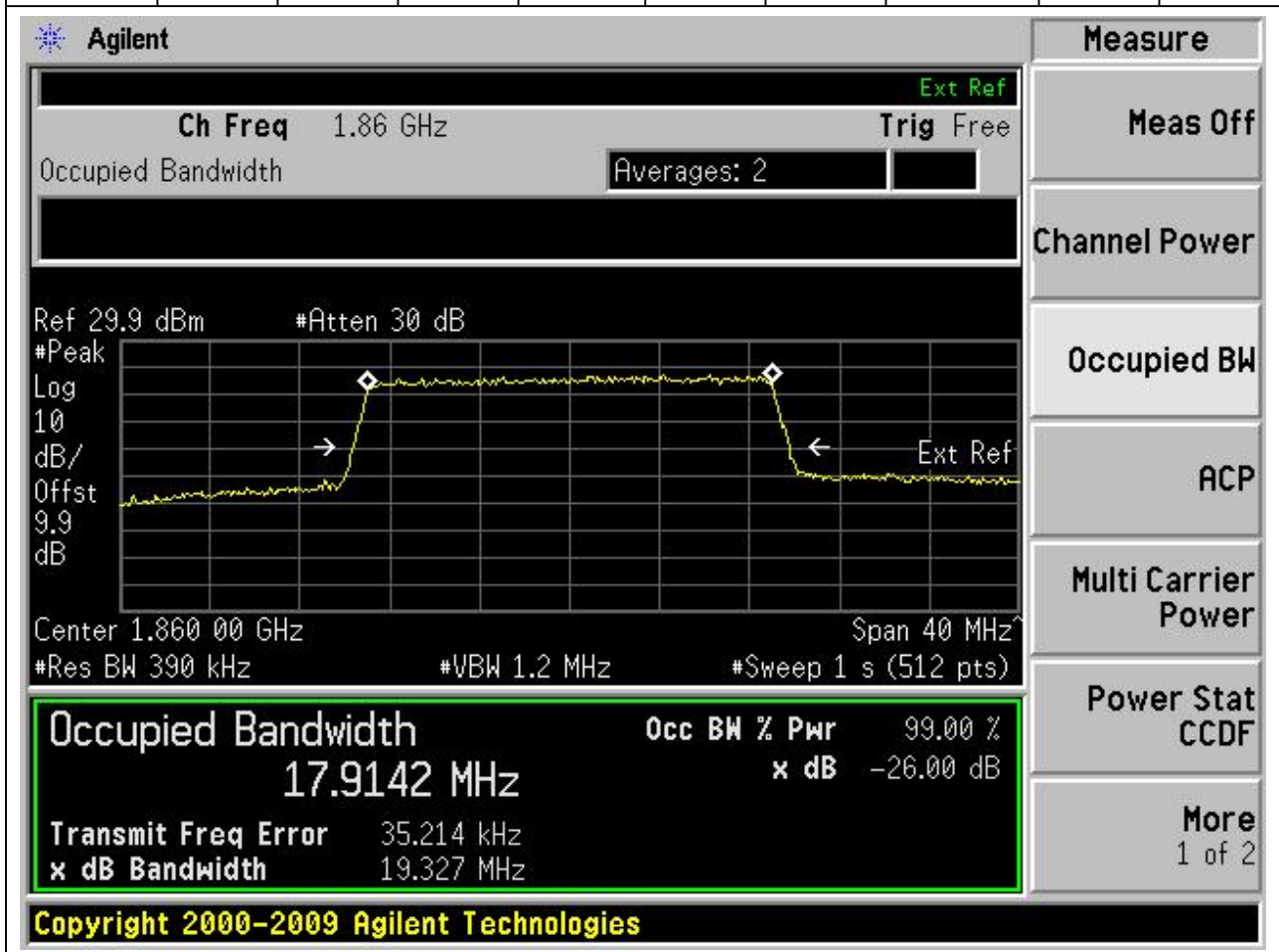
1.32. LTE Occupied Bandwidth_Part22-24-27(Channel:18700, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1860	99	26	0.39	Peak	9.9	17.91	19.33	20	Pass



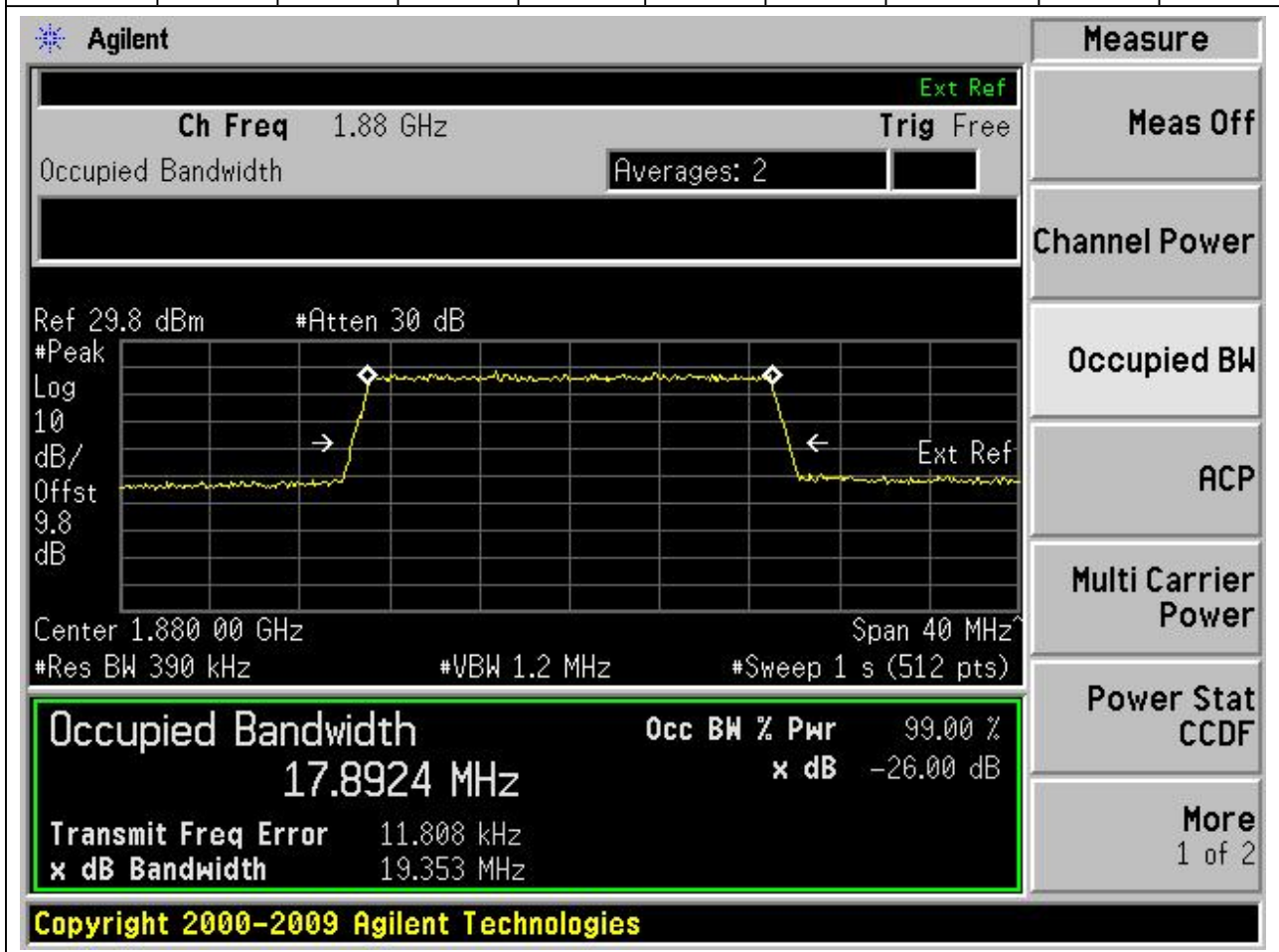
1.33. LTE Occupied Bandwidth_Part22-24-27(Channel:18900, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1880	99	26	0.39	Peak	9.8	17.89	19.35	20	Pass



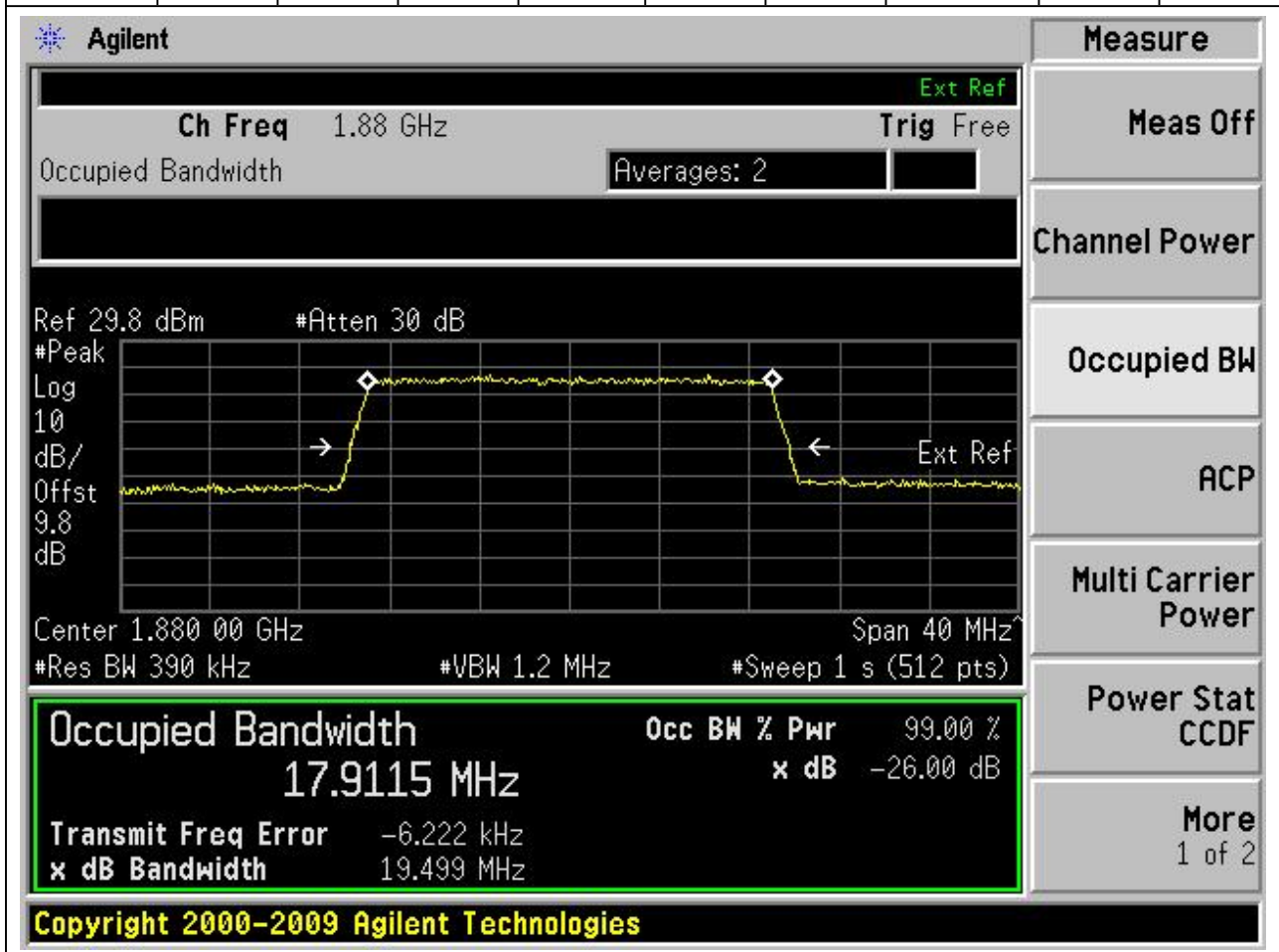
1.34. LTE Occupied Bandwidth_Part22-24-27(Channel:18900, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1880	99	26	0.39	Peak	9.8	17.91	19.5	20	Pass



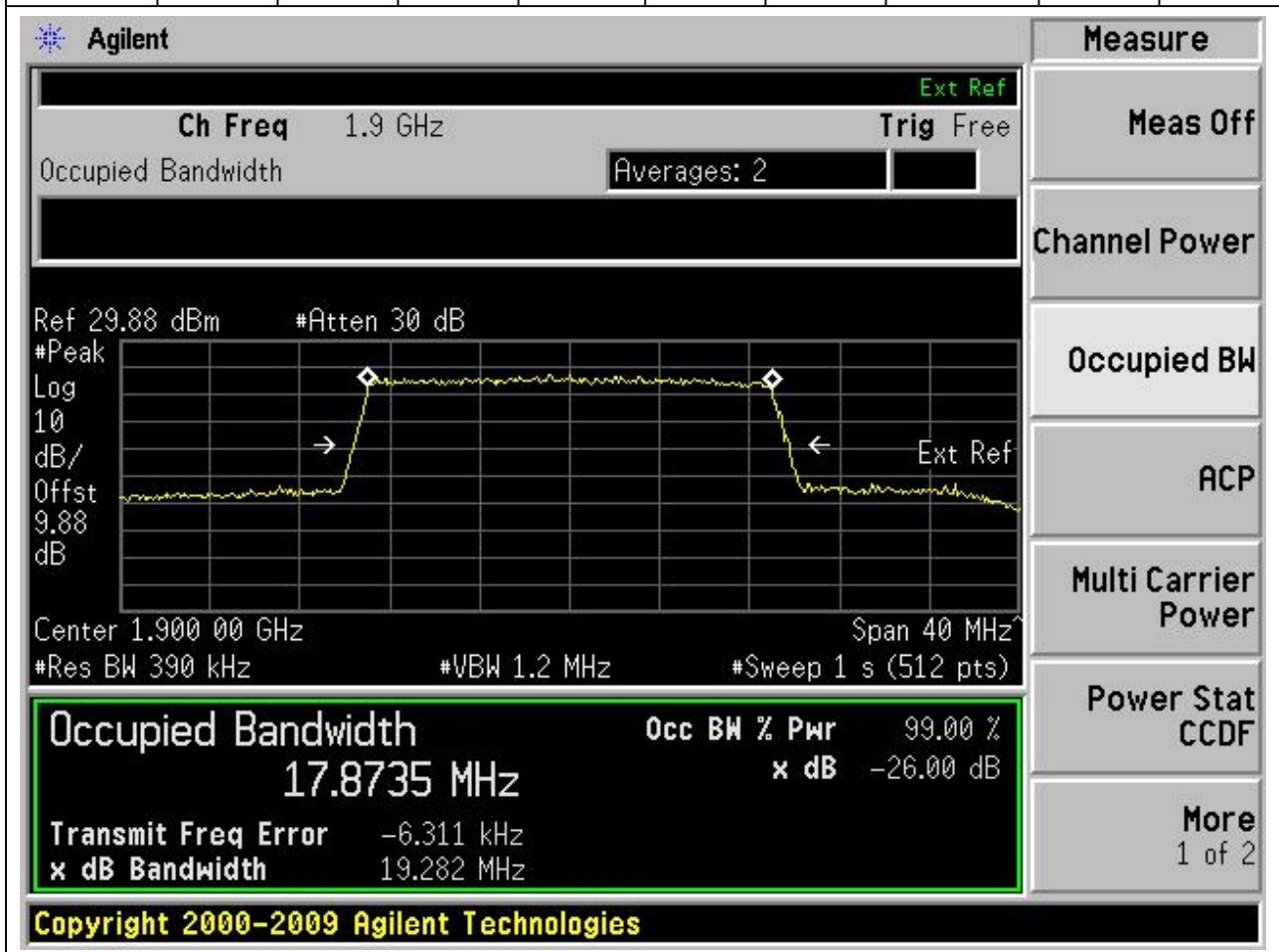
1.36. LTE Occupied Bandwidth_Part22-24-27(Channel:19100, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1900	99	26	0.39	Peak	9.88	17.87	19.28	20	Pass



2. LTE_Band4

EUT Sample No.:	
EUT Name:	
EUT Manufacturer:	
EUT Model:	
EUT Serial Number:	
EUT Hardware Version:	
EUT Software Version:	
Low Temperature(LT):	-10 °C
Normal Temperature(NT):	+25 °C
High Temperature(HT):	+55 °C
Low Voltage(LV):	3.6 V
Normal Voltage(NV):	3.8 V
High Voltage(HV):	4.2 V

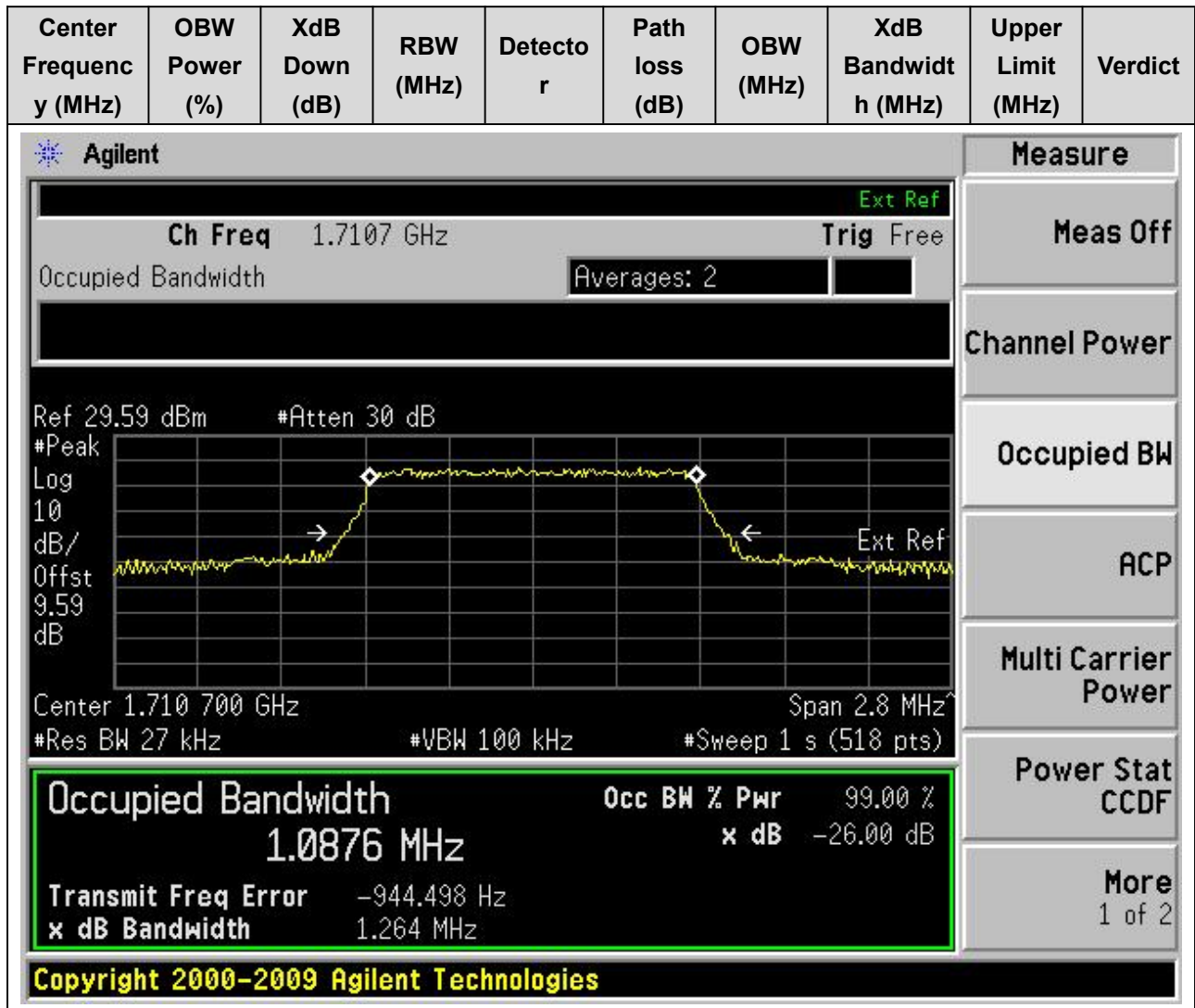
2.1. LTE Occupied Bandwidth_Part22-24-27(Channel:19957, Bandwidth:1.4, Modulation:QPSK, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1710.7	99	26	0.027	Peak	9.59	1.09	1.26	1.4	Pass



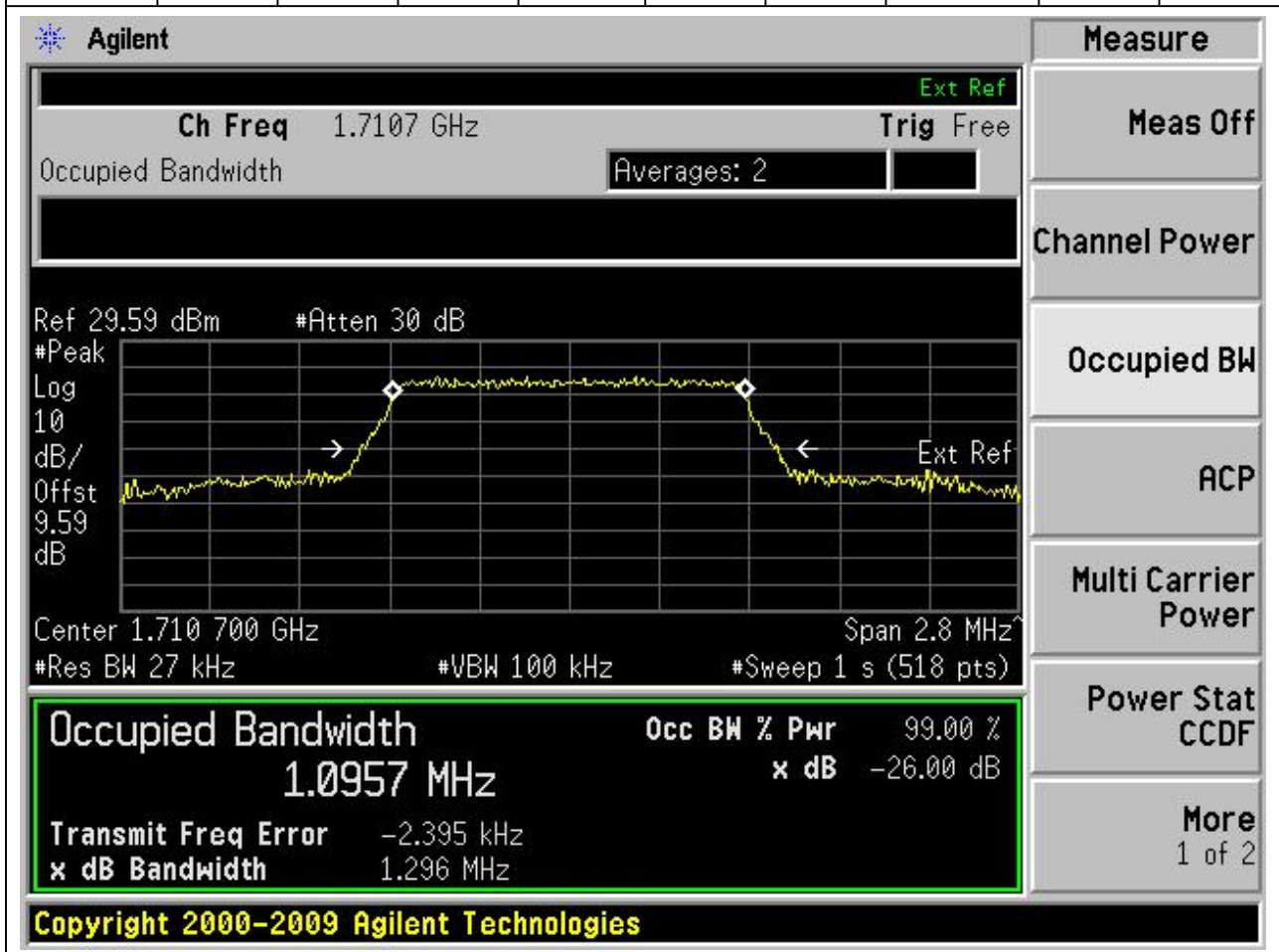
2.2. LTE Occupied Bandwidth_Part22-24-27(Channel:19957, Bandwidth:1.4, Modulation:16QAM, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1710.7	99	26	0.027	Peak	9.59	1.1	1.3	1.4	Pass



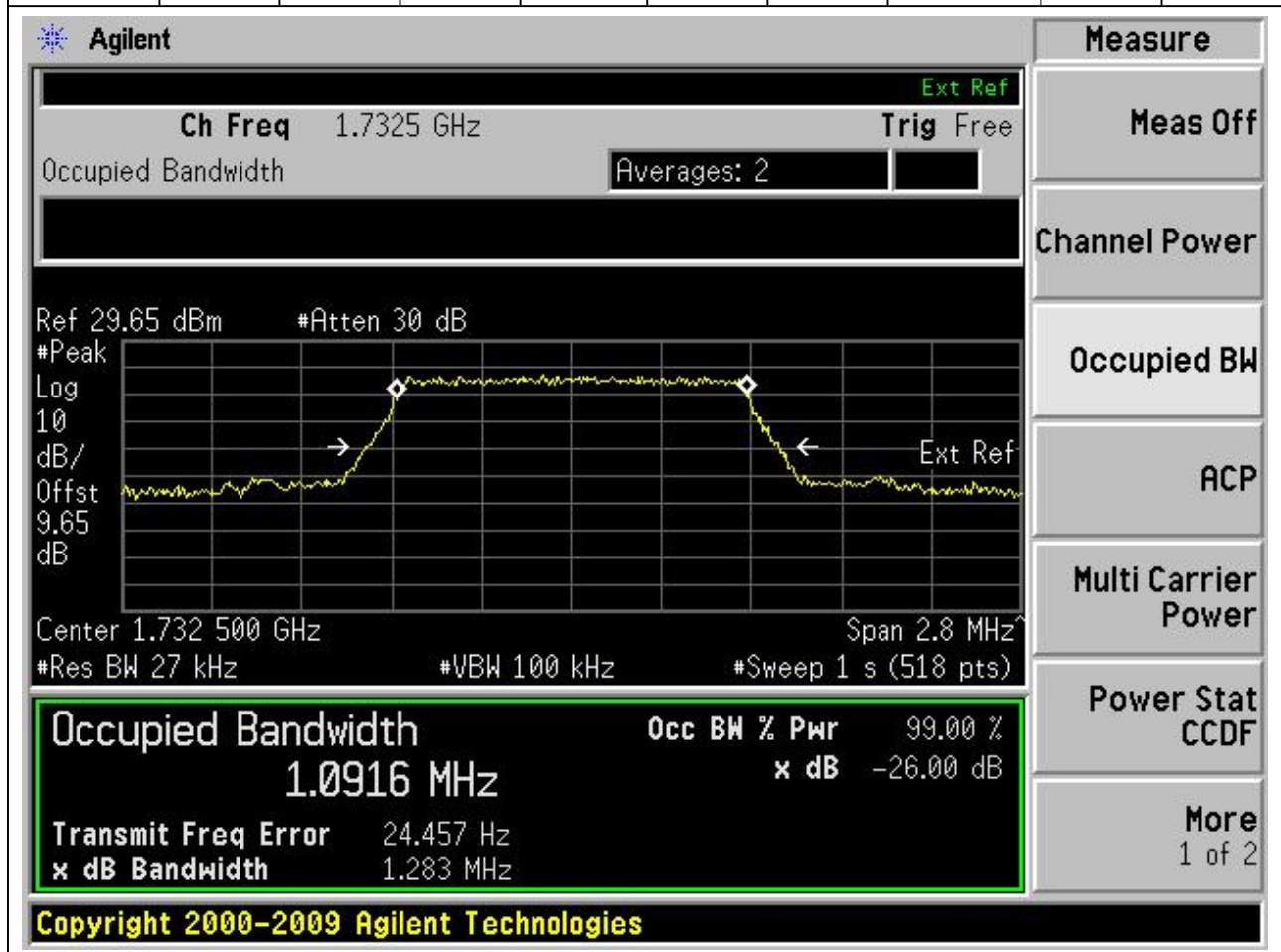
2.3. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:1.4, Modulation:QPSK, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.027	Peak	9.65	1.09	1.28	1.4	Pass



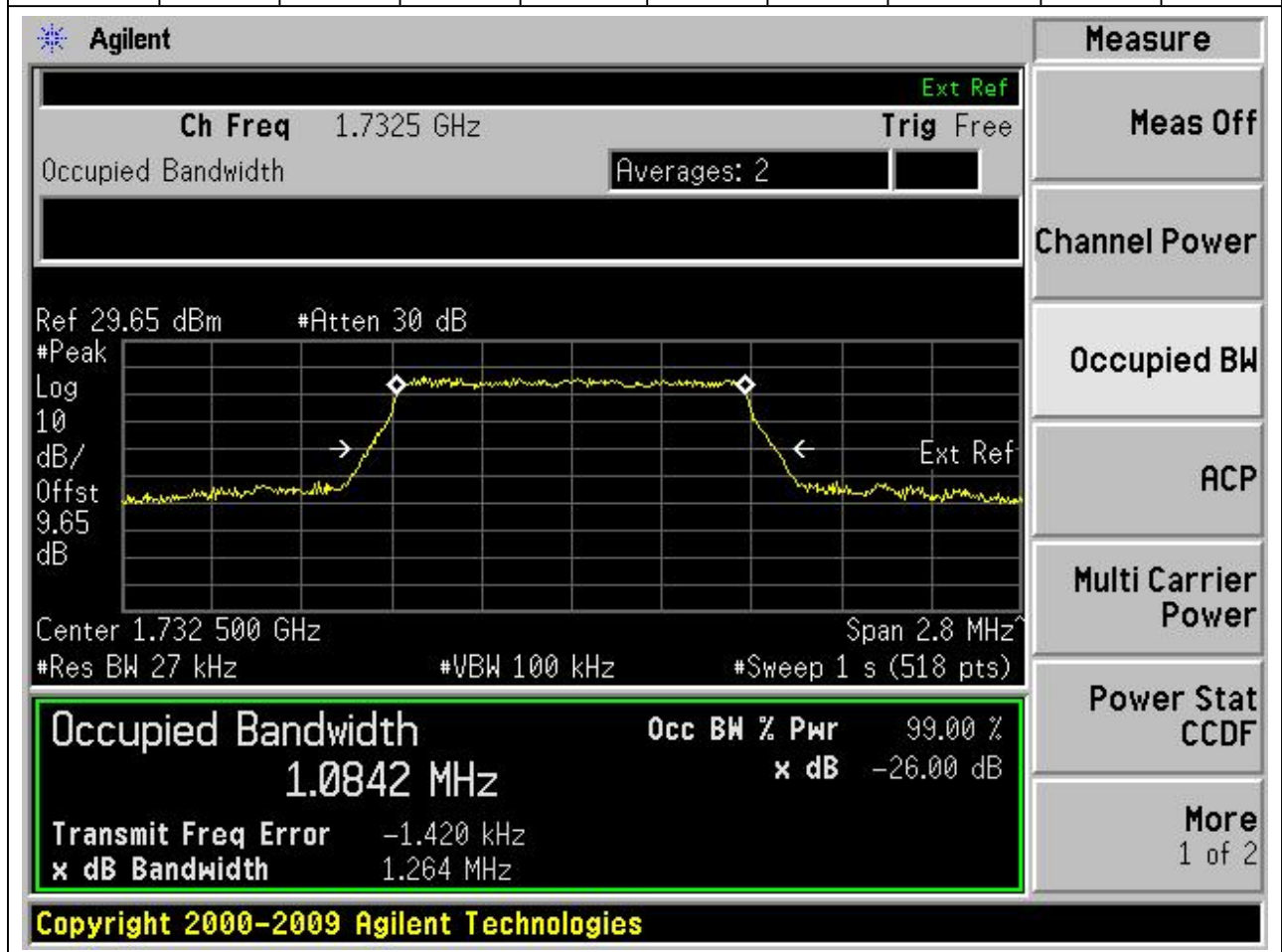
2.4. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:1.4, Modulation:16QAM, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.027	Peak	9.65	1.08	1.26	1.4	Pass



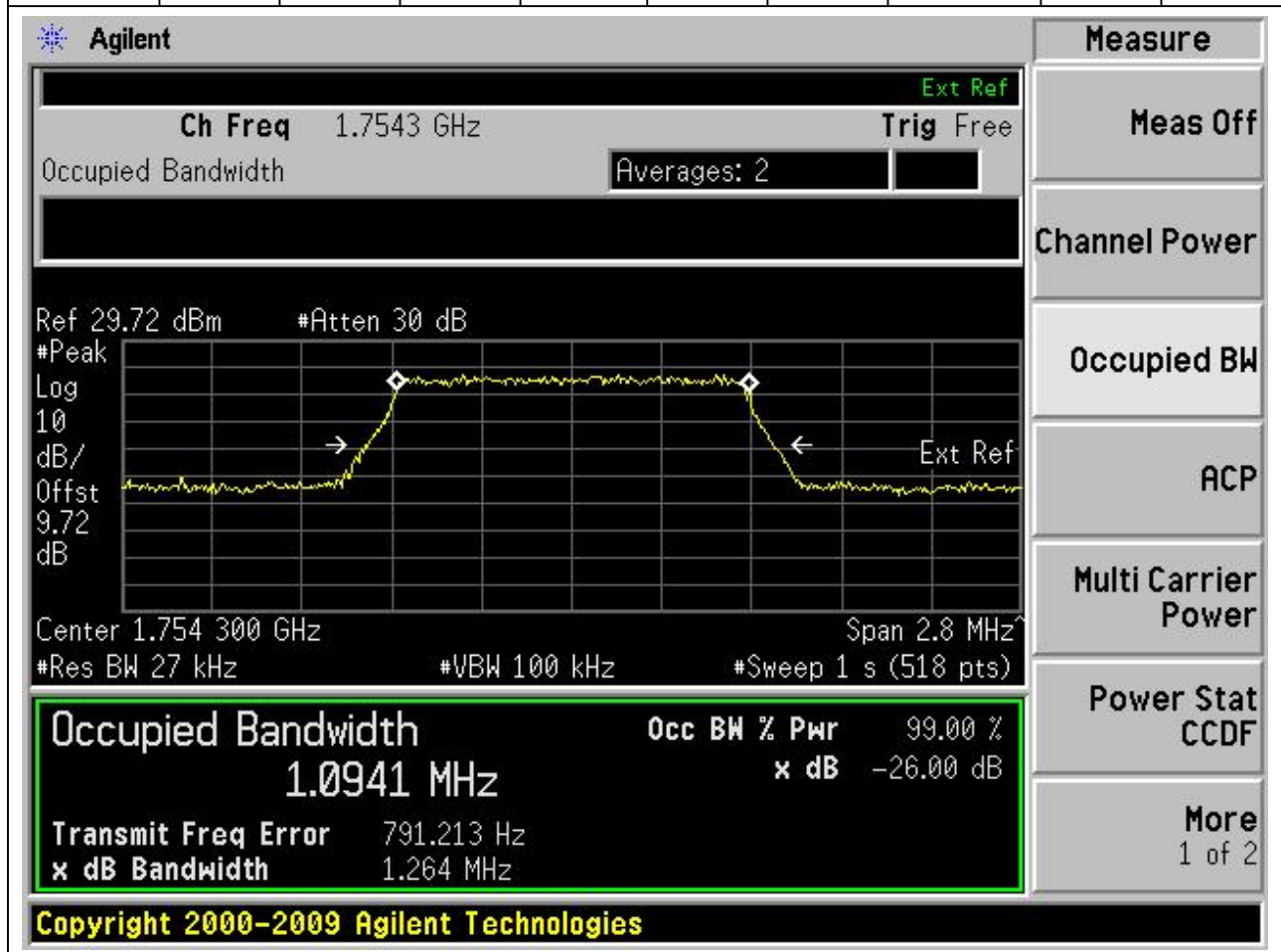
2.5. LTE Occupied Bandwidth_Part22-24-27(Channel:20393, Bandwidth:1.4, Modulation:QPSK, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1754.3	99	26	0.027	Peak	9.72	1.09	1.26	1.4	Pass



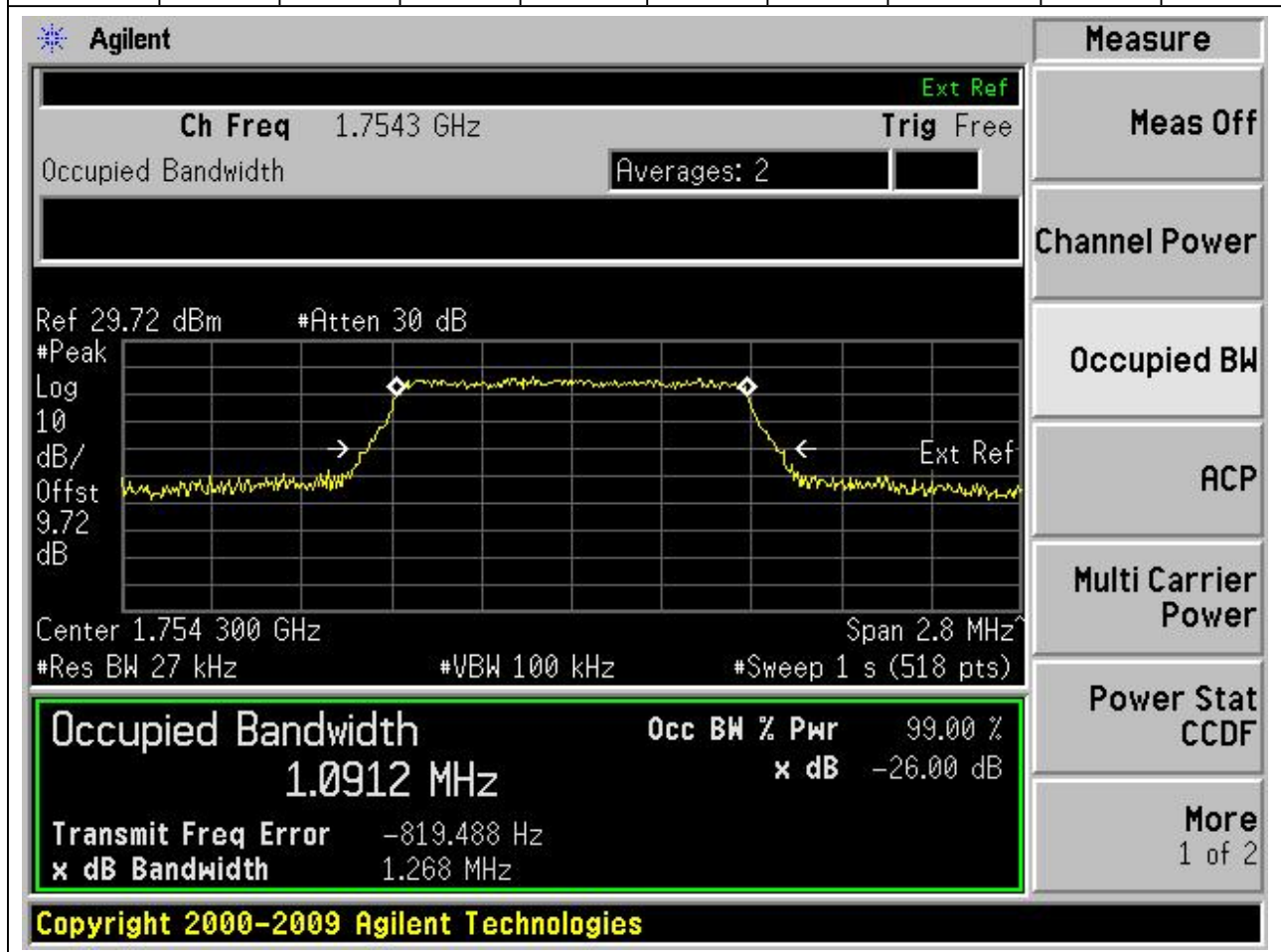
2.6. LTE Occupied Bandwidth_Part22-24-27(Channel:20393, Bandwidth:1.4, Modulation:16QAM, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1754.3	99	26	0.027	Peak	9.72	1.09	1.27	1.4	Pass



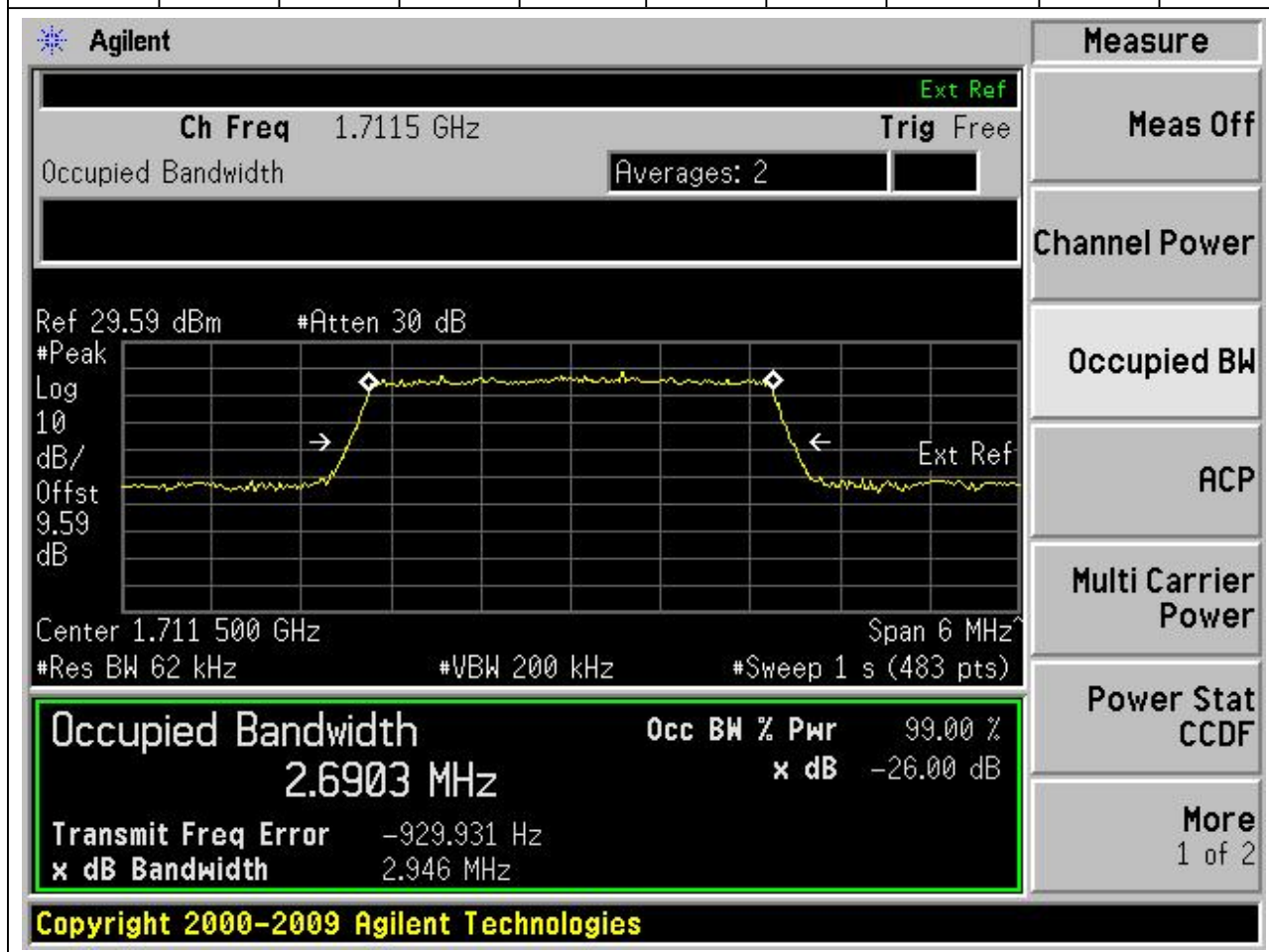
2.7. LTE Occupied Bandwidth_Part22-24-27(Channel:19965, Bandwidth:3, Modulation:QPSK, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1711.5	99	26	0.062	Peak	9.59	2.69	2.95	3	Pass



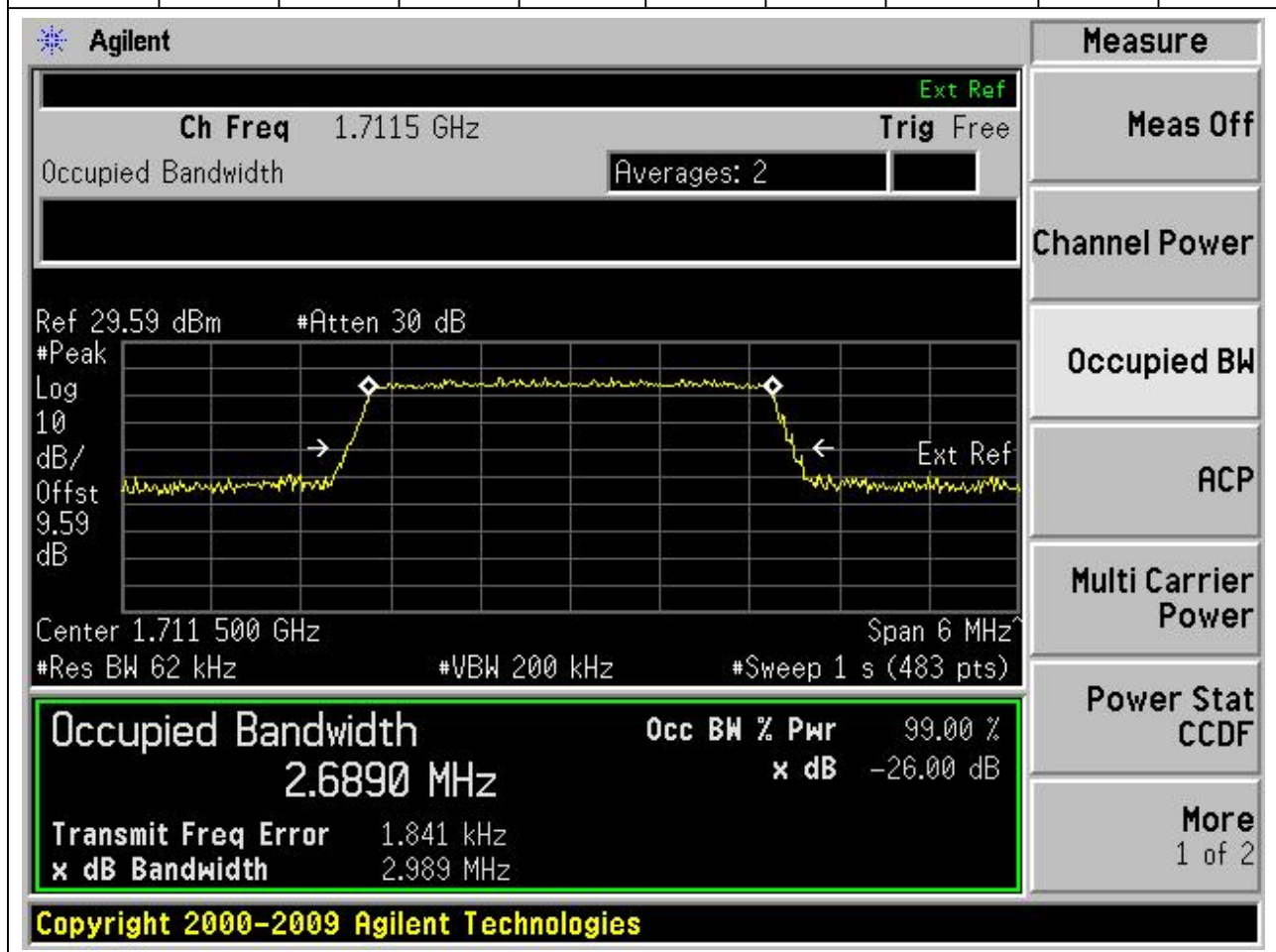
2.8. LTE Occupied Bandwidth_Part22-24-27(Channel:19965, Bandwidth:3, Modulation:16QAM, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1711.5	99	26	0.062	Peak	9.59	2.69	2.99	3	Pass



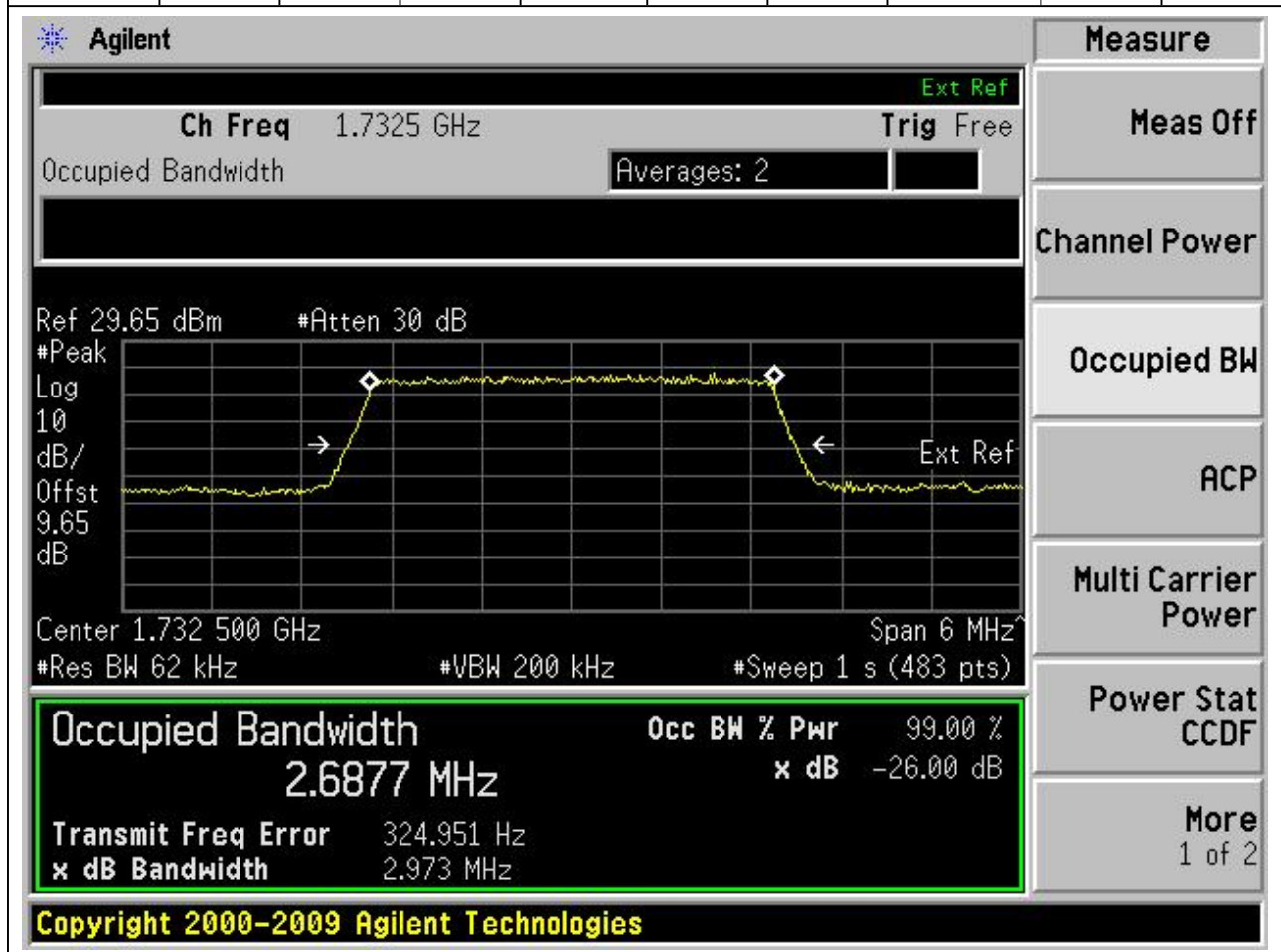
2.9. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:3, Modulation:QPSK, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.062	Peak	9.65	2.69	2.97	3	Pass



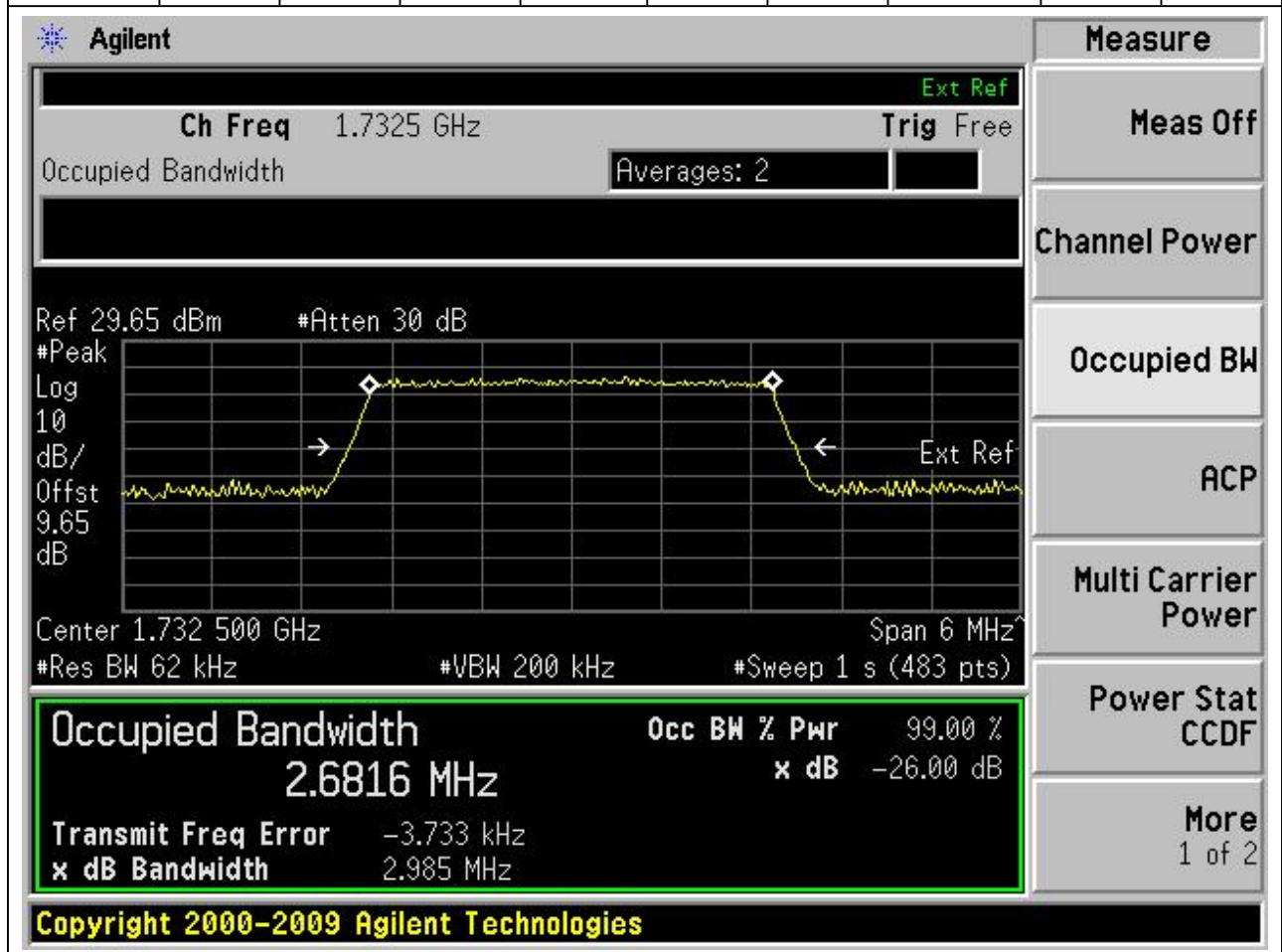
2.10. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:3, Modulation:16QAM, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.062	Peak	9.65	2.68	2.99	3	Pass



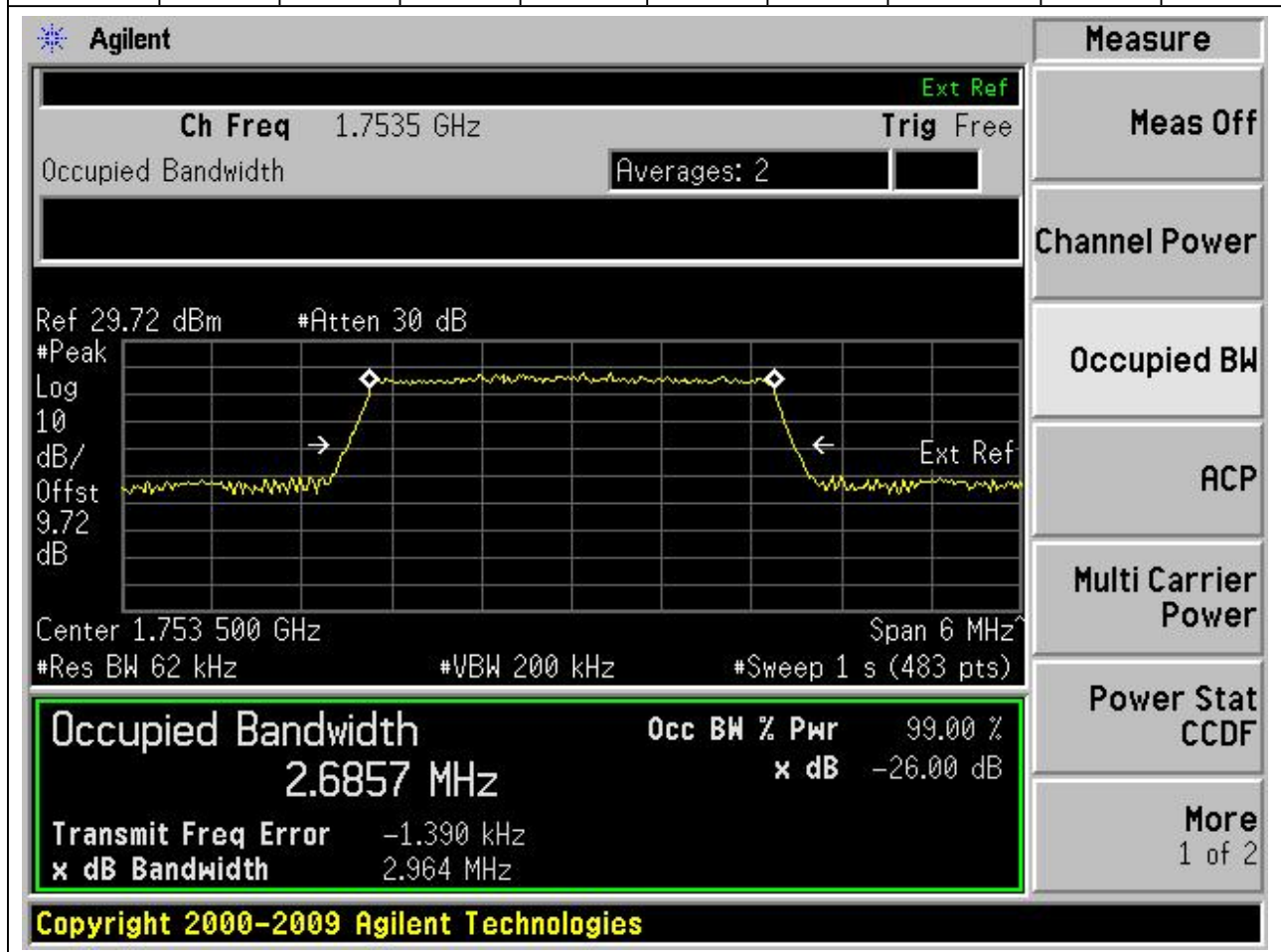
2.11. LTE Occupied Bandwidth_Part22-24-27(Channel:20385, Bandwidth:3, Modulation:QPSK, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1753.5	99	26	0.062	Peak	9.72	2.69	2.96	3	Pass



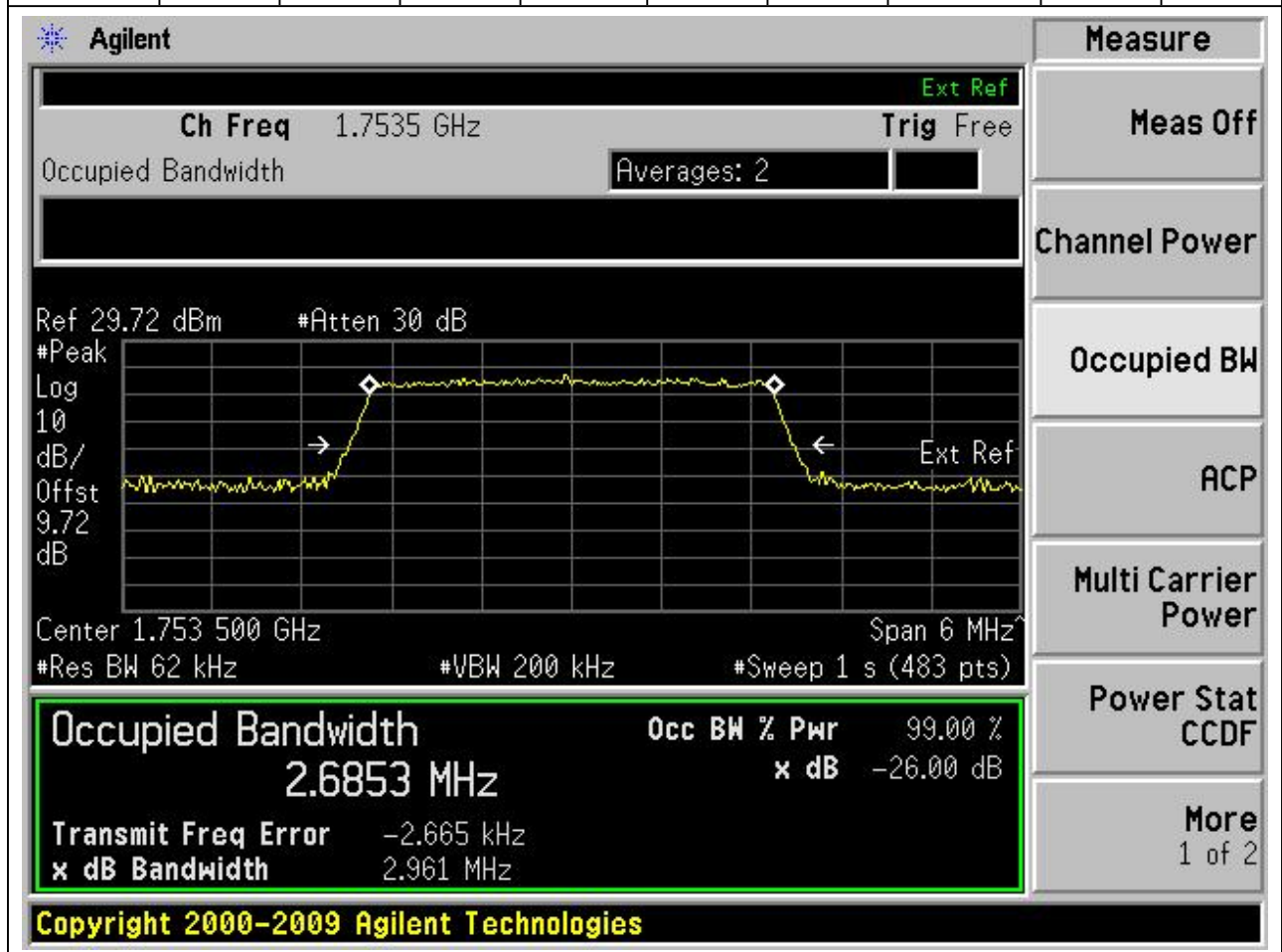
2.12. LTE Occupied Bandwidth_Part22-24-27(Channel:20385, Bandwidth:3, Modulation:16QAM, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1753.5	99	26	0.062	Peak	9.72	2.69	2.96	3	Pass



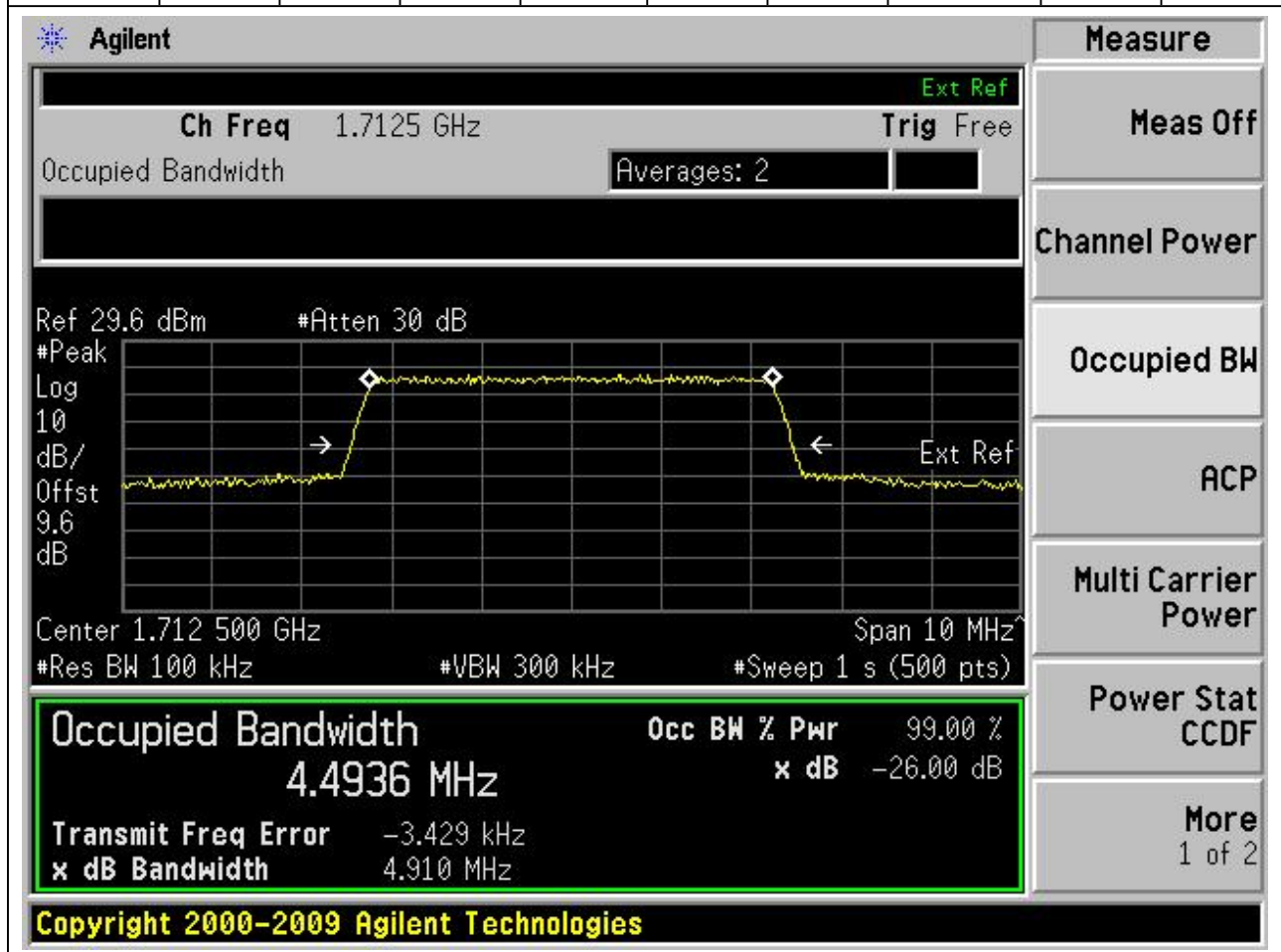
2.13. LTE Occupied Bandwidth_Part22-24-27(Channel:19975, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1712.5	99	26	0.1	Peak	9.6	4.49	4.91	5	Pass



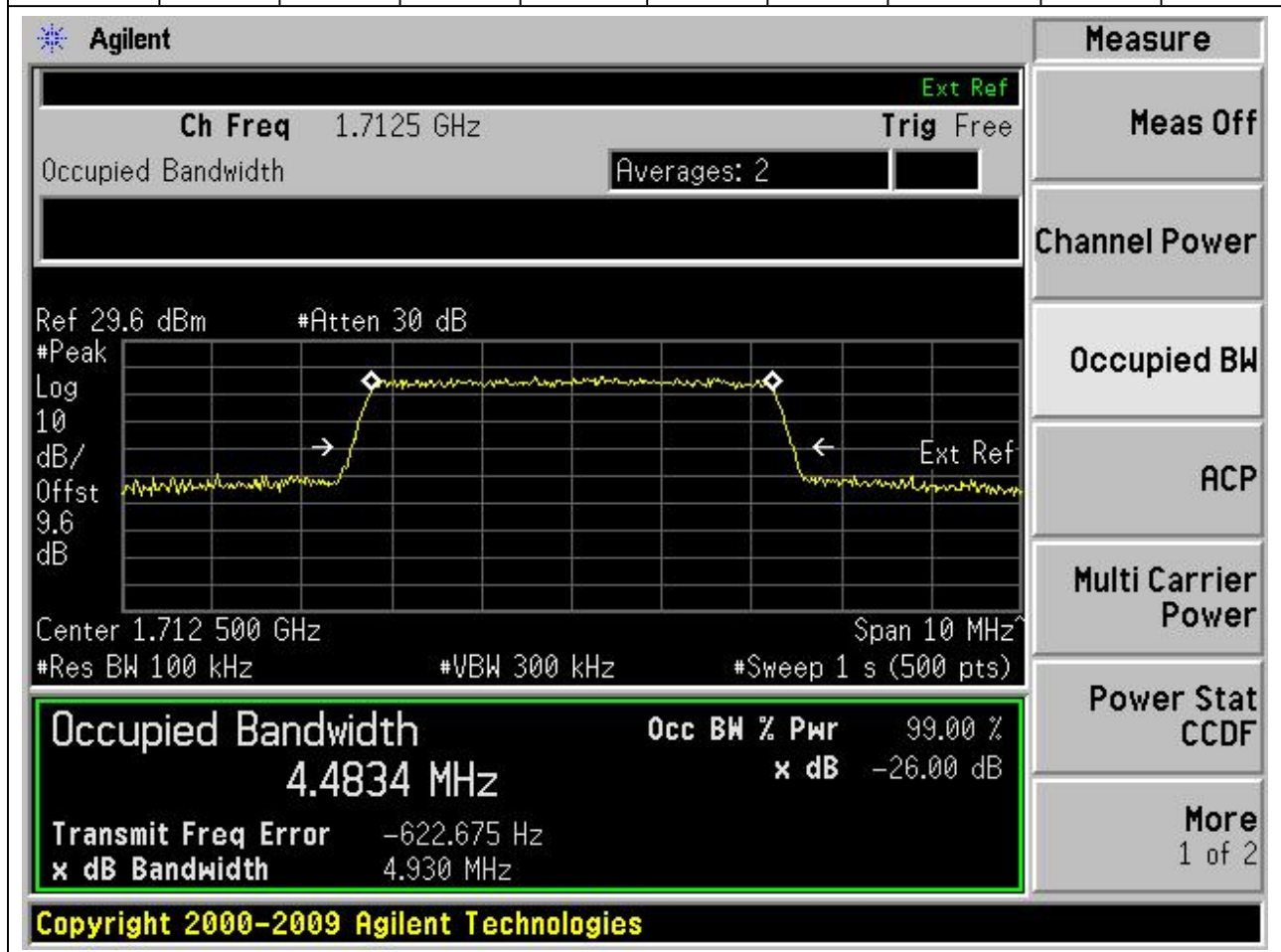
2.14. LTE Occupied Bandwidth_Part22-24-27(Channel:19975, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1712.5	99	26	0.1	Peak	9.6	4.48	4.93	5	Pass



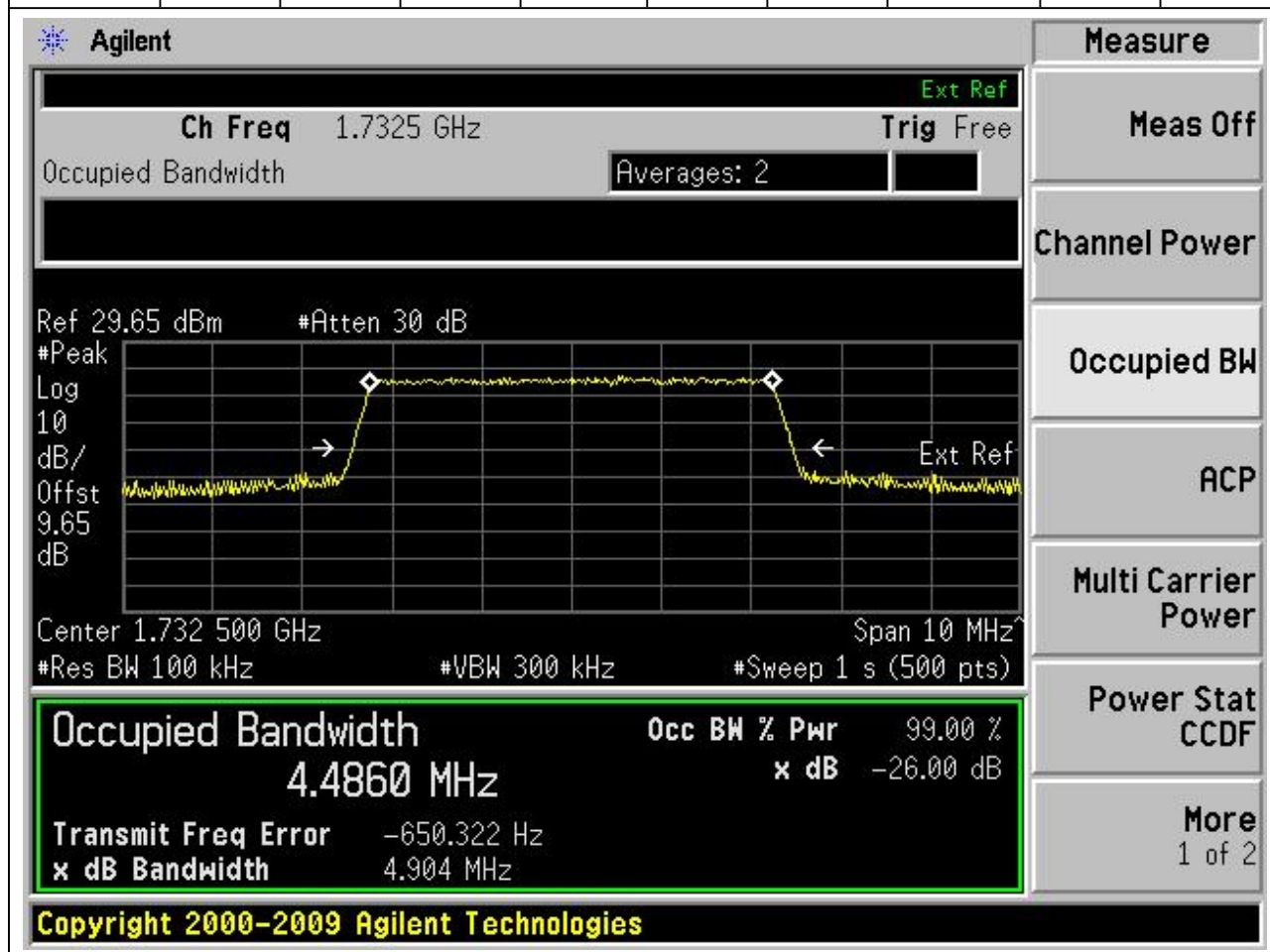
2.15. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.1	Peak	9.65	4.49	4.9	5	Pass



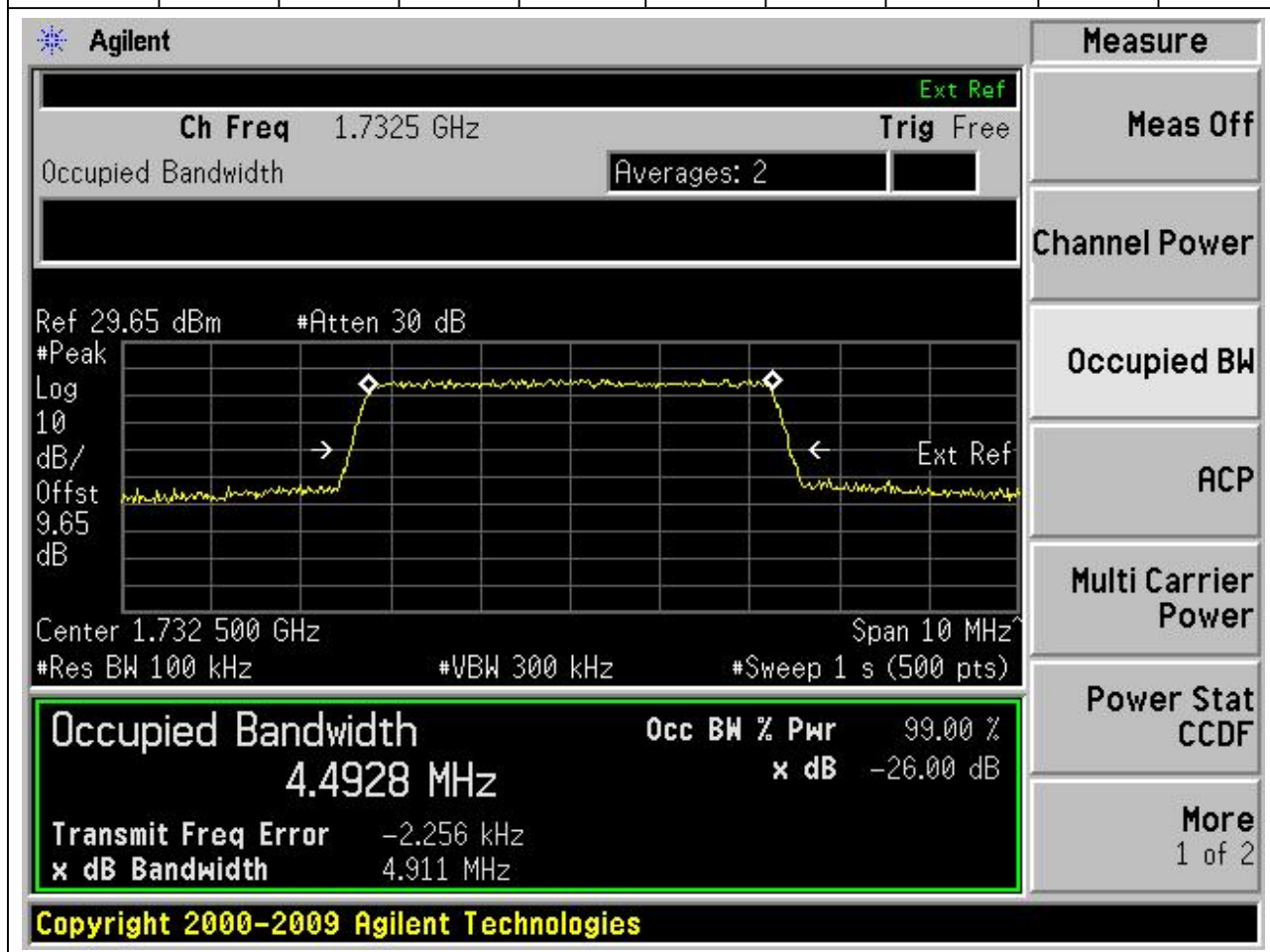
2.16. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.1	Peak	9.65	4.49	4.91	5	Pass



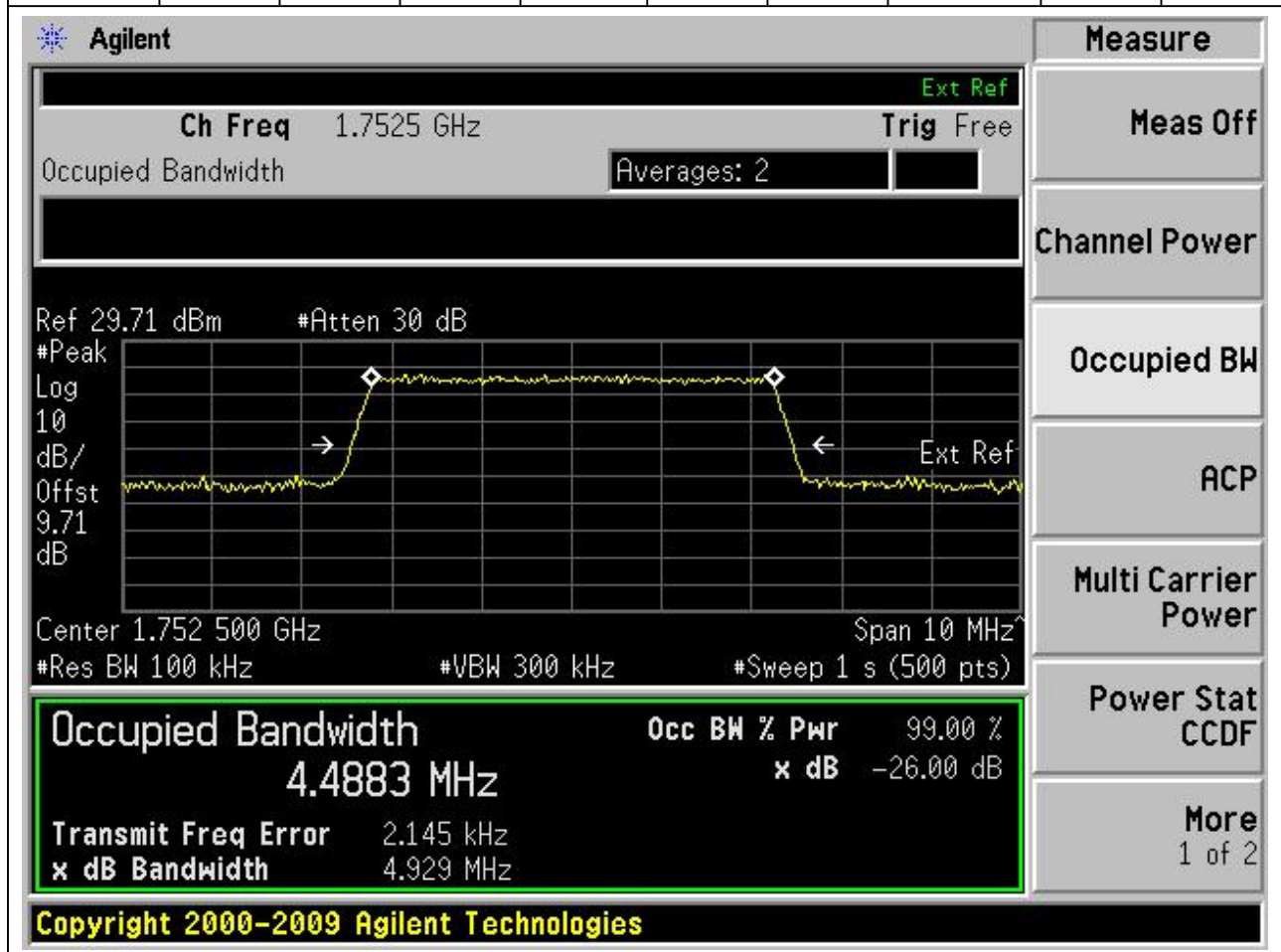
2.17. LTE Occupied Bandwidth_Part22-24-27(Channel:20375, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1752.5	99	26	0.1	Peak	9.71	4.49	4.93	5	Pass



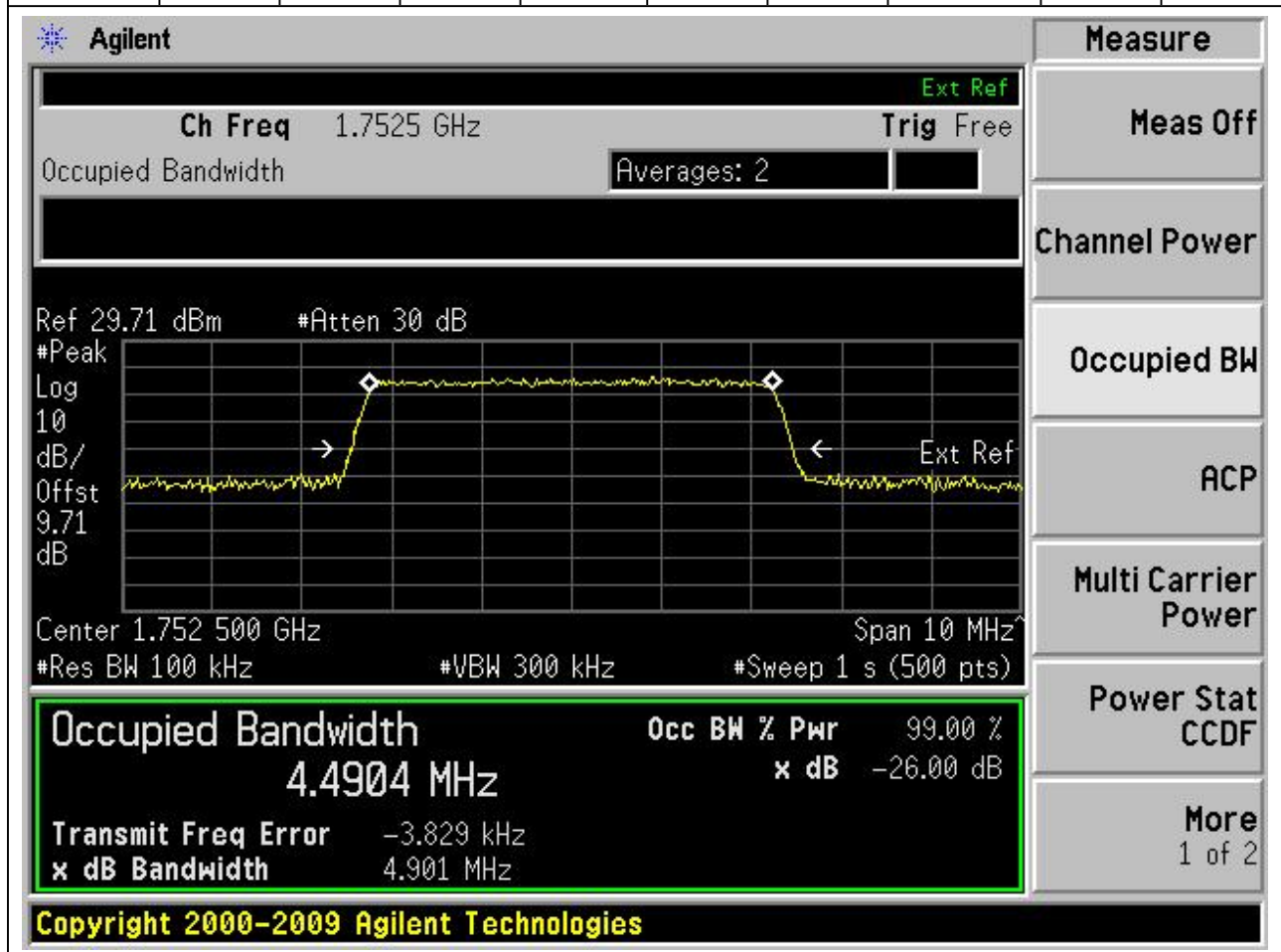
2.18. LTE Occupied Bandwidth_Part22-24-27(Channel:20375, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1752.5	99	26	0.1	Peak	9.71	4.49	4.9	5	Pass



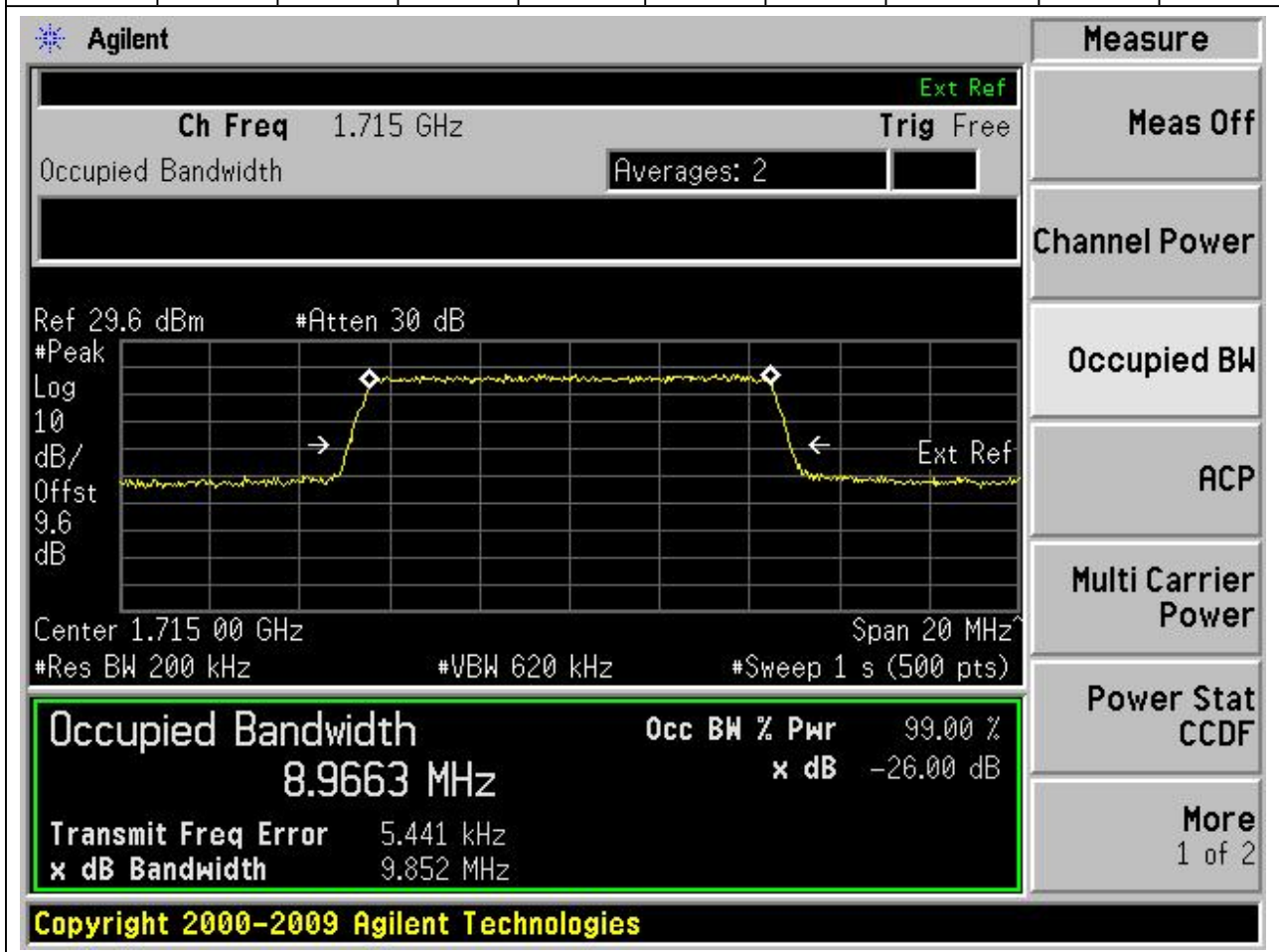
2.19. LTE Occupied Bandwidth_Part22-24-27(Channel:20000, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1715	99	26	0.2	Peak	9.6	8.97	9.85	10	Pass



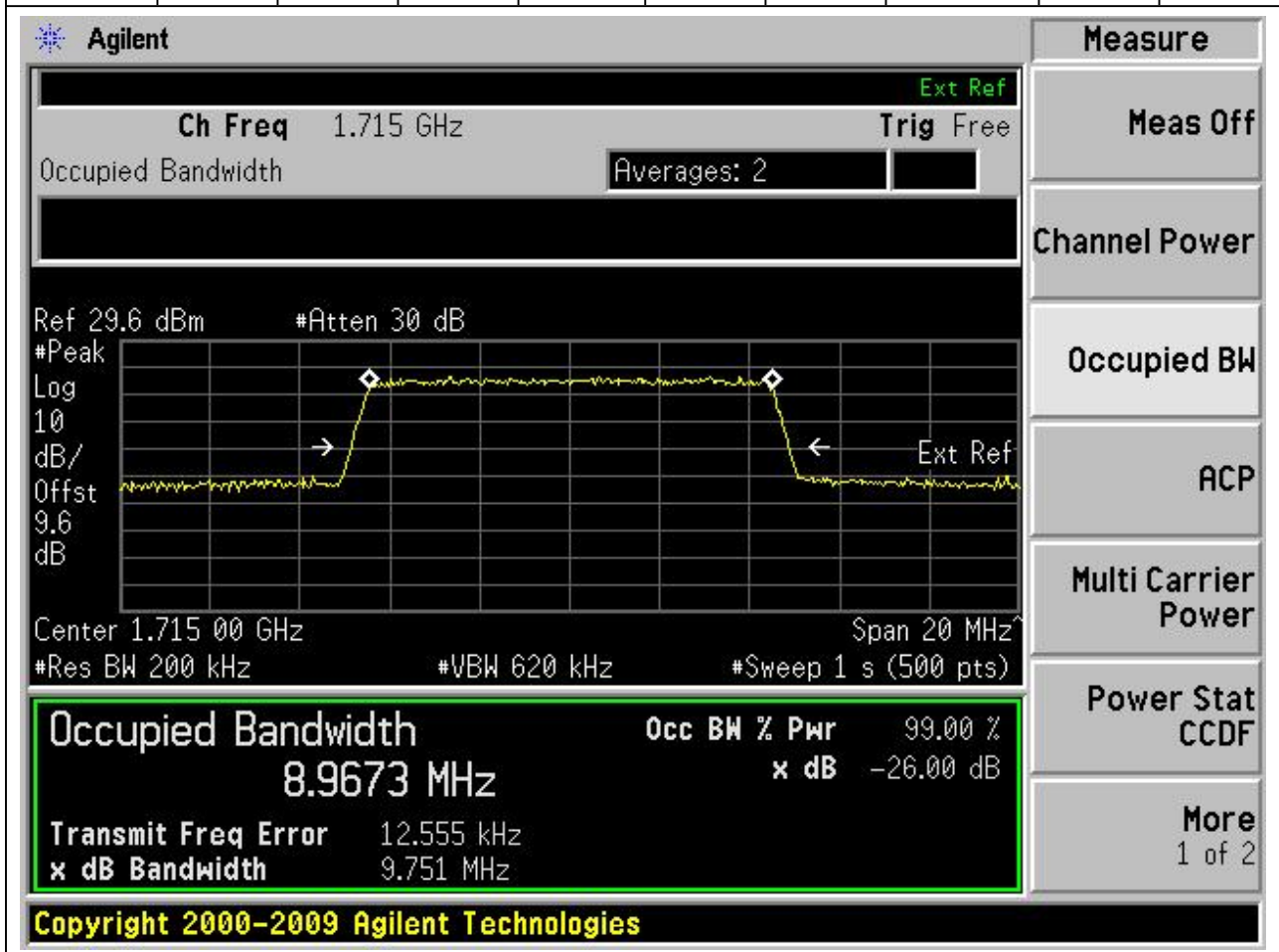
2.20. LTE Occupied Bandwidth_Part22-24-27(Channel:20000, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1715	99	26	0.2	Peak	9.6	8.97	9.75	10	Pass



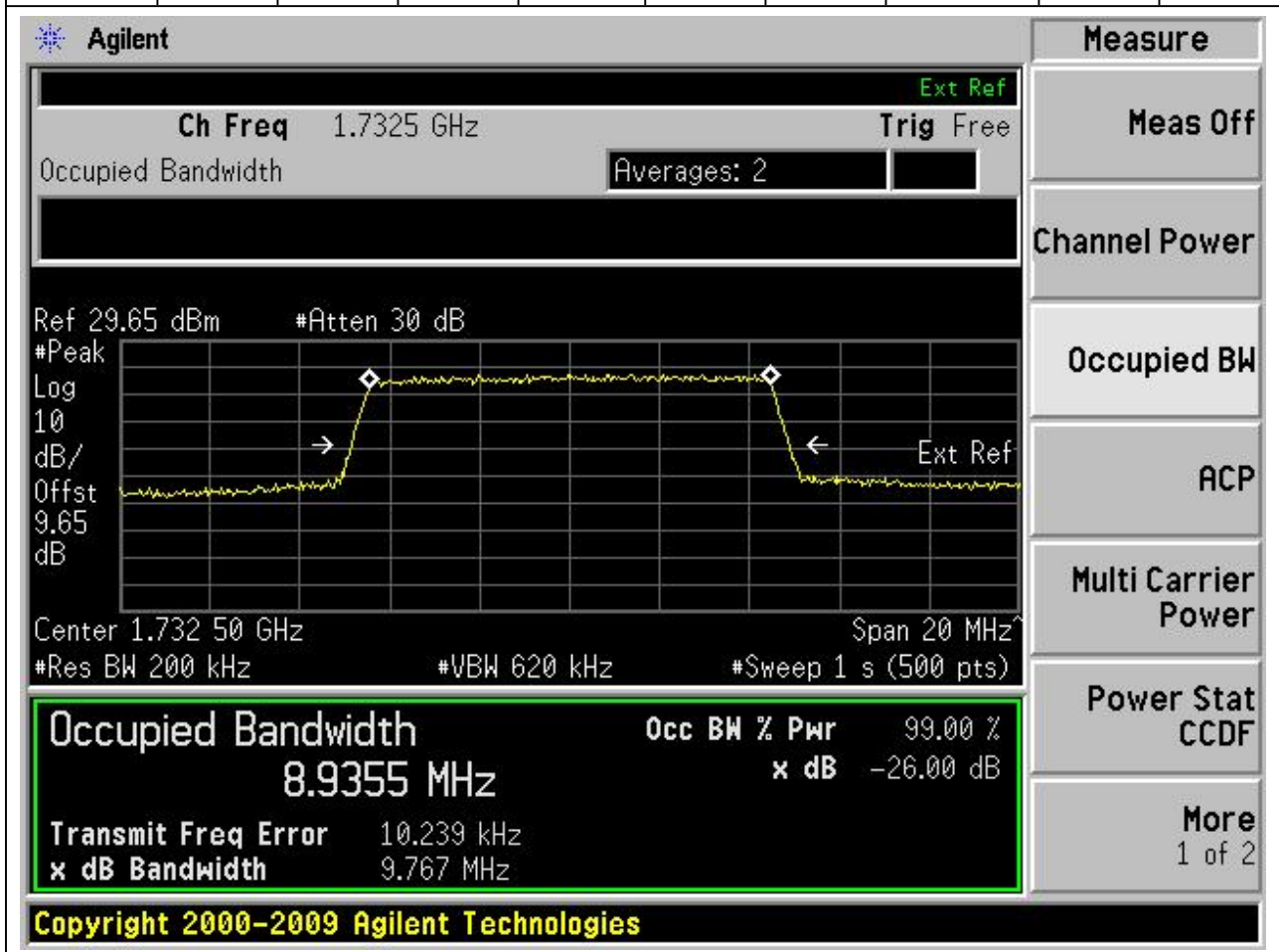
2.21. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.2	Peak	9.65	8.94	9.77	10	Pass



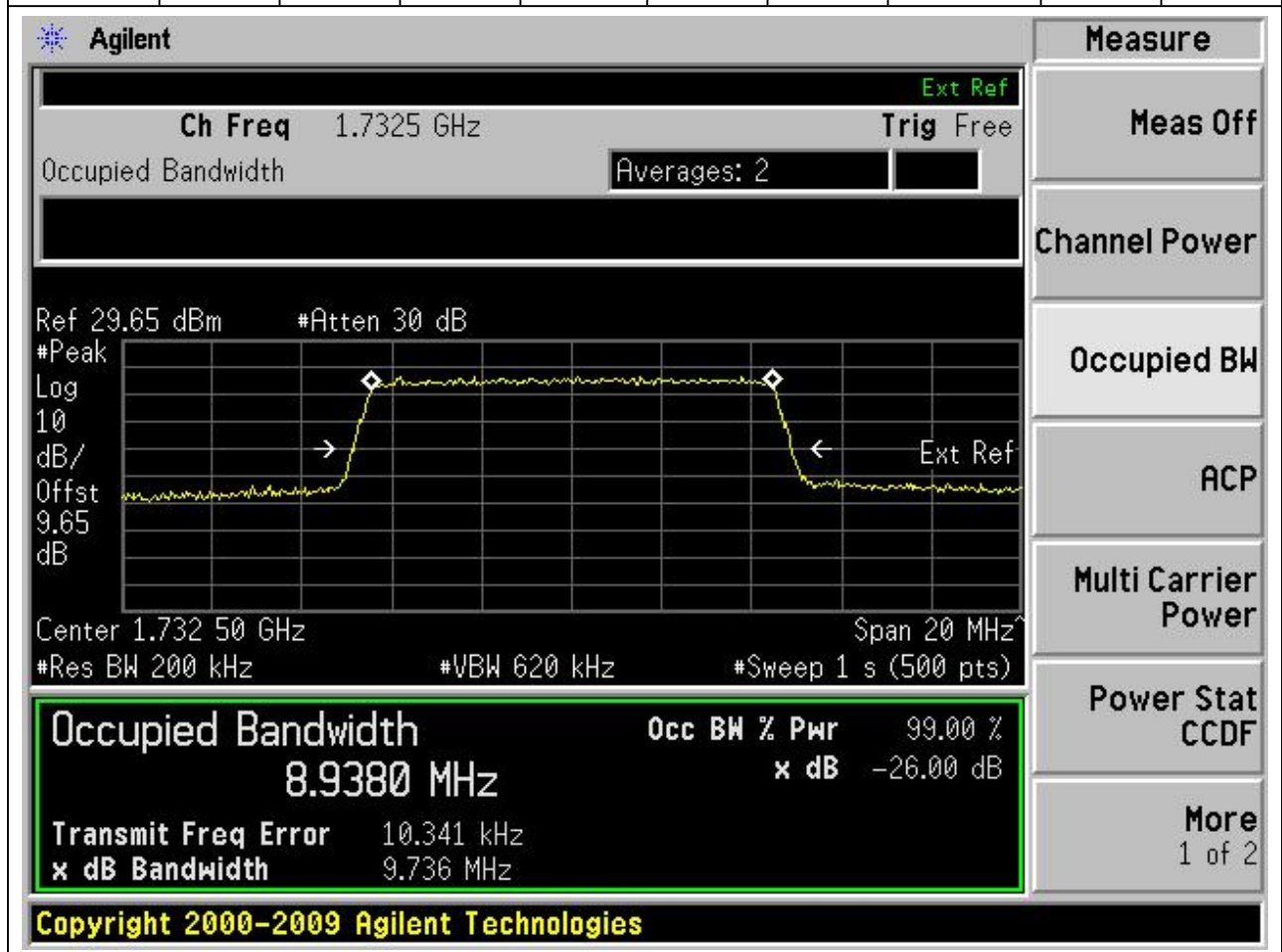
2.22. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.2	Peak	9.65	8.94	9.74	10	Pass



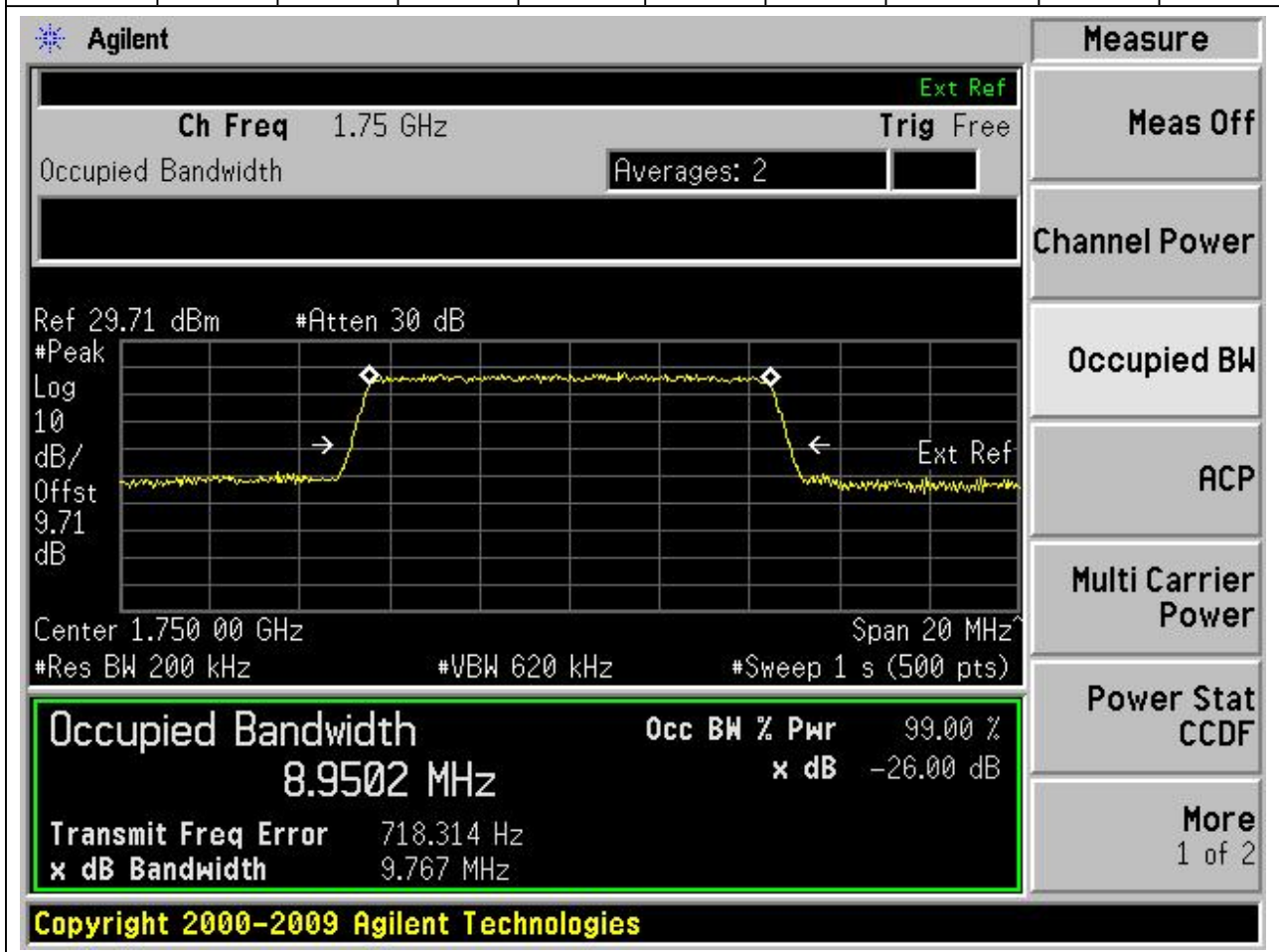
2.23. LTE Occupied Bandwidth_Part22-24-27(Channel:20350, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1750	99	26	0.2	Peak	9.71	8.95	9.77	10	Pass



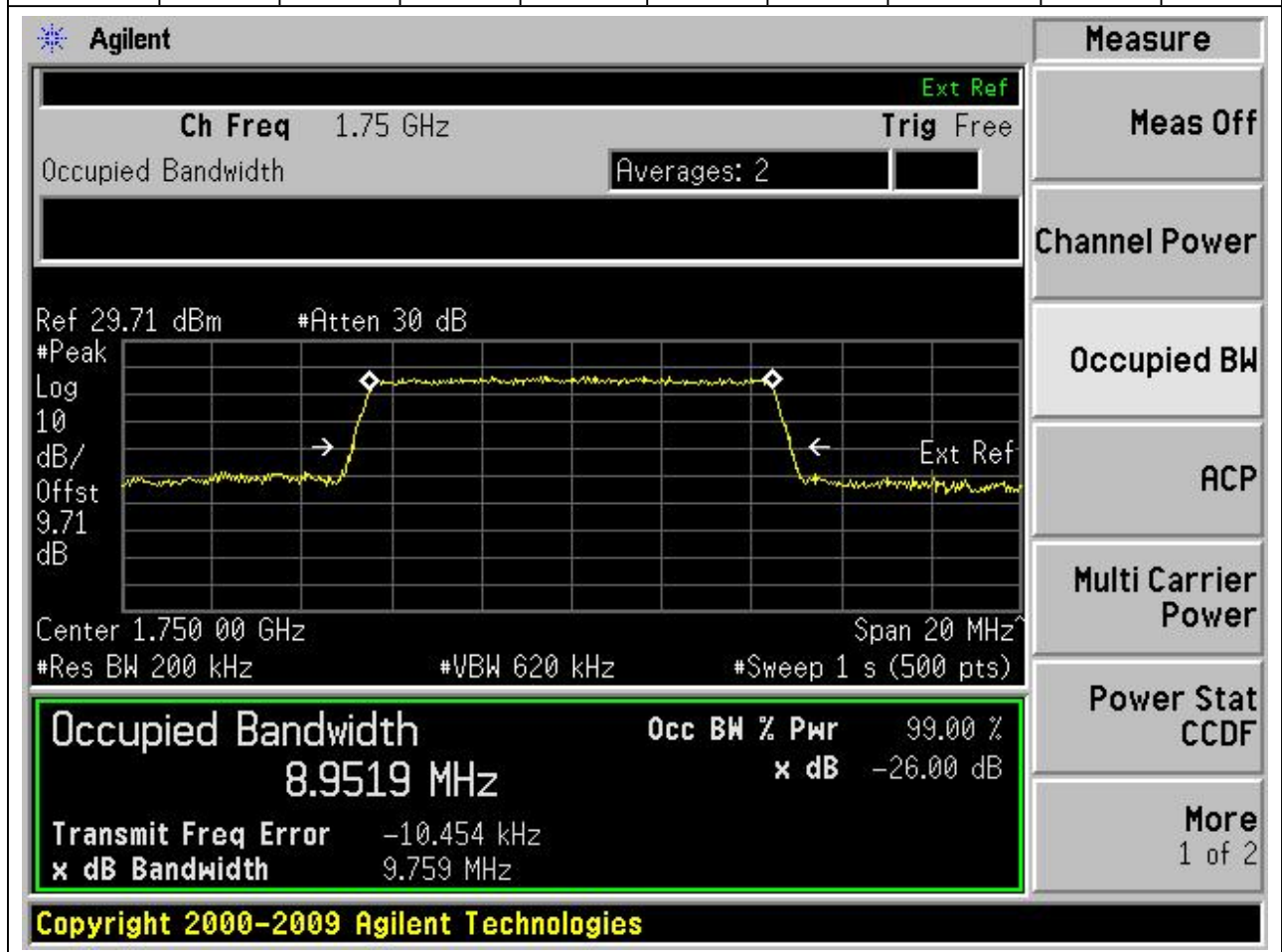
2.24. LTE Occupied Bandwidth_Part22-24-27(Channel:20350, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1750	99	26	0.2	Peak	9.71	8.95	9.76	10	Pass



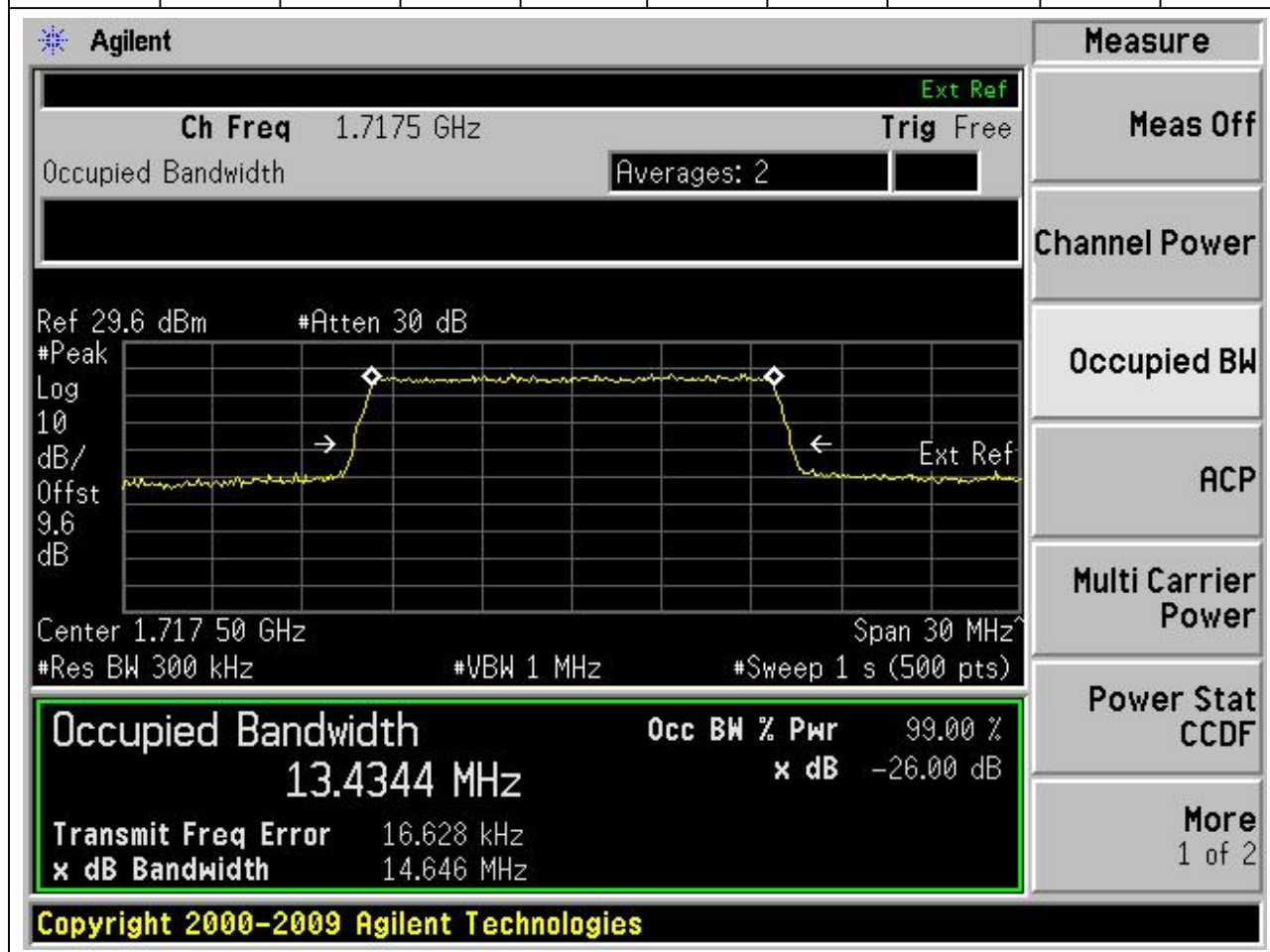
2.25. LTE Occupied Bandwidth_Part22-24-27(Channel:20025, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1717.5	99	26	0.3	Peak	9.6	13.43	14.65	15	Pass



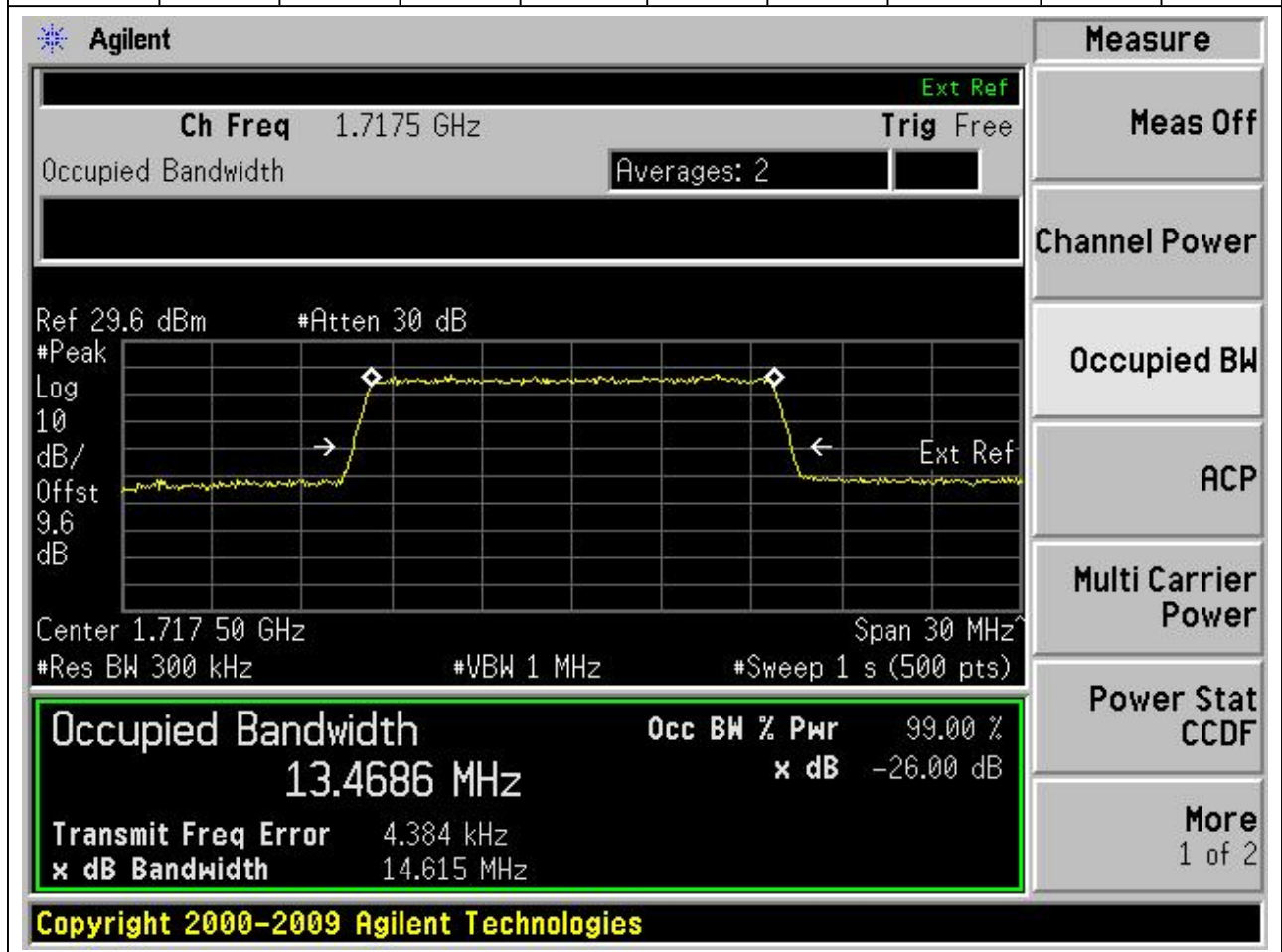
2.26. LTE Occupied Bandwidth_Part22-24-27(Channel:20025, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1717.5	99	26	0.3	Peak	9.6	13.47	14.61	15	Pass



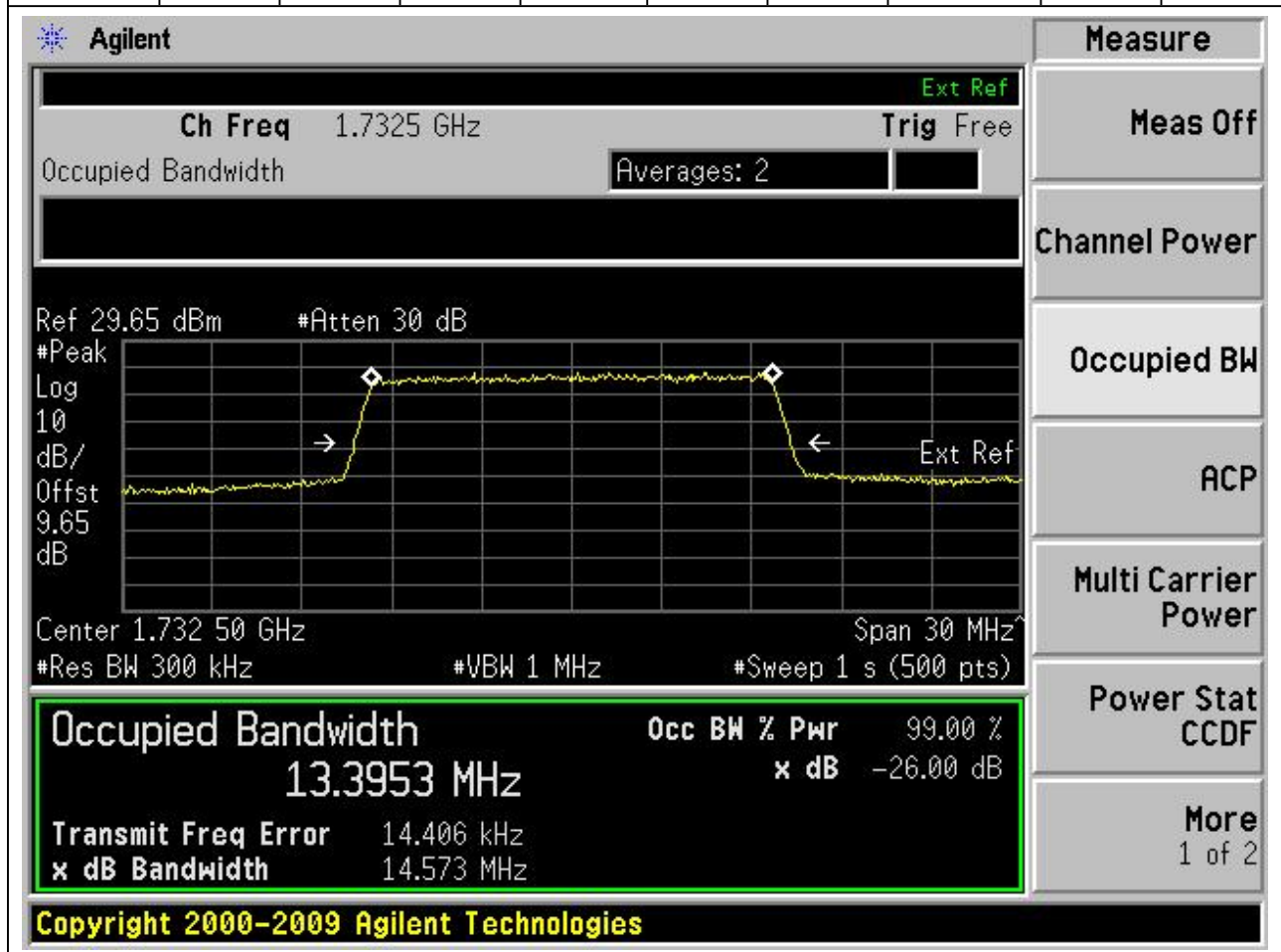
2.27. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.3	Peak	9.65	13.4	14.57	15	Pass



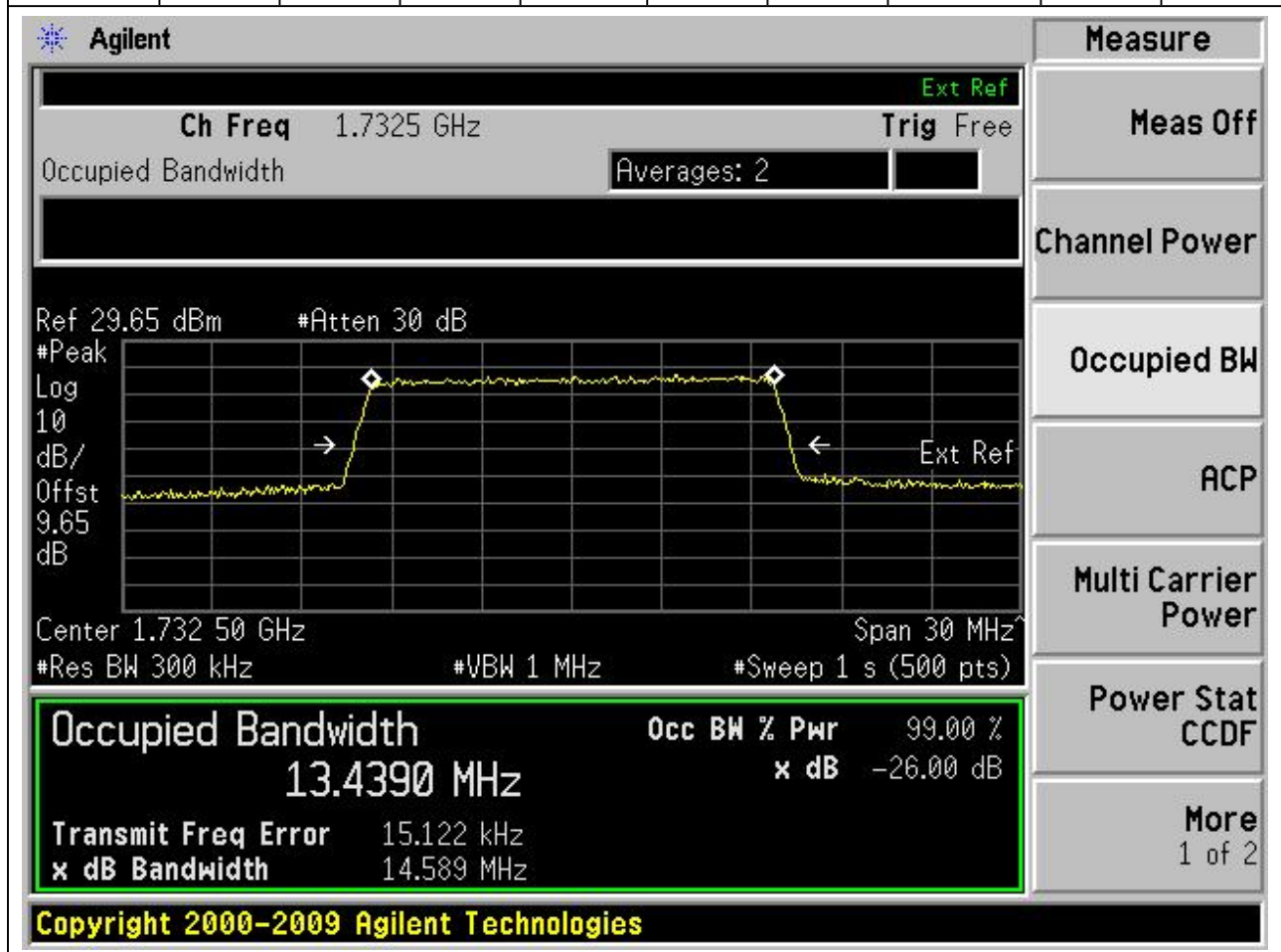
2.28. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.3	Peak	9.65	13.44	14.59	15	Pass



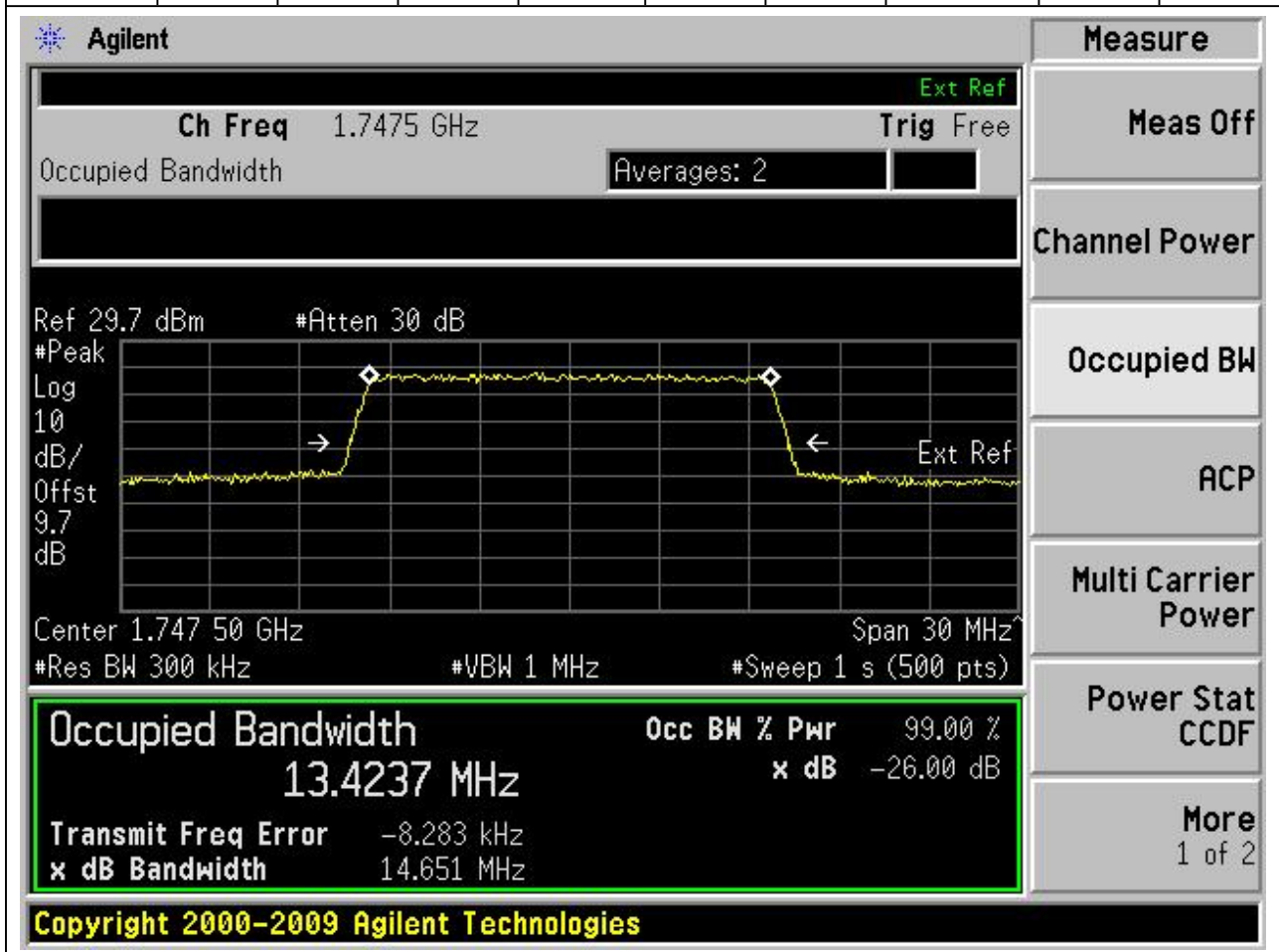
2.29. LTE Occupied Bandwidth_Part22-24-27(Channel:20325, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1747.5	99	26	0.3	Peak	9.7	13.42	14.65	15	Pass



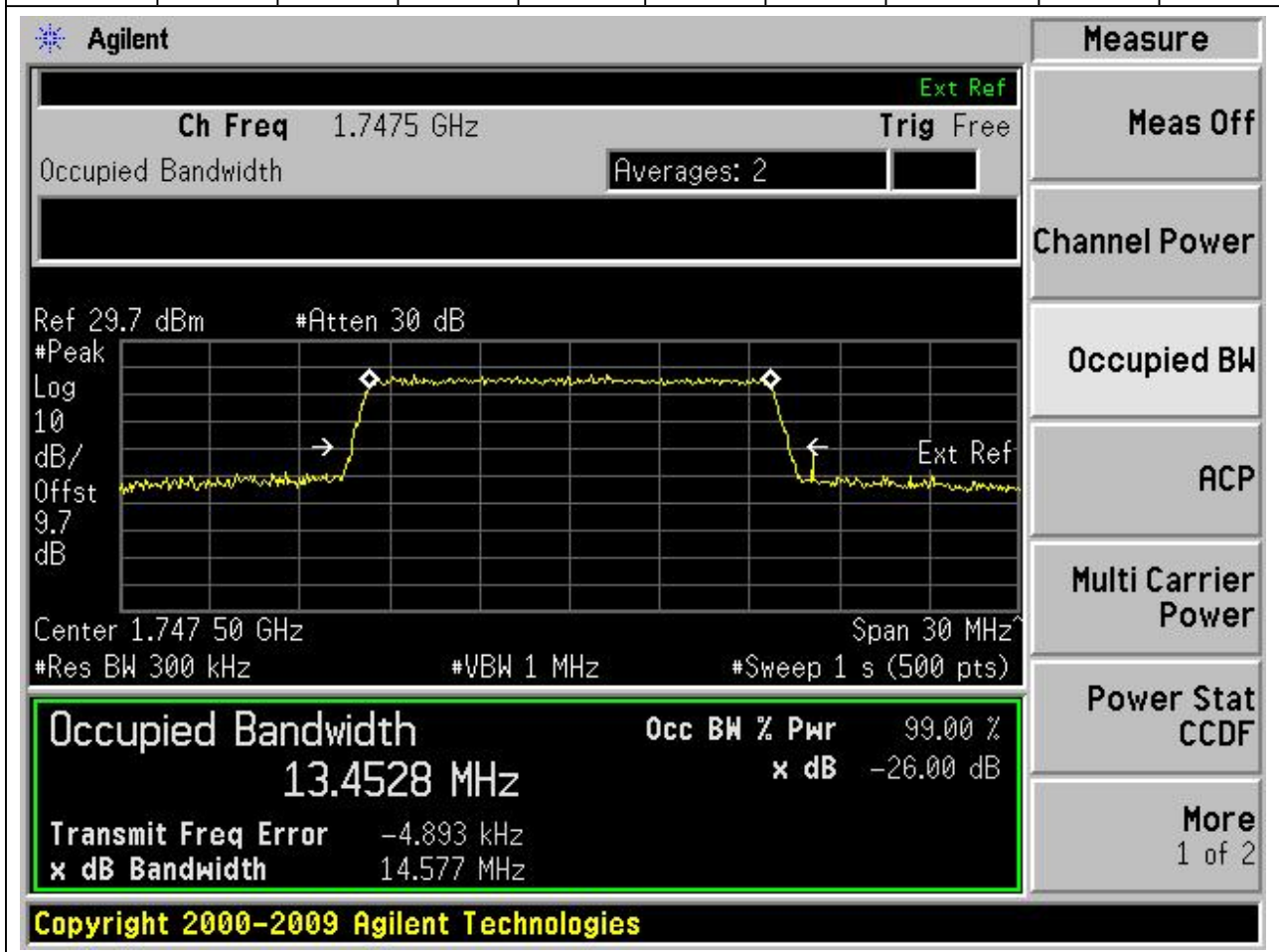
2.30. LTE Occupied Bandwidth_Part22-24-27(Channel:20325, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1747.5	99	26	0.3	Peak	9.7	13.45	14.58	15	Pass



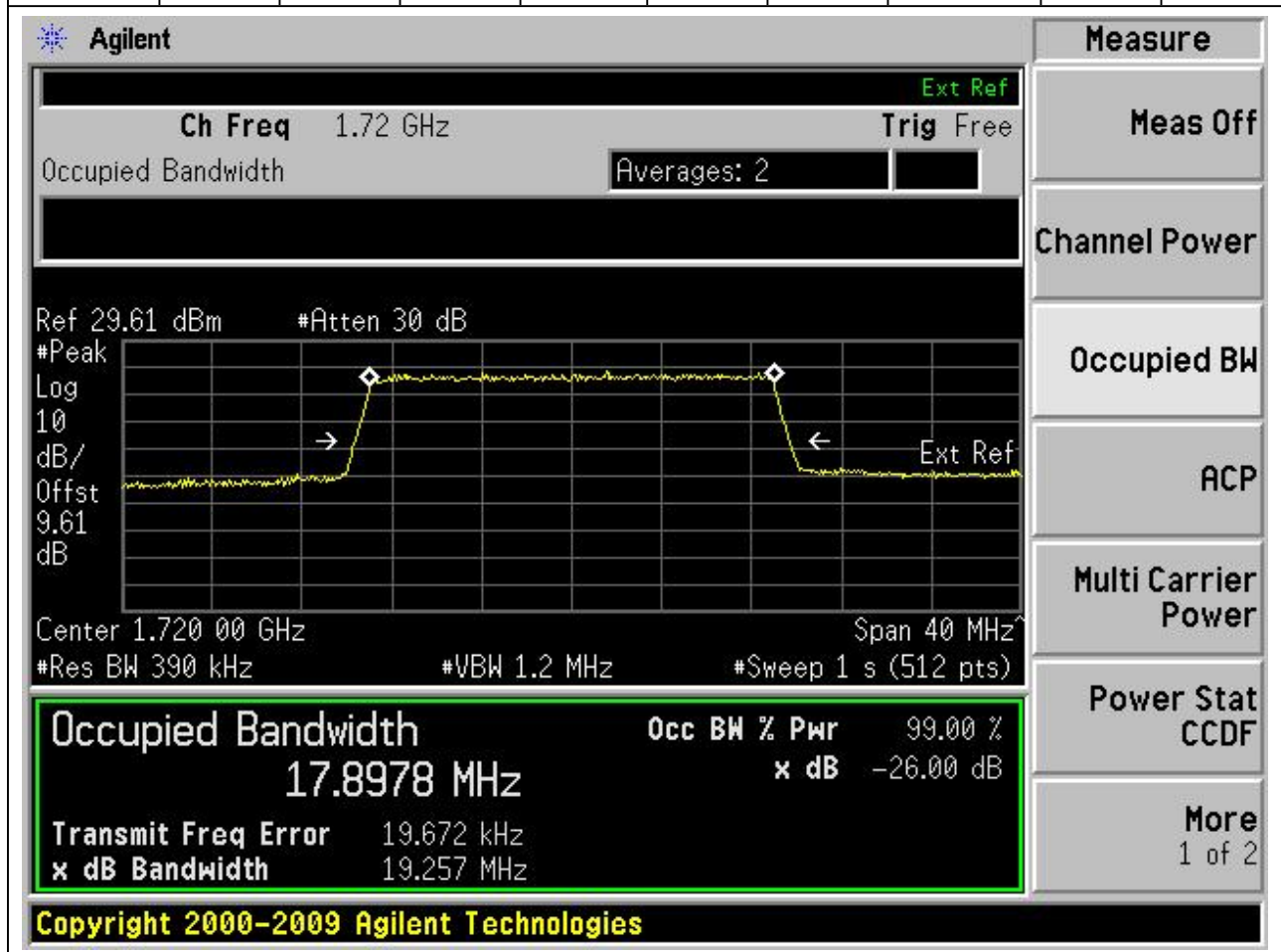
2.31. LTE Occupied Bandwidth_Part22-24-27(Channel:20050, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1720	99	26	0.39	Peak	9.61	17.9	19.26	20	Pass



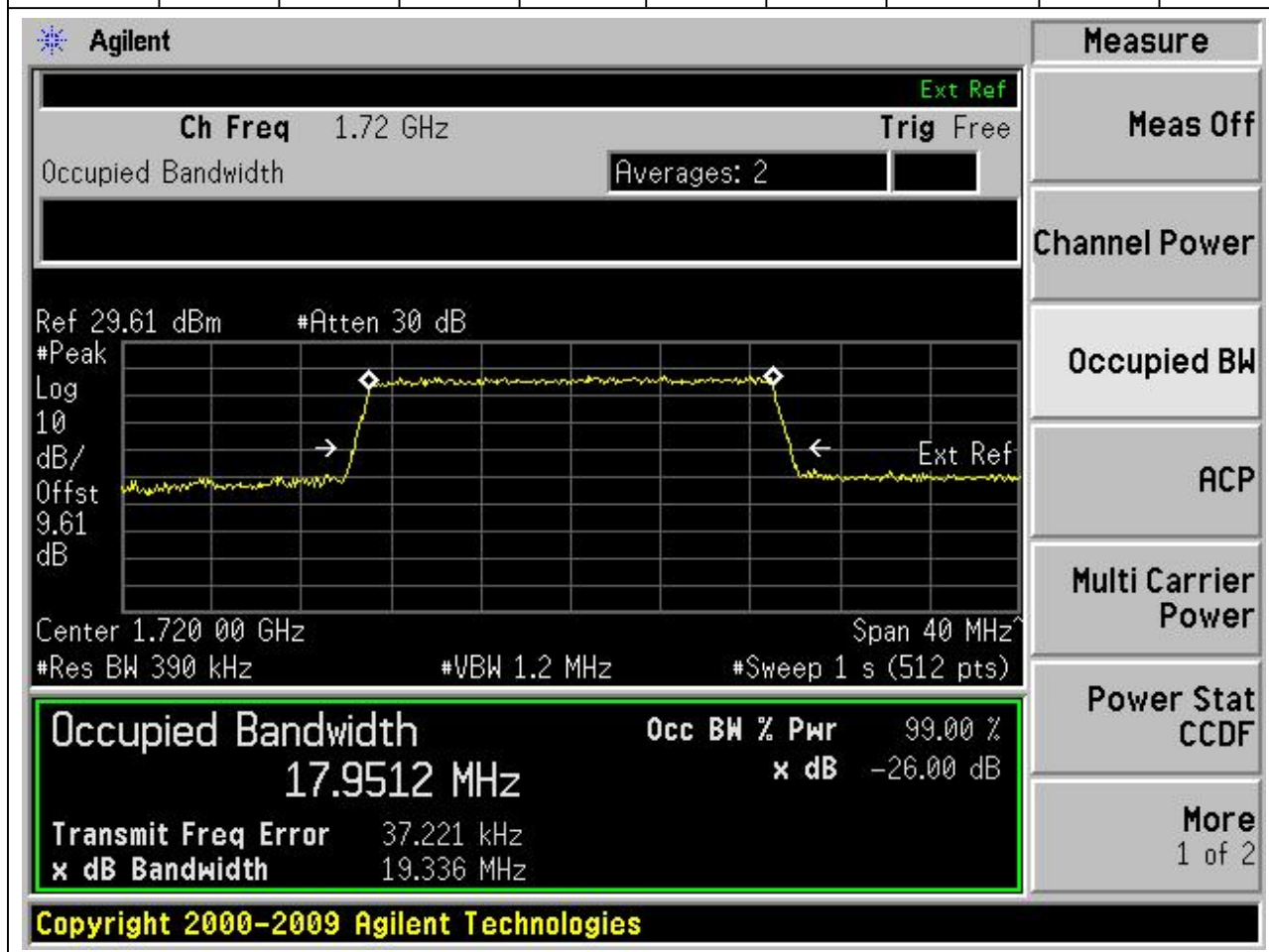
2.32. LTE Occupied Bandwidth_Part22-24-27(Channel:20050, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1720	99	26	0.39	Peak	9.61	17.95	19.34	20	Pass



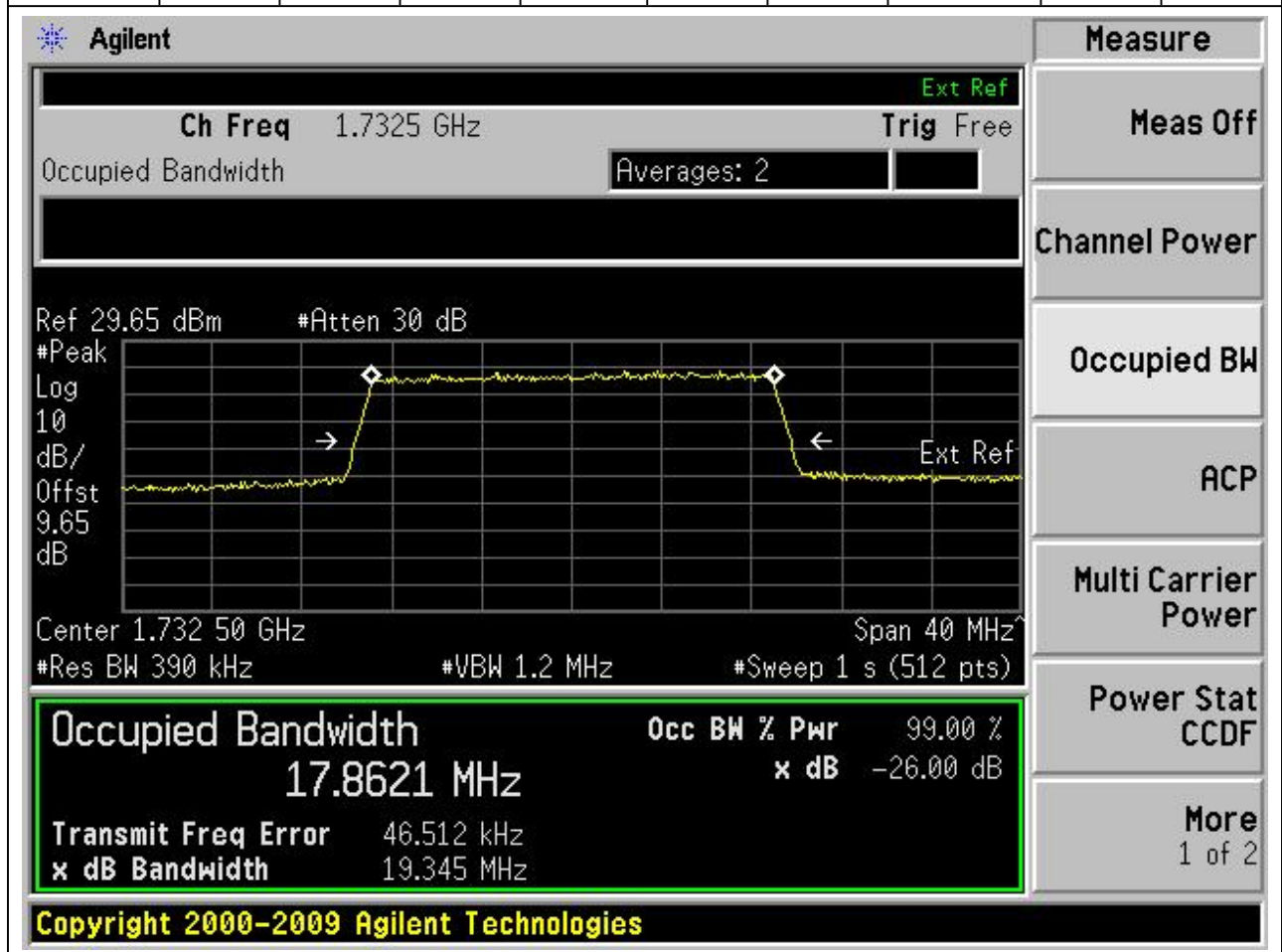
2.33. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.39	Peak	9.65	17.86	19.34	20	Pass



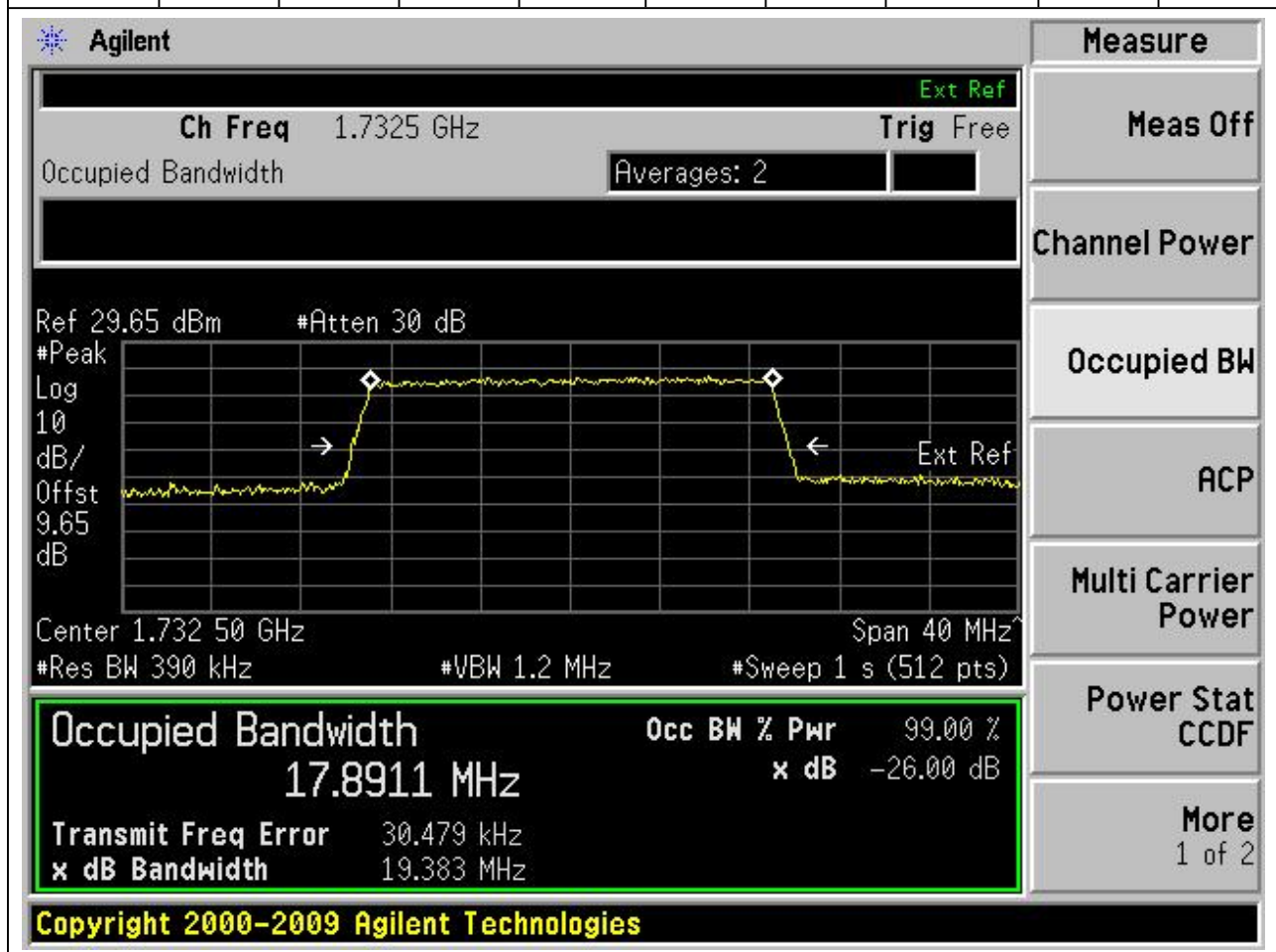
2.34. LTE Occupied Bandwidth_Part22-24-27(Channel:20175, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1732.5	99	26	0.39	Peak	9.65	17.89	19.38	20	Pass



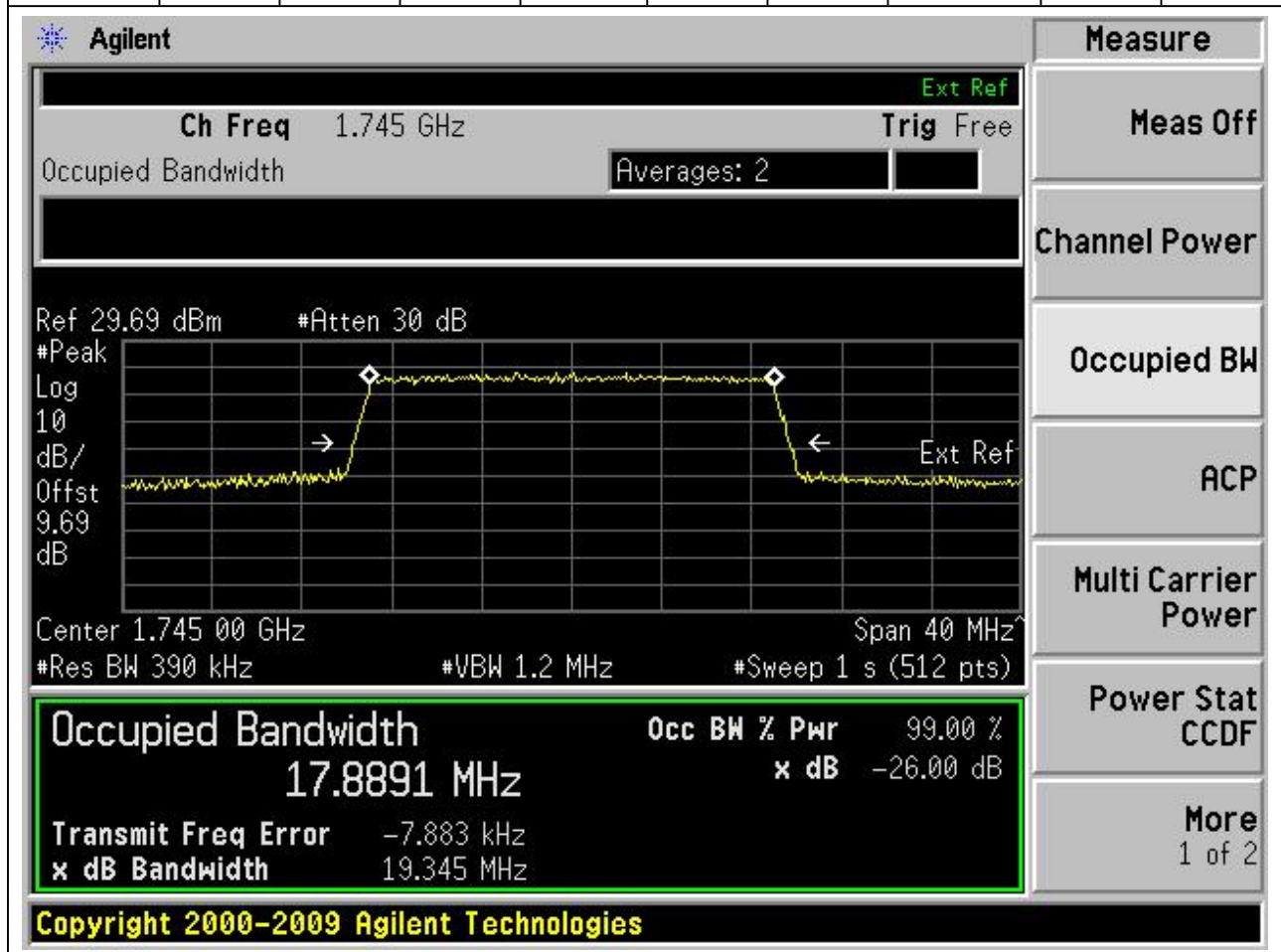
2.35. LTE Occupied Bandwidth_Part22-24-27(Channel:20300, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1745	99	26	0.39	Peak	9.69	17.89	19.34	20	Pass



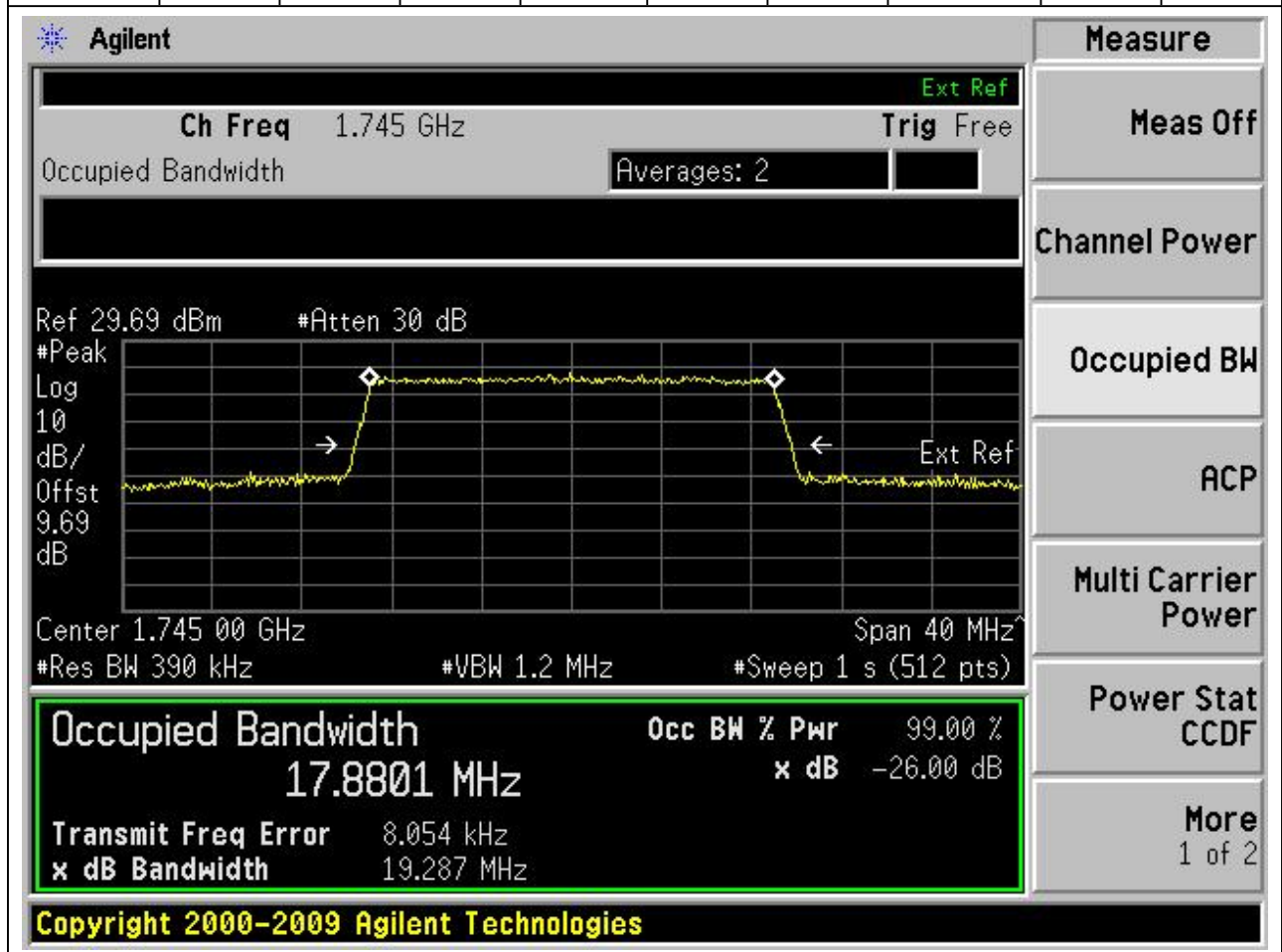
2.36. LTE Occupied Bandwidth_Part22-24-27(Channel:20300, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
1745	99	26	0.39	Peak	9.69	17.88	19.29	20	Pass



3. LTE_Band5

EUT Sample No.:	
EUT Name:	
EUT Manufacturer:	
EUT Model:	
EUT Serial Number:	
EUT Hardware Version:	
EUT Software Version:	
Low Temperature(LT):	-10 °C
Normal Temperature(NT):	+25 °C
High Temperature(HT):	+55 °C
Low Voltage(LV):	3.6 V
Normal Voltage(NV):	3.8 V
High Voltage(HV):	4.2 V

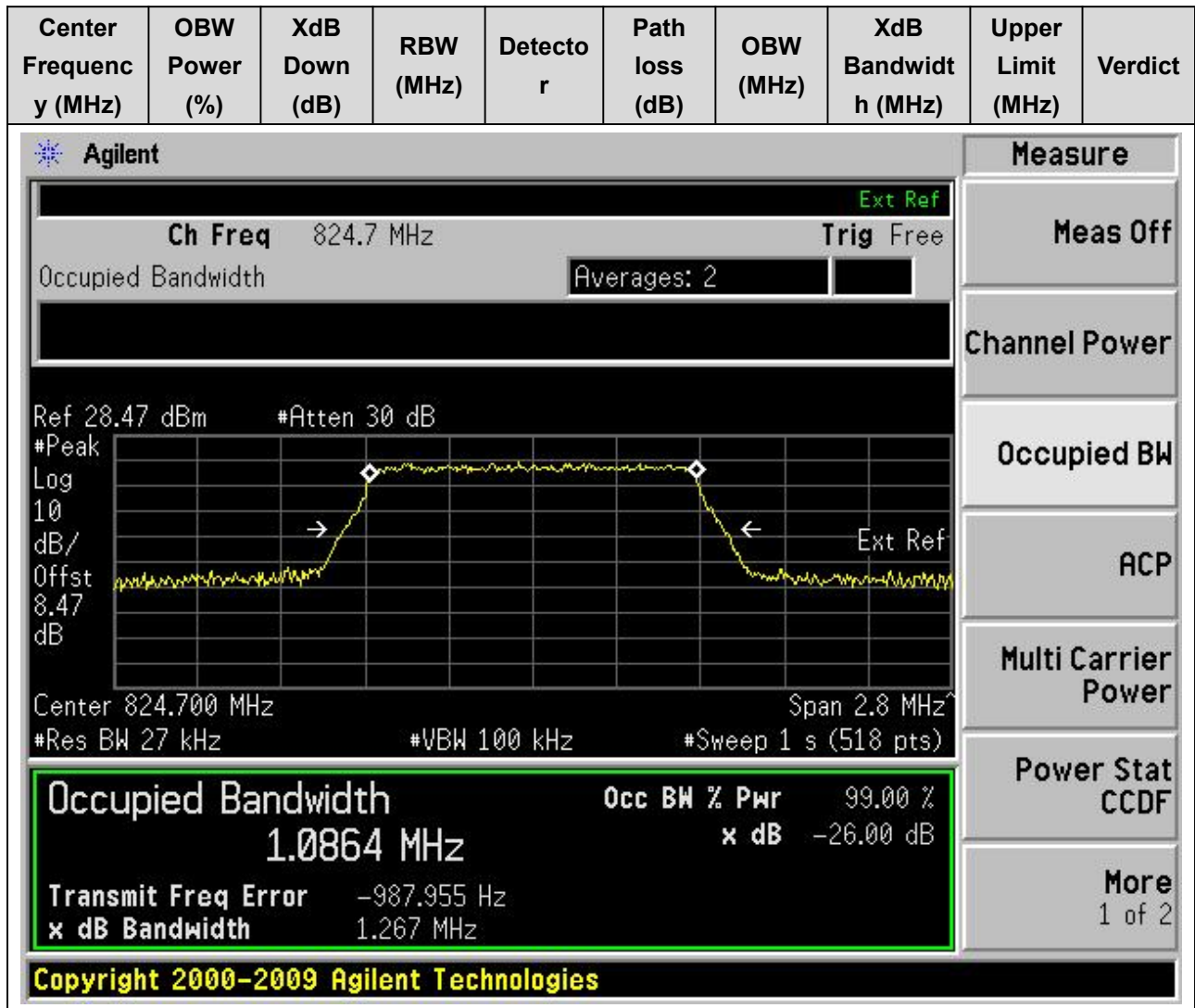
3.1. LTE Occupied Bandwidth_Part22-24-27(Channel:20407, Bandwidth:1.4, Modulation:QPSK, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
824.7	99	26	0.027	Peak	8.47	1.09	1.27	1.4	Pass



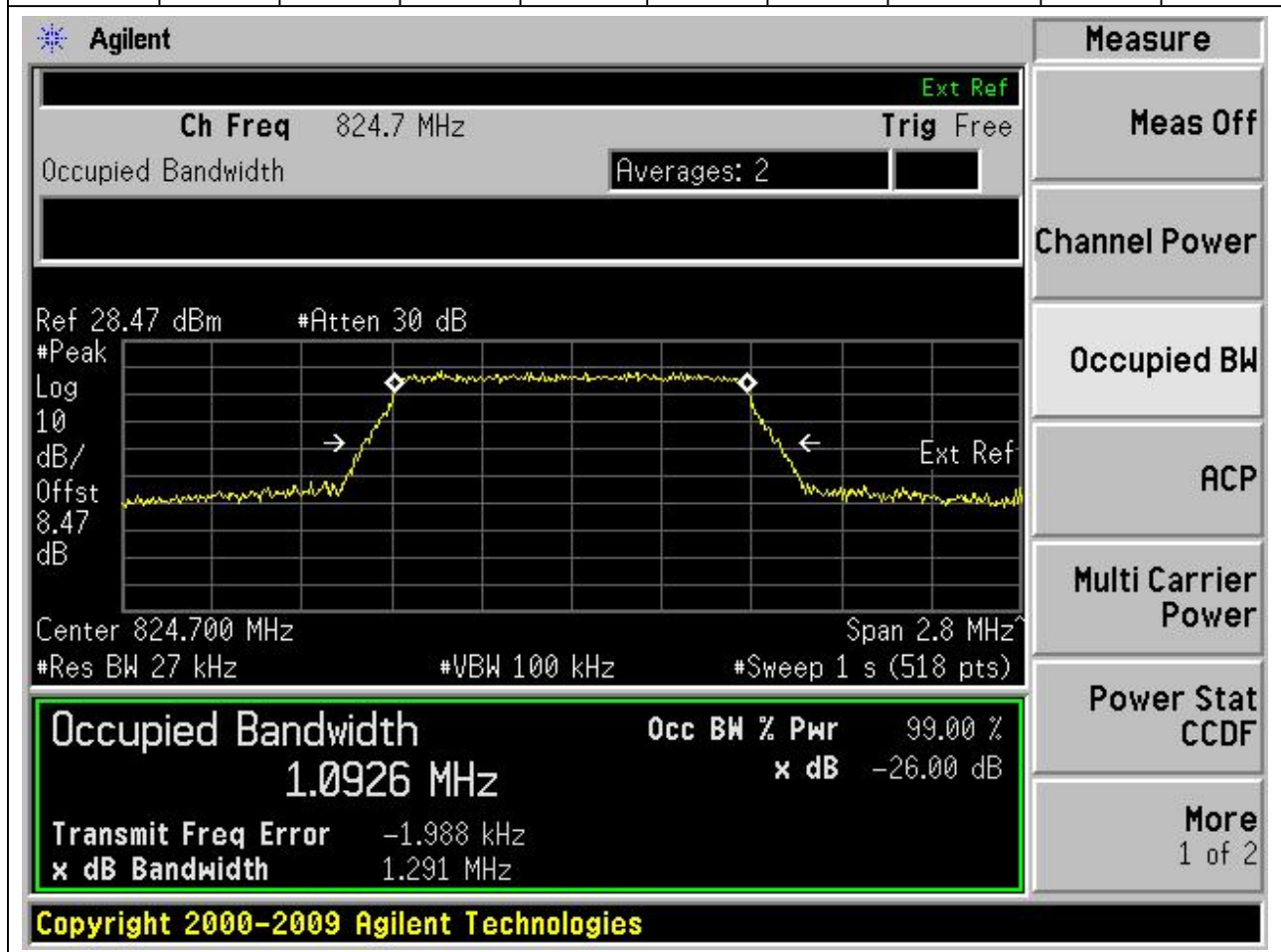
3.2. LTE Occupied Bandwidth_Part22-24-27(Channel:20407, Bandwidth:1.4, Modulation:16QAM, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
824.7	99	26	0.027	Peak	8.47	1.09	1.29	1.4	Pass



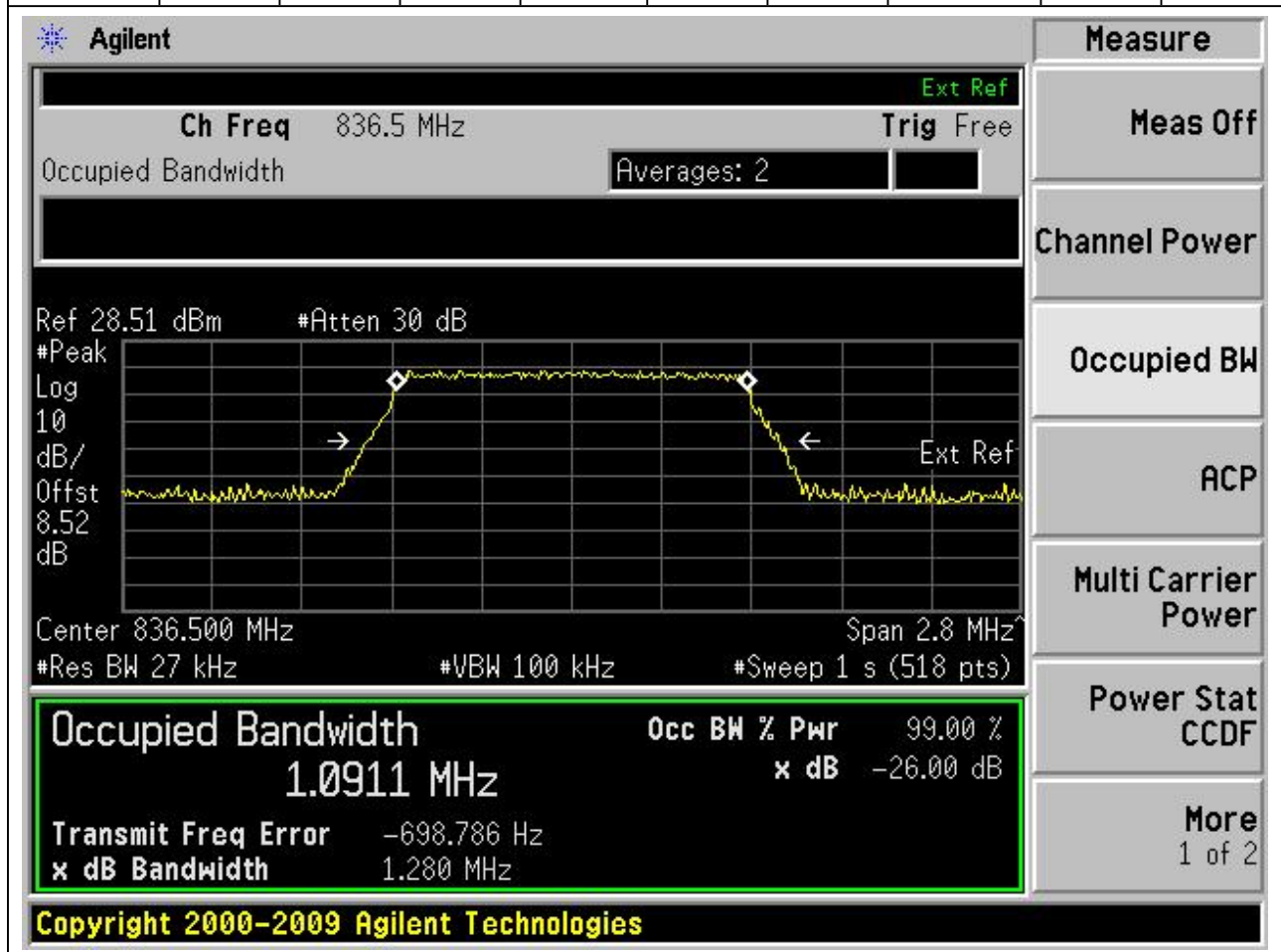
3.3. LTE Occupied Bandwidth_Part22-24-27(Channel:20525, Bandwidth:1.4, Modulation:QPSK, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
836.5	99	26	0.027	Peak	8.52	1.09	1.28	1.4	Pass



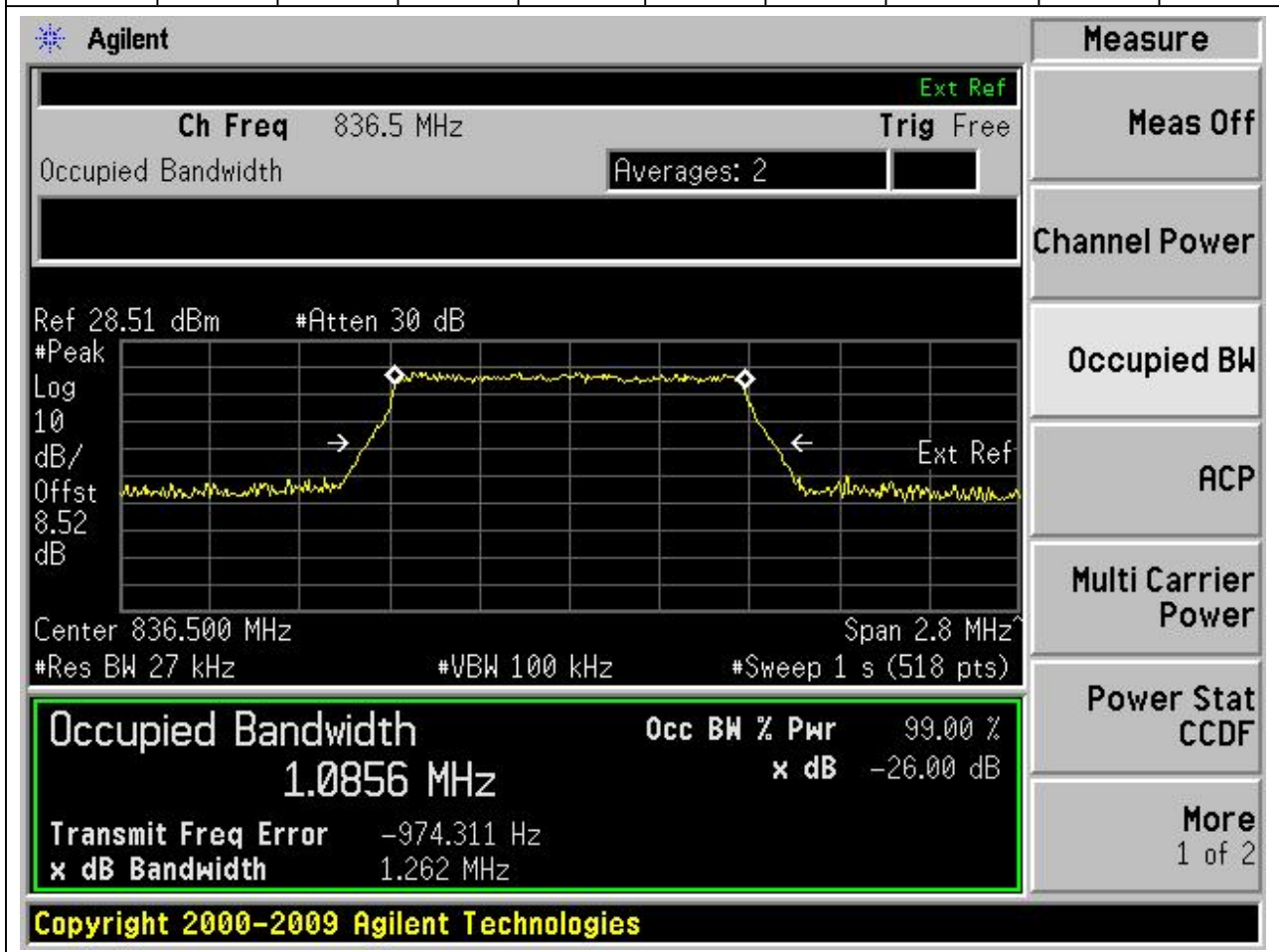
3.4. LTE Occupied Bandwidth_Part22-24-27(Channel:20525, Bandwidth:1.4, Modulation:16QAM, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
836.5	99	26	0.027	Peak	8.52	1.09	1.26	1.4	Pass



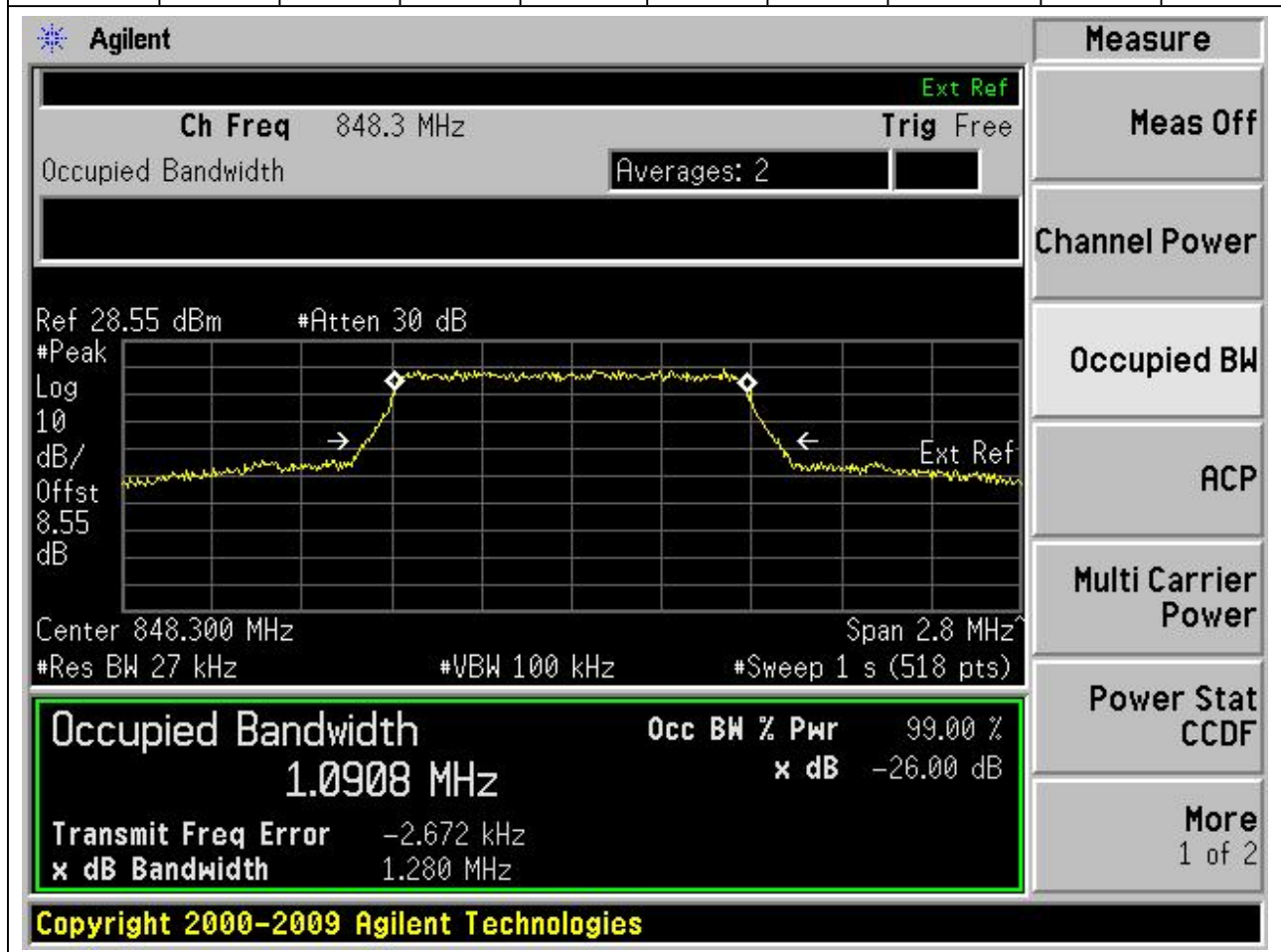
3.5. LTE Occupied Bandwidth_Part22-24-27(Channel:20643, Bandwidth:1.4, Modulation:QPSK, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
848.3	99	26	0.027	Peak	8.55	1.09	1.28	1.4	Pass



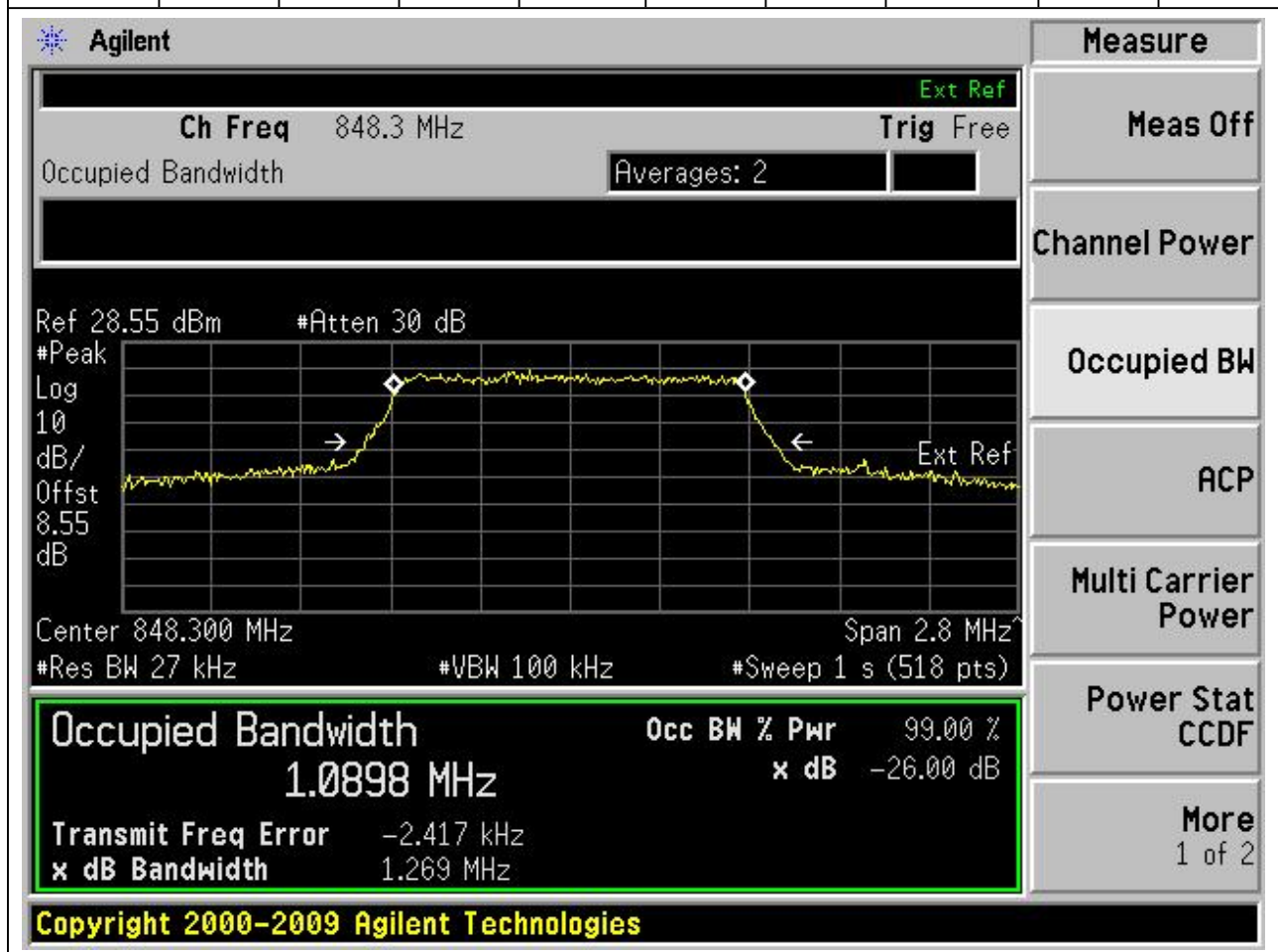
3.6. LTE Occupied Bandwidth_Part22-24-27(Channel:20643, Bandwidth:1.4, Modulation:16QAM, RB Number:6, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
848.3	99	26	0.027	Peak	8.55	1.09	1.27	1.4	Pass



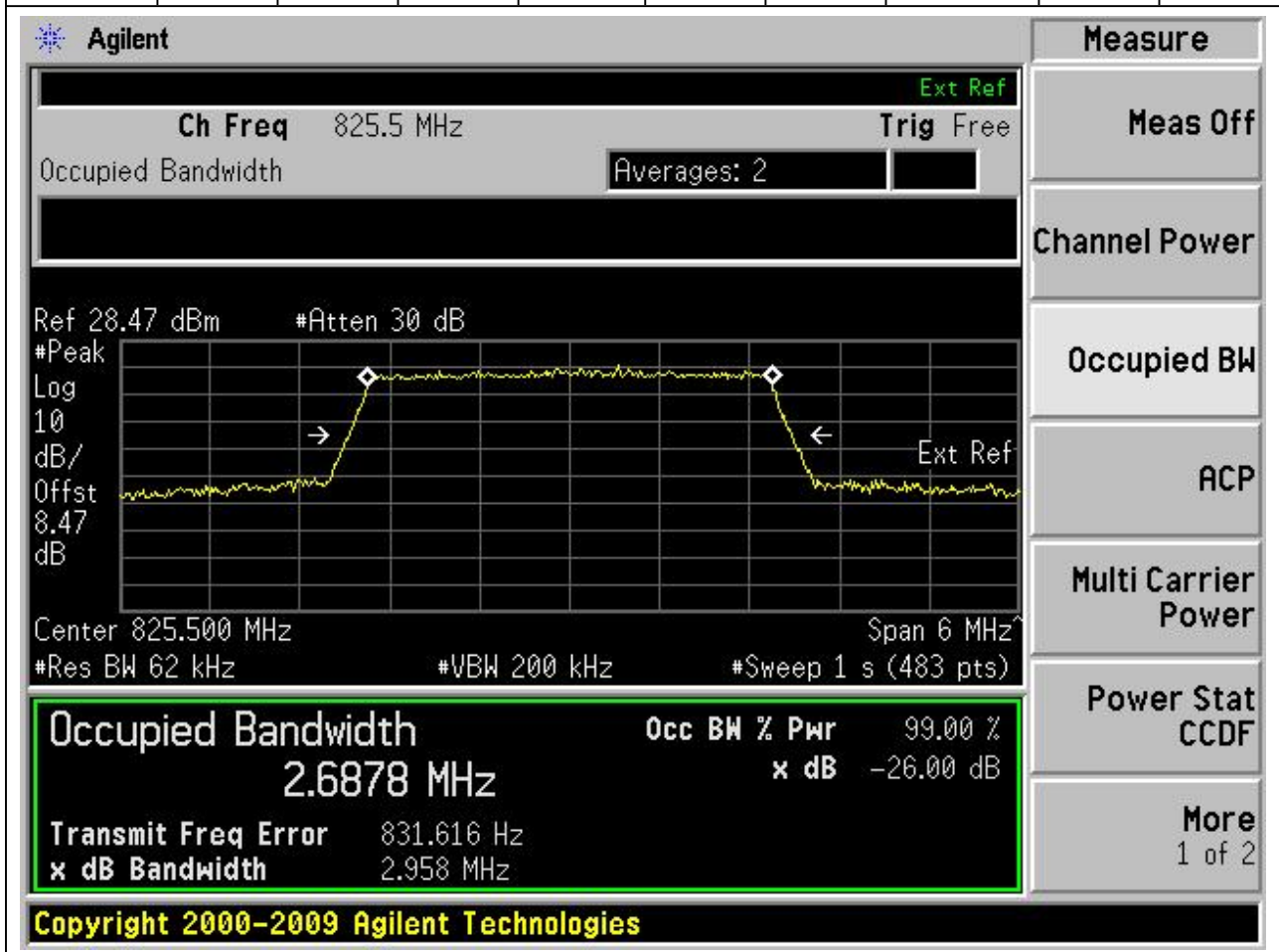
3.7. LTE Occupied Bandwidth_Part22-24-27(Channel:20415, Bandwidth:3, Modulation:QPSK, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
825.5	99	26	0.062	Peak	8.47	2.69	2.96	3	Pass



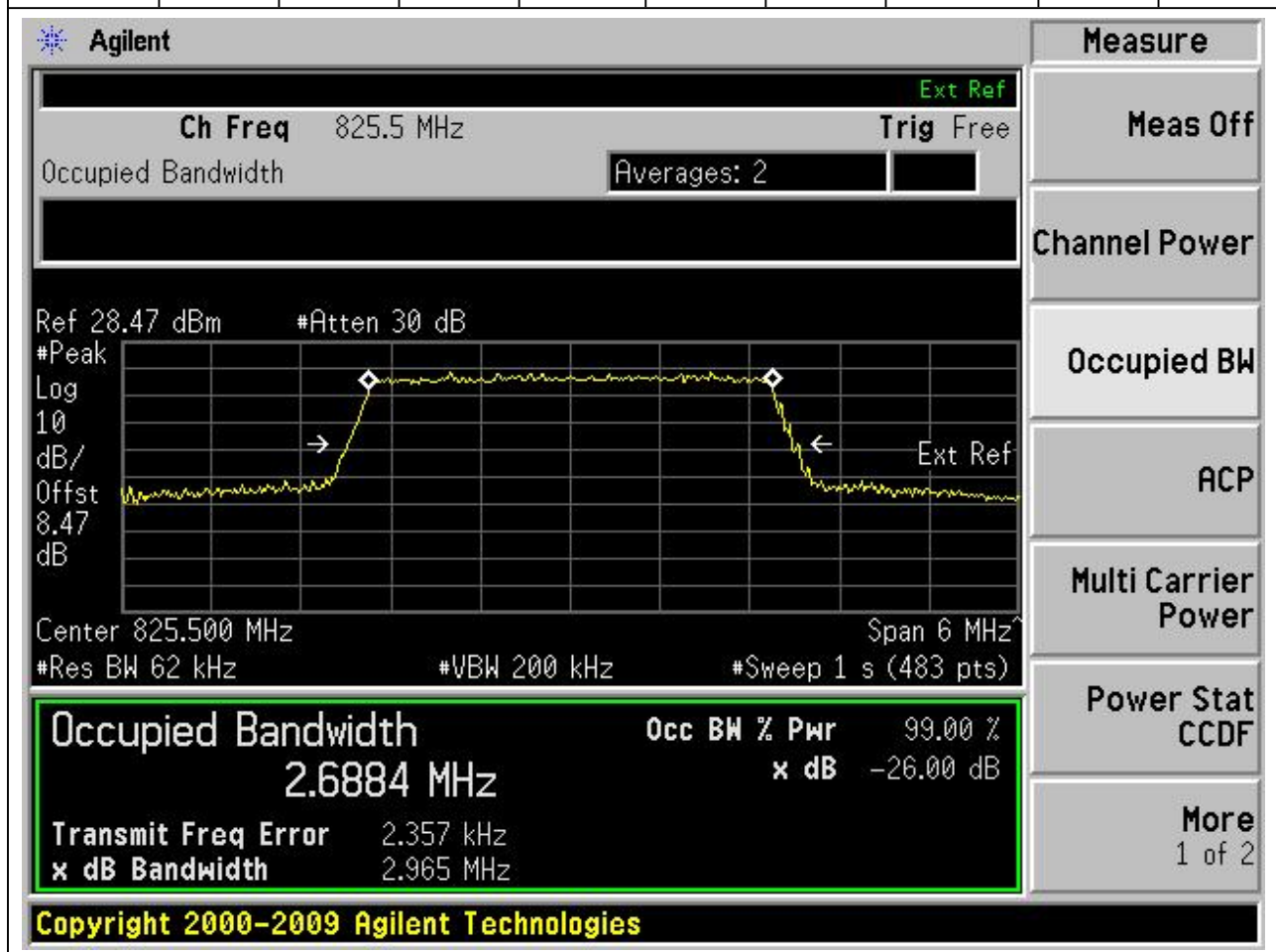
3.8. LTE Occupied Bandwidth_Part22-24-27(Channel:20415, Bandwidth:3, Modulation:16QAM, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
825.5	99	26	0.062	Peak	8.47	2.69	2.96	3	Pass



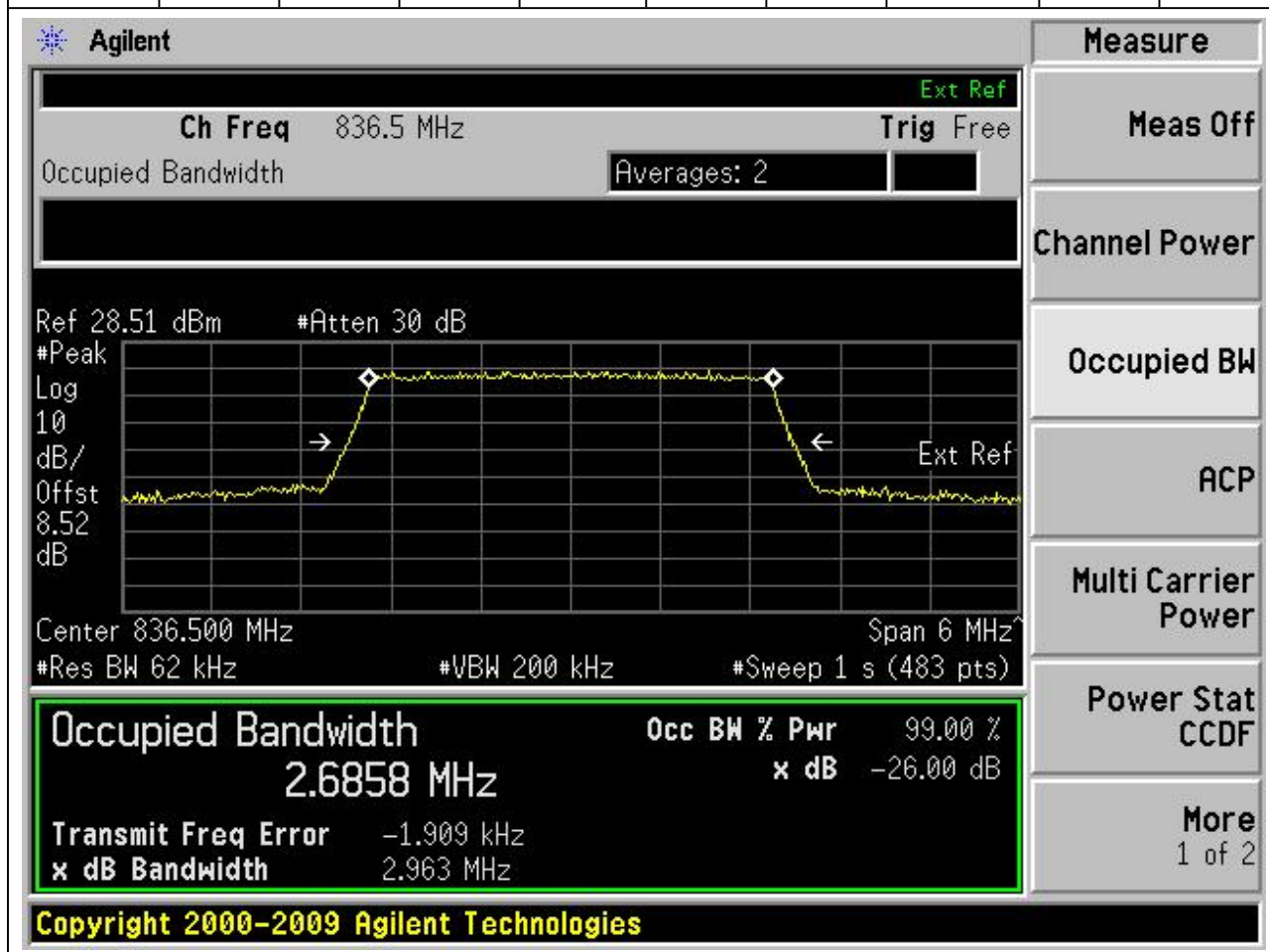
3.9. LTE Occupied Bandwidth_Part22-24-27(Channel:20525, Bandwidth:3, Modulation:QPSK, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
836.5	99	26	0.062	Peak	8.52	2.69	2.96	3	Pass



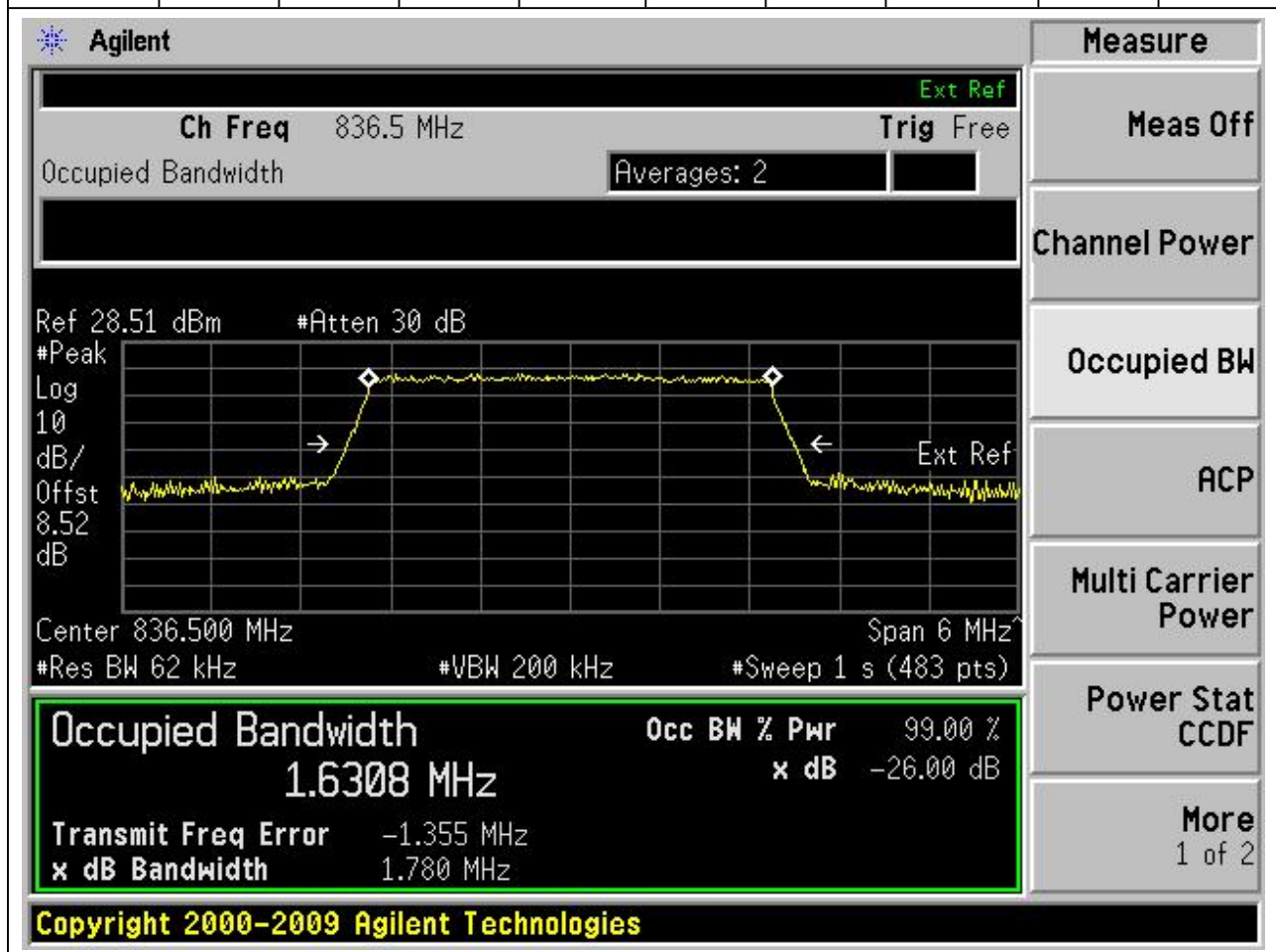
3.10. LTE Occupied Bandwidth_Part22-24-27(Channel:20525, Bandwidth:3, Modulation:16QAM, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
836.5	99	26	0.062	Peak	8.52	1.63	1.78	3	Pass



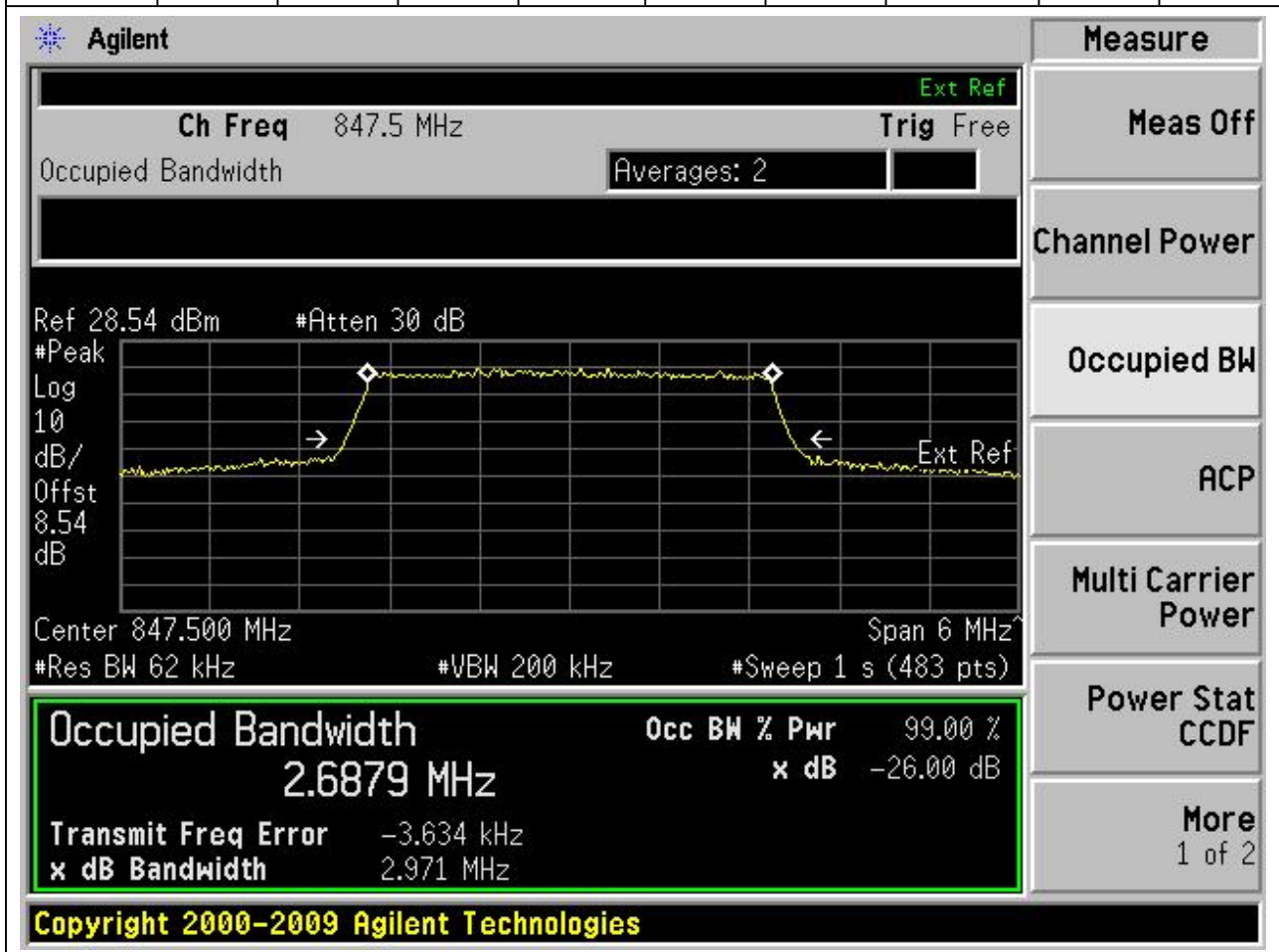
3.11. LTE Occupied Bandwidth_Part22-24-27(Channel:20635, Bandwidth:3, Modulation:QPSK, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
847.5	99	26	0.062	Peak	8.54	2.69	2.97	3	Pass



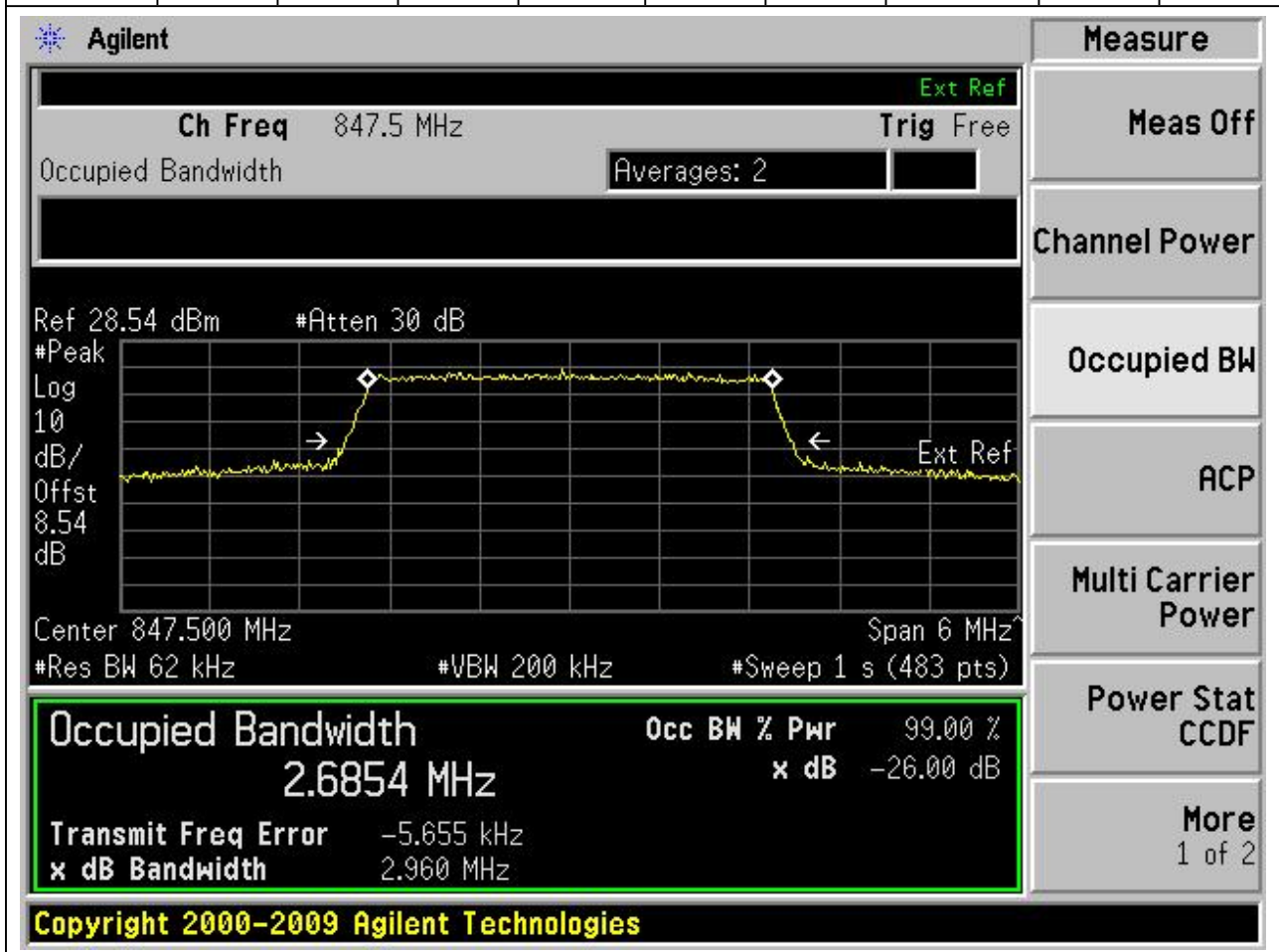
3.12. LTE Occupied Bandwidth_Part22-24-27(Channel:20635, Bandwidth:3, Modulation:16QAM, RB Number:15, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
847.5	99	26	0.062	Peak	8.54	2.69	2.96	3	Pass



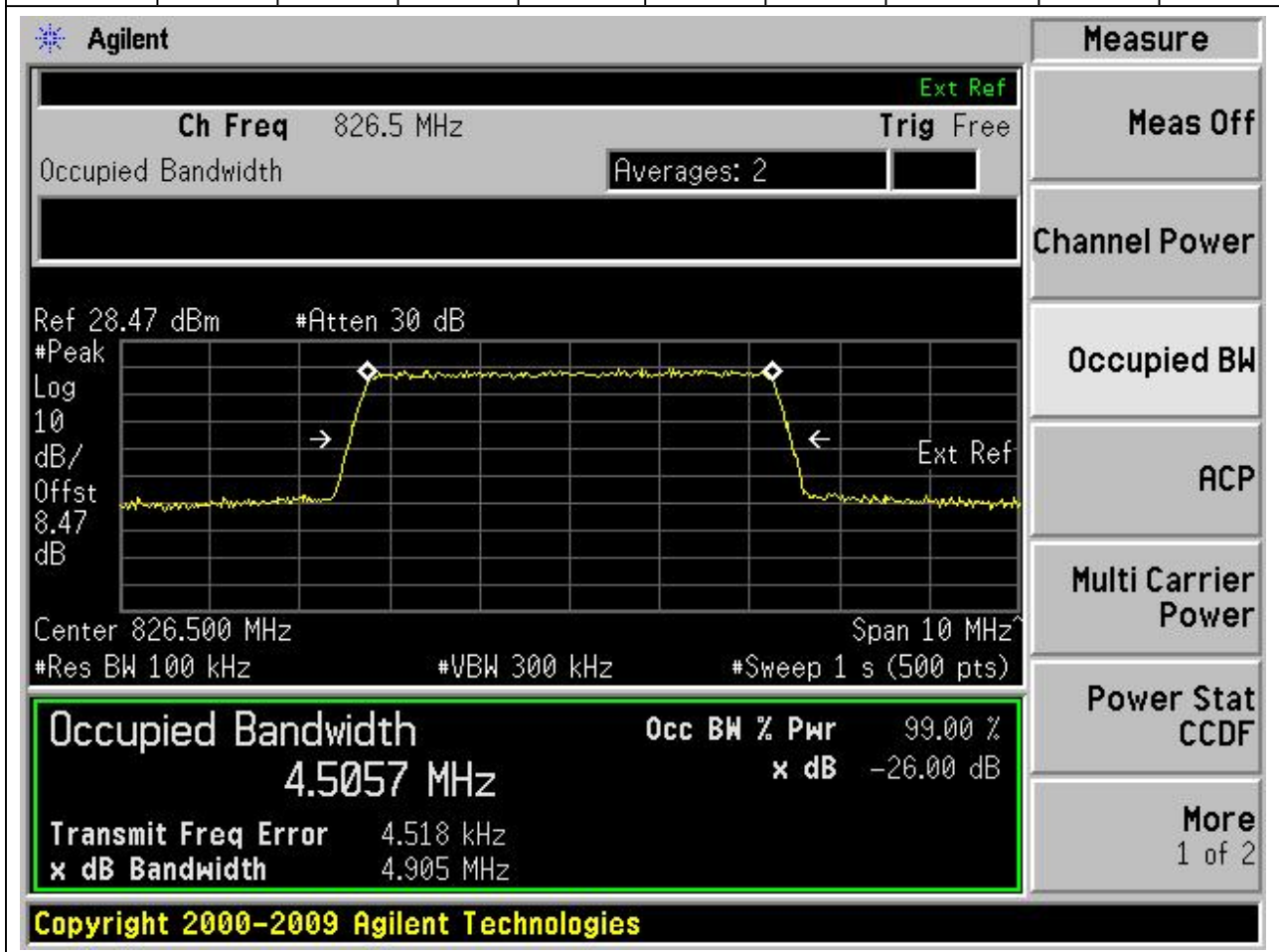
3.13. LTE Occupied Bandwidth_Part22-24-27(Channel:20425, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
826.5	99	26	0.1	Peak	8.47	4.51	4.91	5	Pass



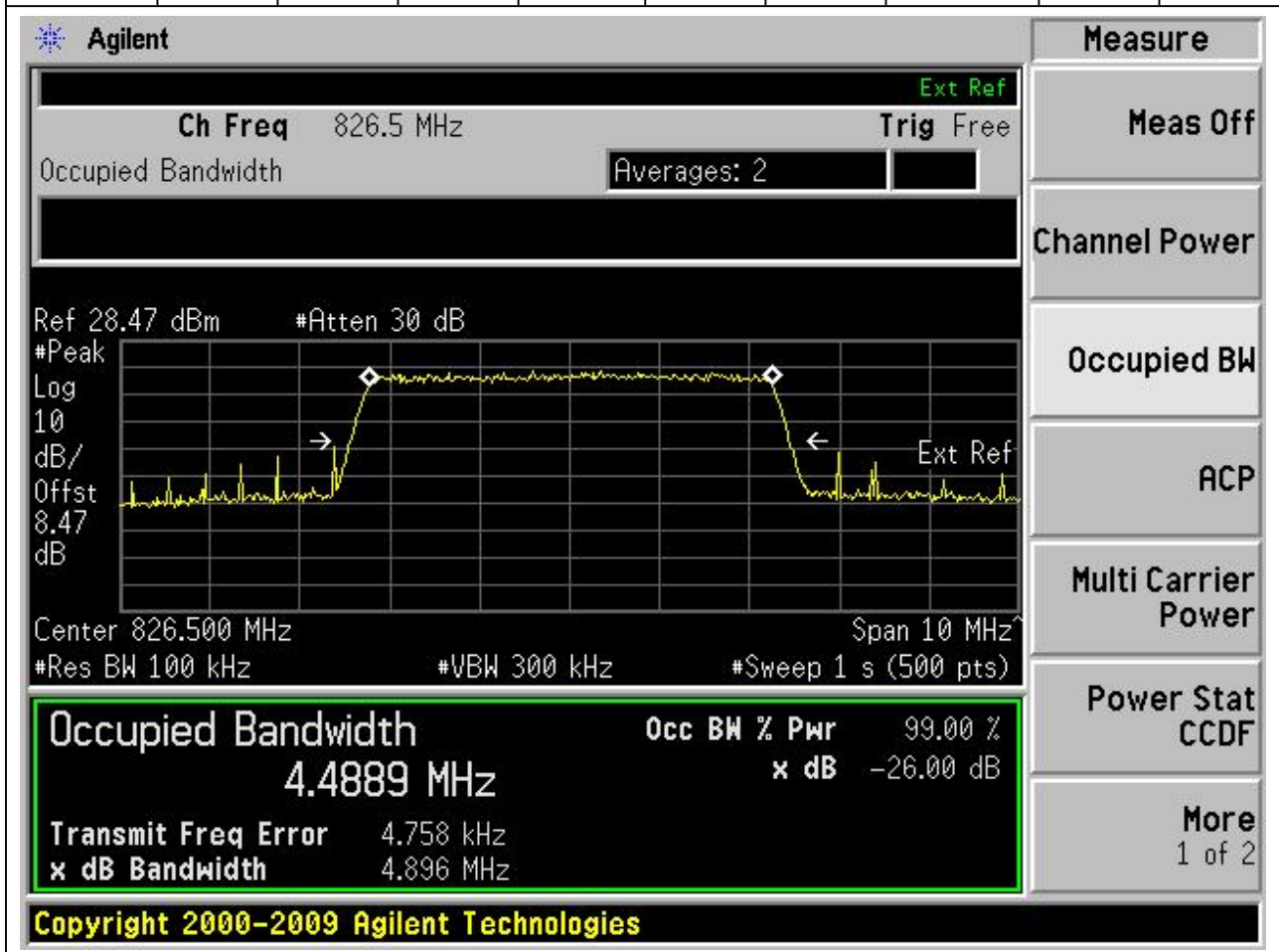
3.14. LTE Occupied Bandwidth_Part22-24-27(Channel:20425, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
826.5	99	26	0.1	Peak	8.47	4.49	4.9	5	Pass



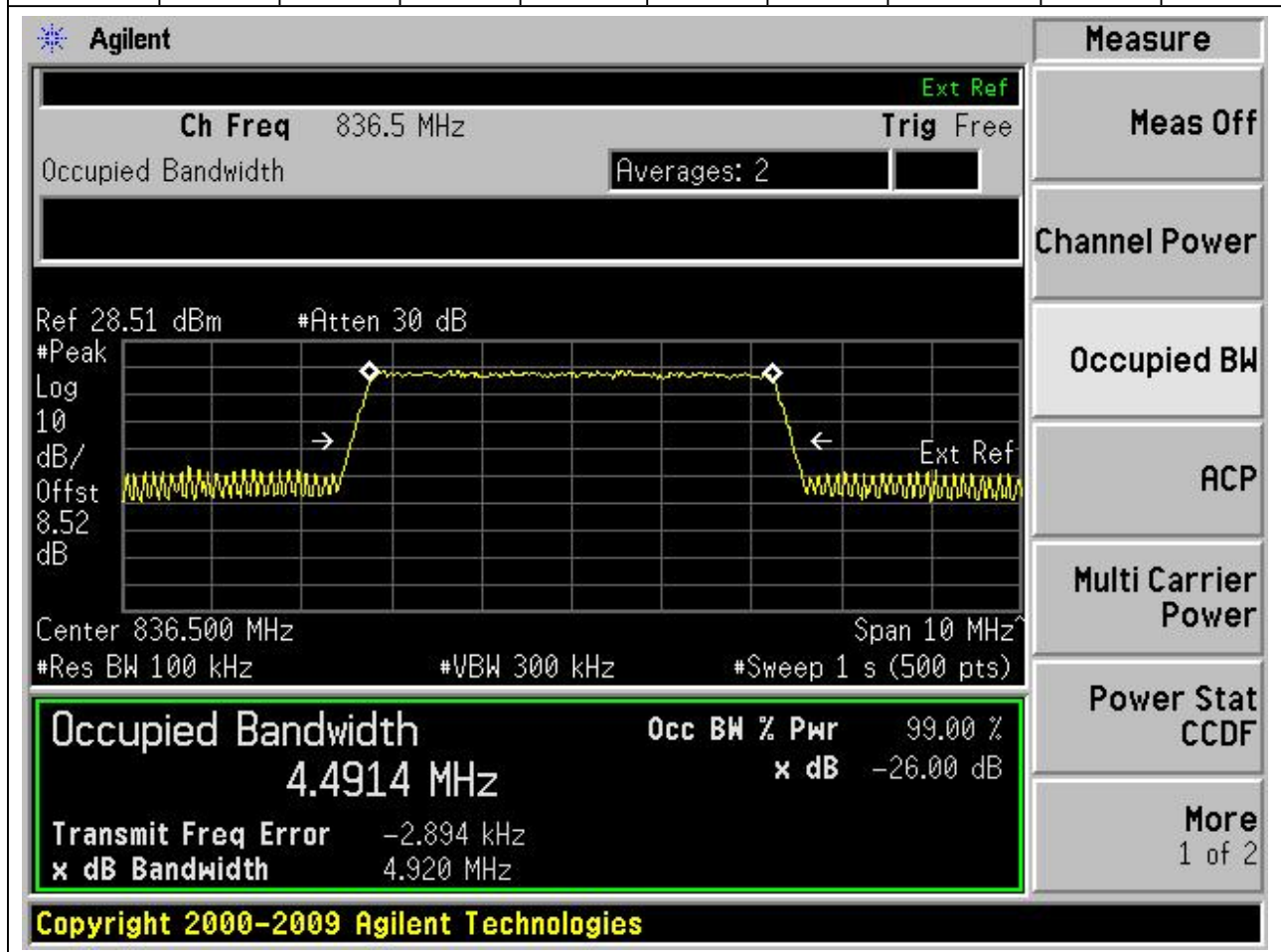
3.15. LTE Occupied Bandwidth_Part22-24-27(Channel:20525, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
836.5	99	26	0.1	Peak	8.52	4.49	4.92	5	Pass



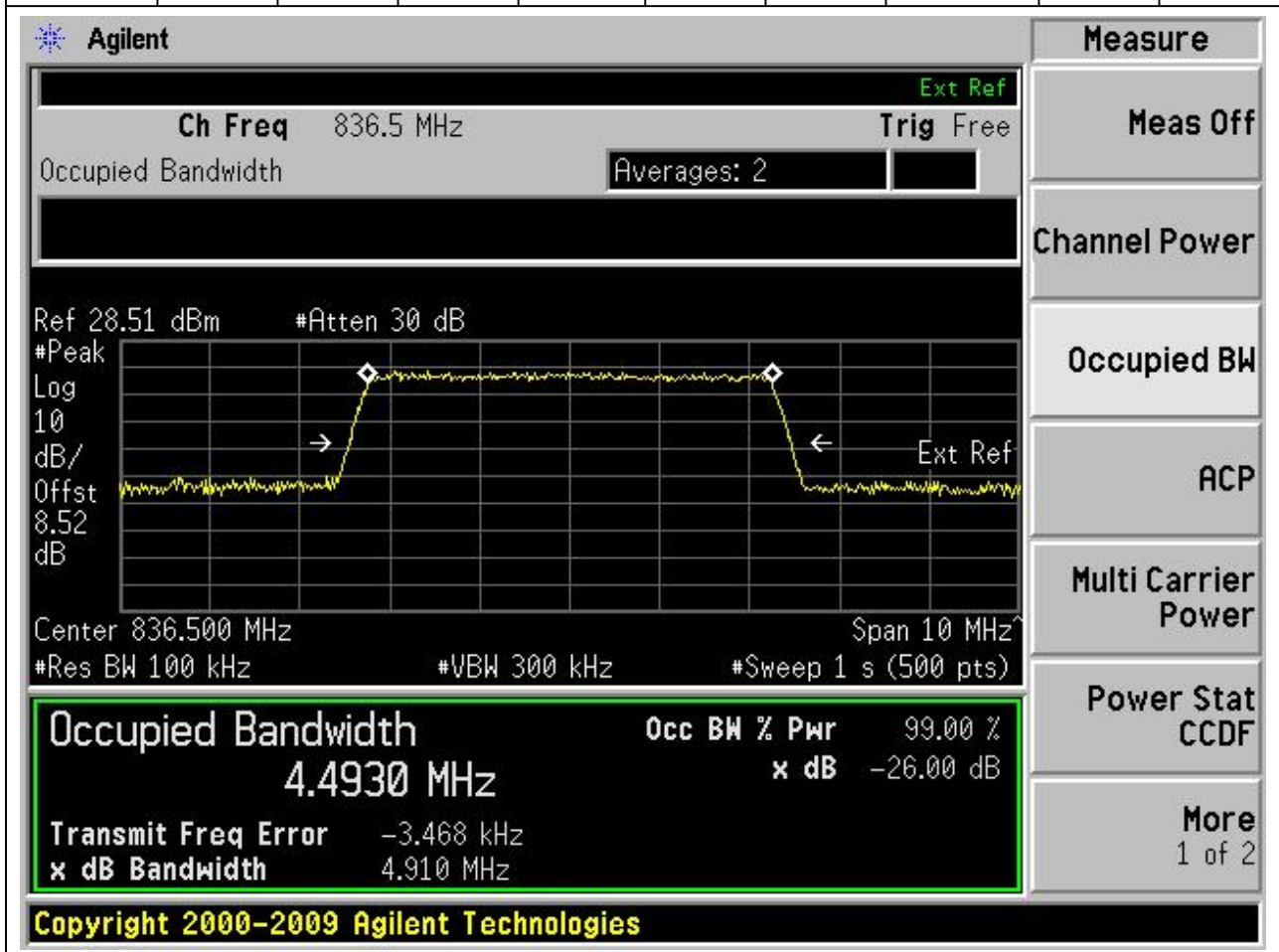
3.16. LTE Occupied Bandwidth_Part22-24-27(Channel:20525, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
836.5	99	26	0.1	Peak	8.52	4.49	4.91	5	Pass



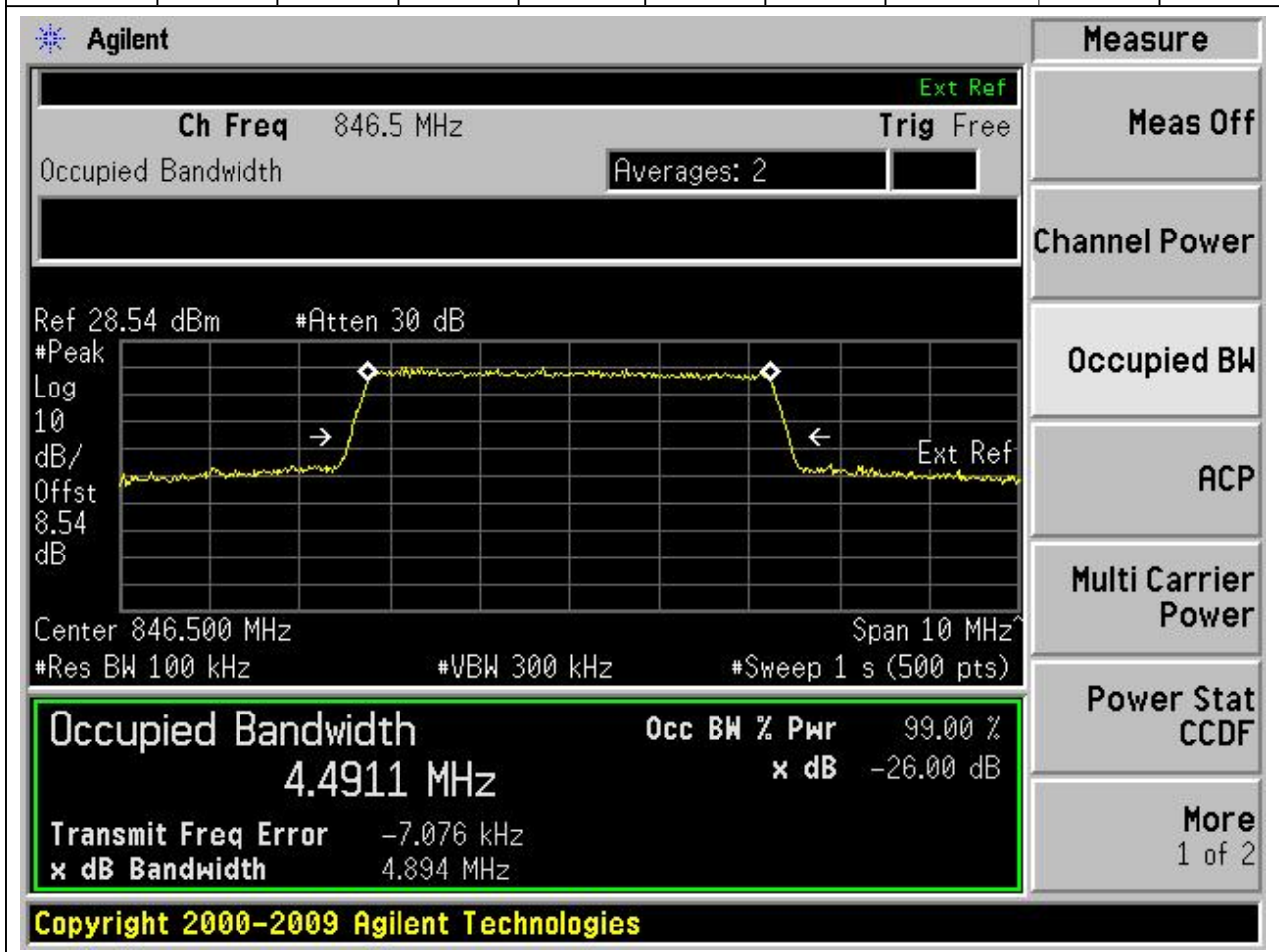
3.17. LTE Occupied Bandwidth_Part22-24-27(Channel:20625, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
846.5	99	26	0.1	Peak	8.54	4.49	4.89	5	Pass



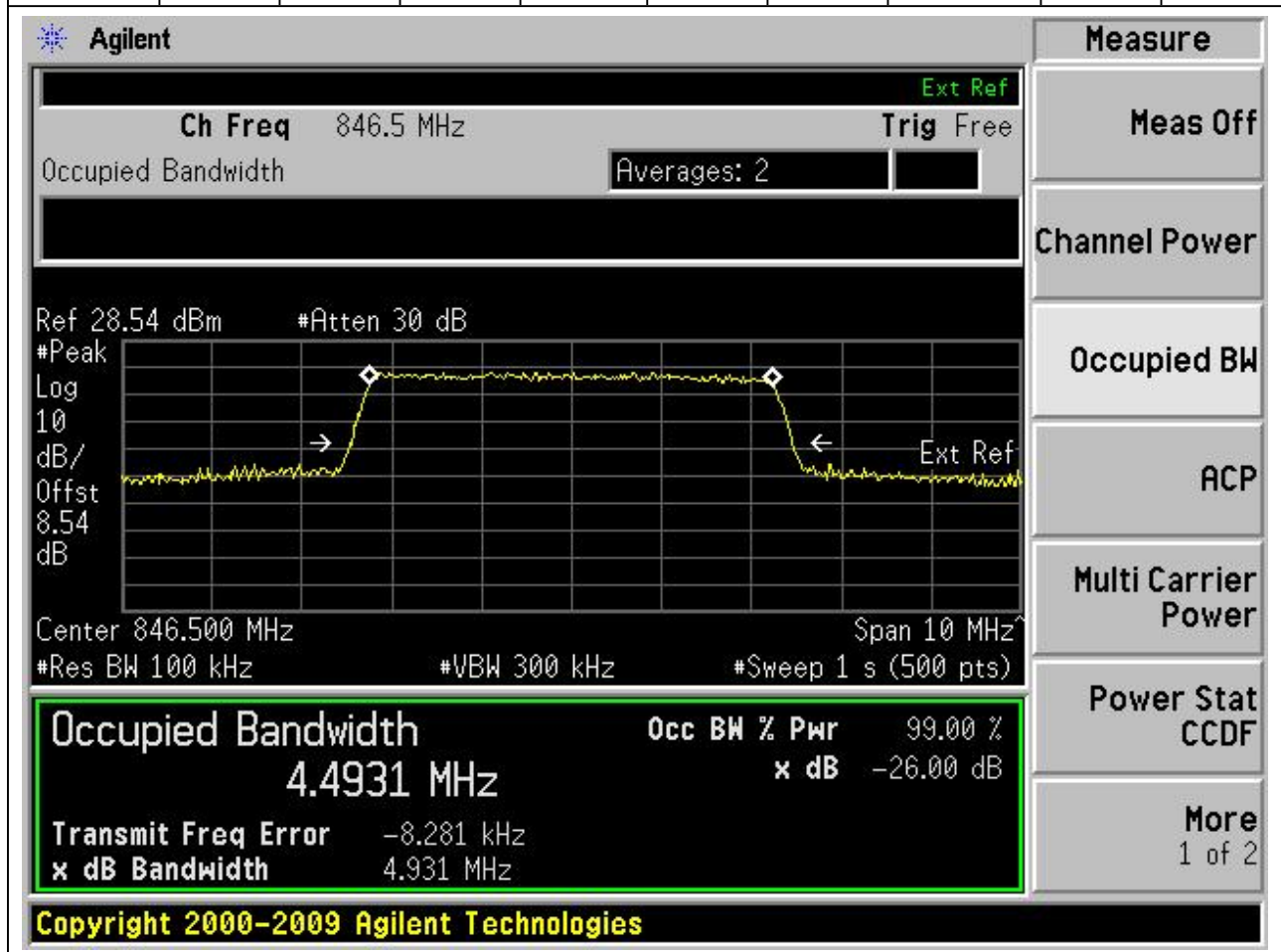
3.18. LTE Occupied Bandwidth_Part22-24-27(Channel:20625, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
846.5	99	26	0.1	Peak	8.54	4.49	4.93	5	Pass



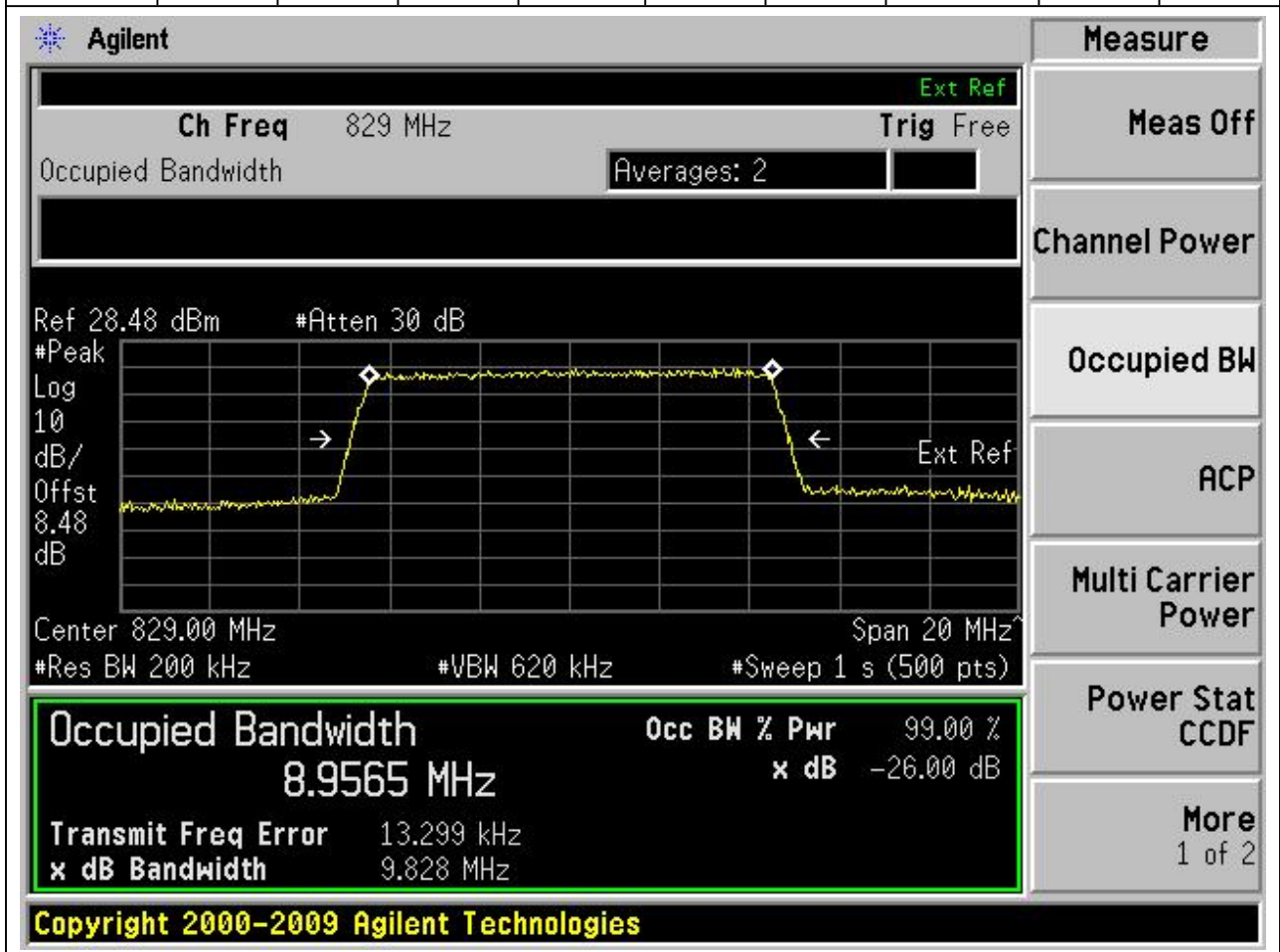
3.19. LTE Occupied Bandwidth_Part22-24-27(Channel:20450, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
829	99	26	0.2	Peak	8.48	8.96	9.83	10	Pass



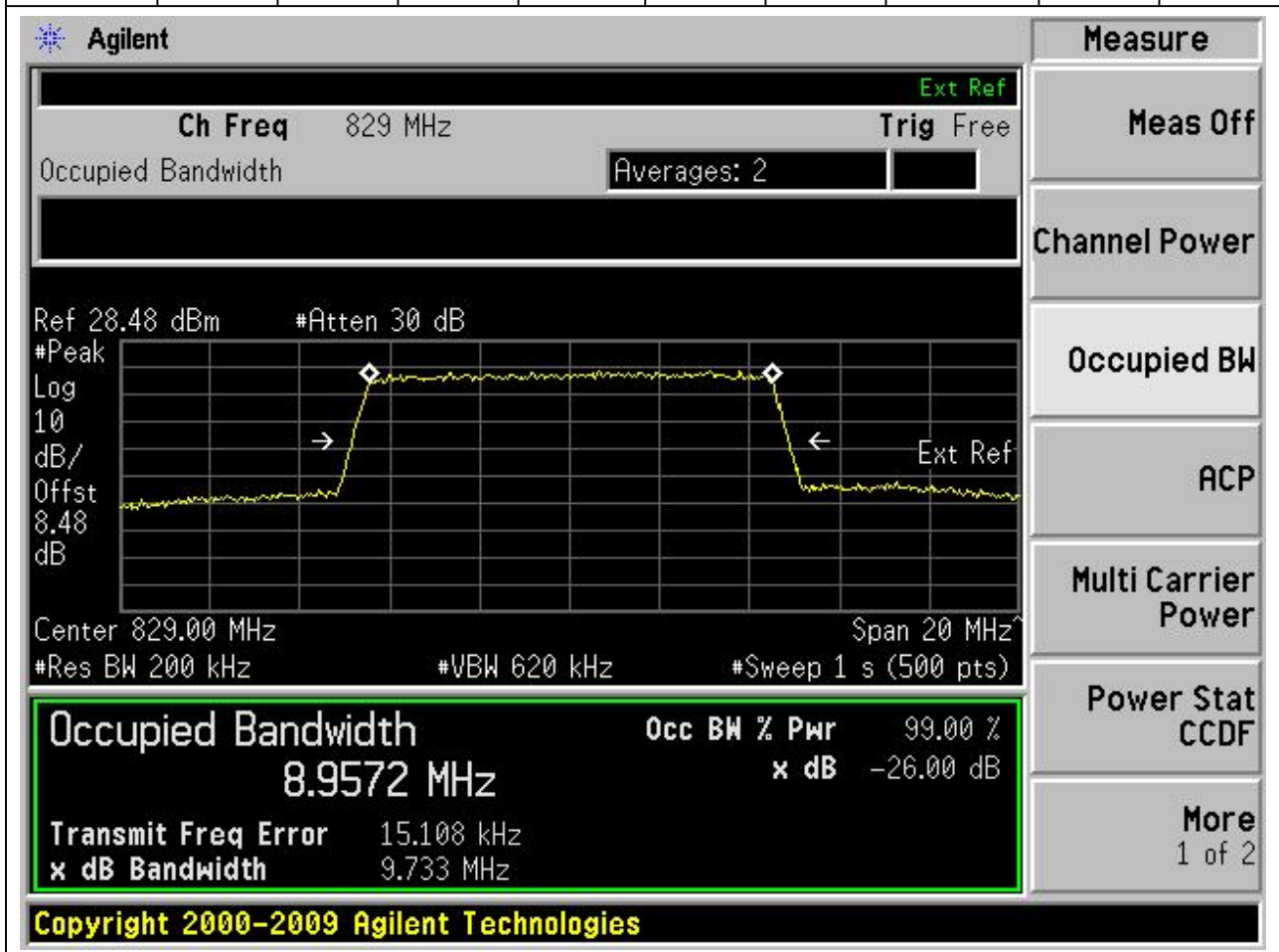
3.20. LTE Occupied Bandwidth_Part22-24-27(Channel:20450, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
829	99	26	0.2	Peak	8.48	8.96	9.73	10	Pass



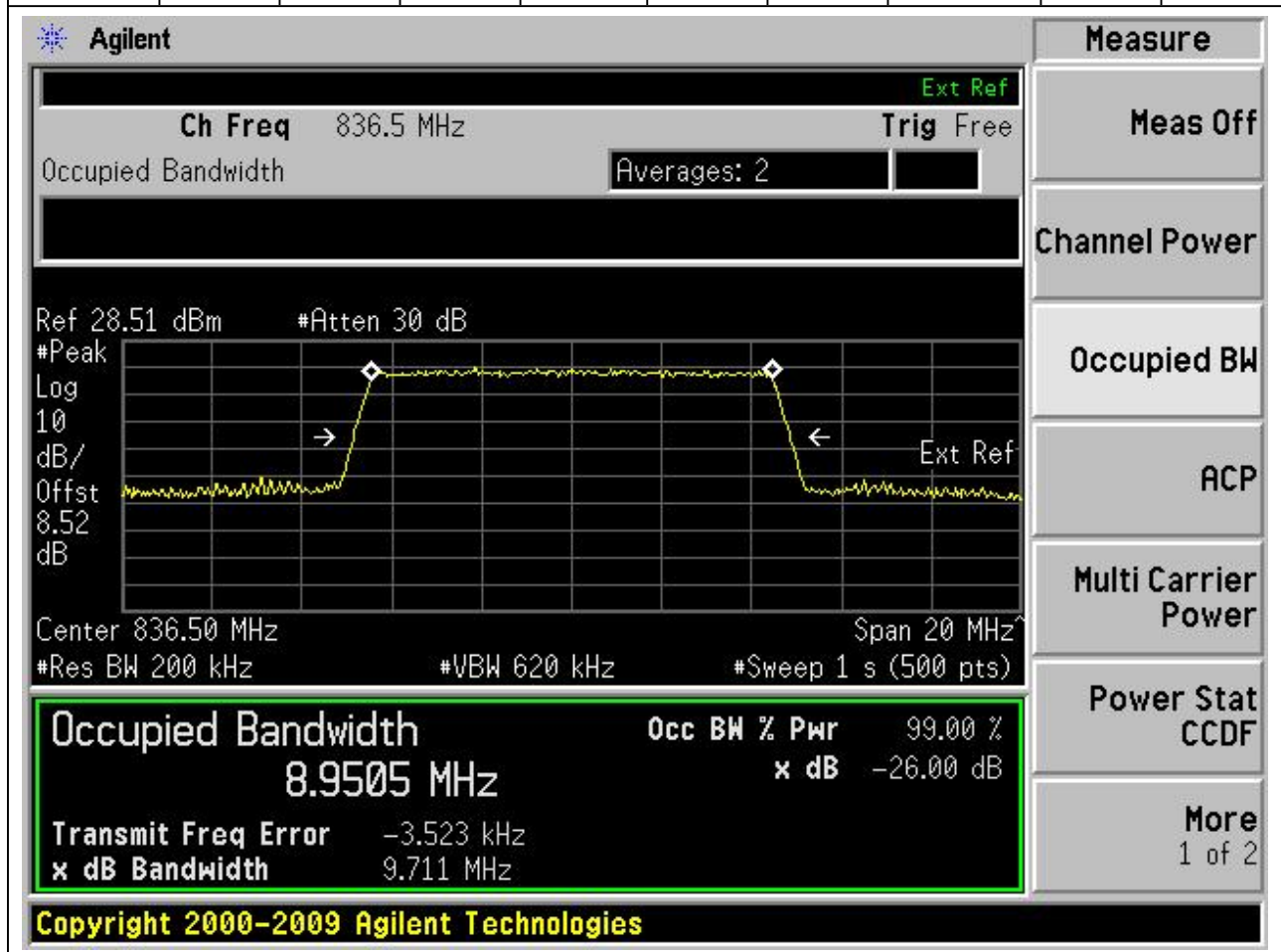
3.21. LTE Occupied Bandwidth_Part22-24-27(Channel:20525, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
836.5	99	26	0.2	Peak	8.52	8.95	9.71	10	Pass



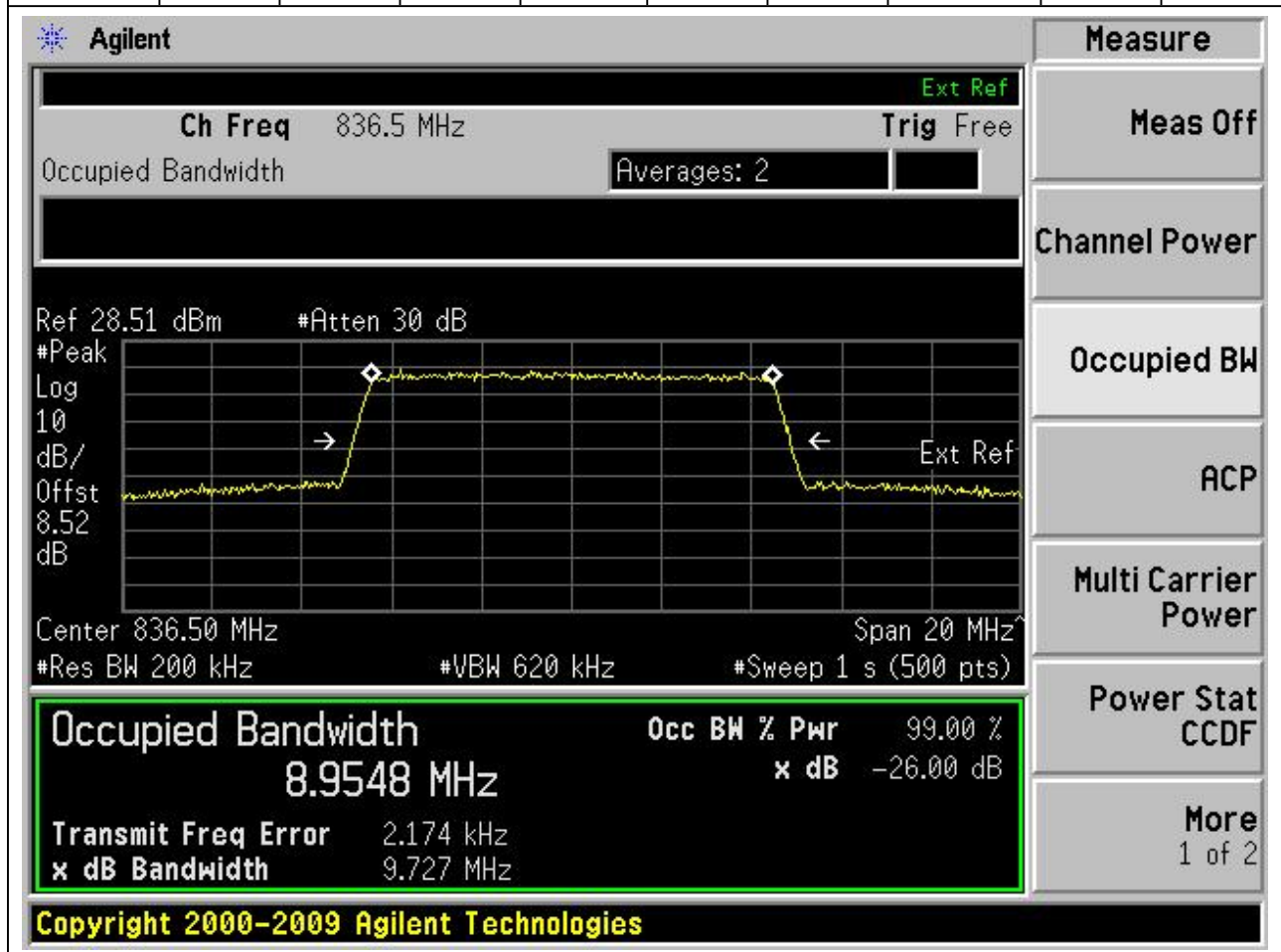
3.22. LTE Occupied Bandwidth_Part22-24-27(Channel:20525, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
836.5	99	26	0.2	Peak	8.52	8.95	9.73	10	Pass



3.23. LTE Occupied Bandwidth_Part22-24-27(Channel:20600, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
844	99	26	0.2	Peak	8.54	8.94	9.71	10	Pass

